

# XPowder™ XPowder12

A SOFTWARE PACKAGE FOR POWDER X-RAY DIFFRACTION ANALYSIS

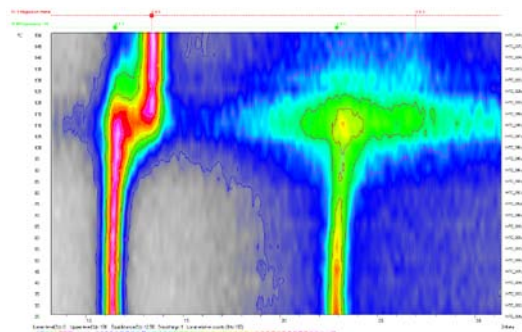
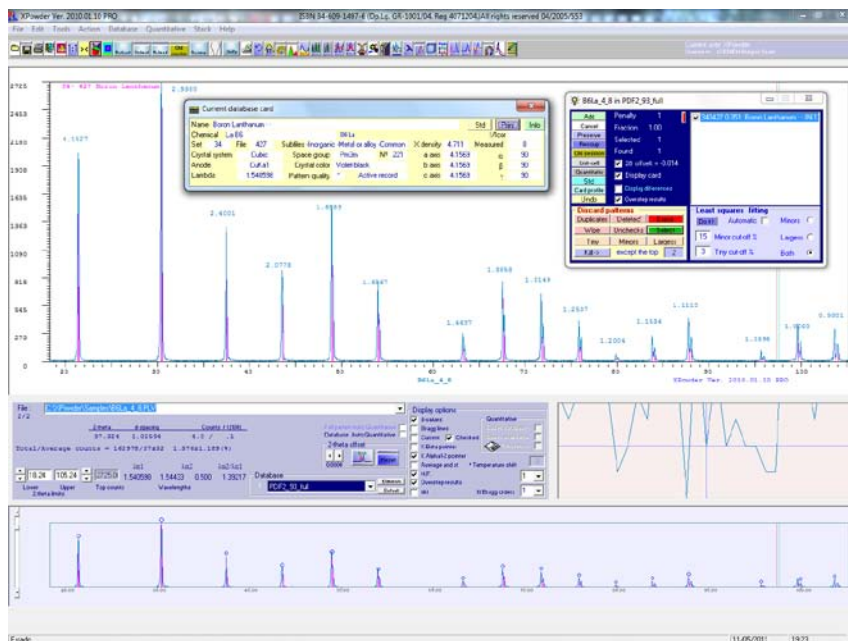
User guide  
Ver 2004.04.82

Updates

New features  
Ver 2010.01.10

Xpowder12  
Ver 2012.01.01

Qualitative, quantitative and microtexture



The program uses PDF2 , AMSCD or customized databases

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**XPowder**

A SOFTWARE PACKAGE FOR POWDER X-RAY DIFFRACTION ANALYSIS

[User guide](#)

Version 2004.04.82

**XPowder12**

[XPowder12. New features](#)

**Qualitative, quantitative and microtexture**

This manual is available in [www.xpowder.com/](http://www.xpowder.com/) User guide  
and can be freely copied and distributed

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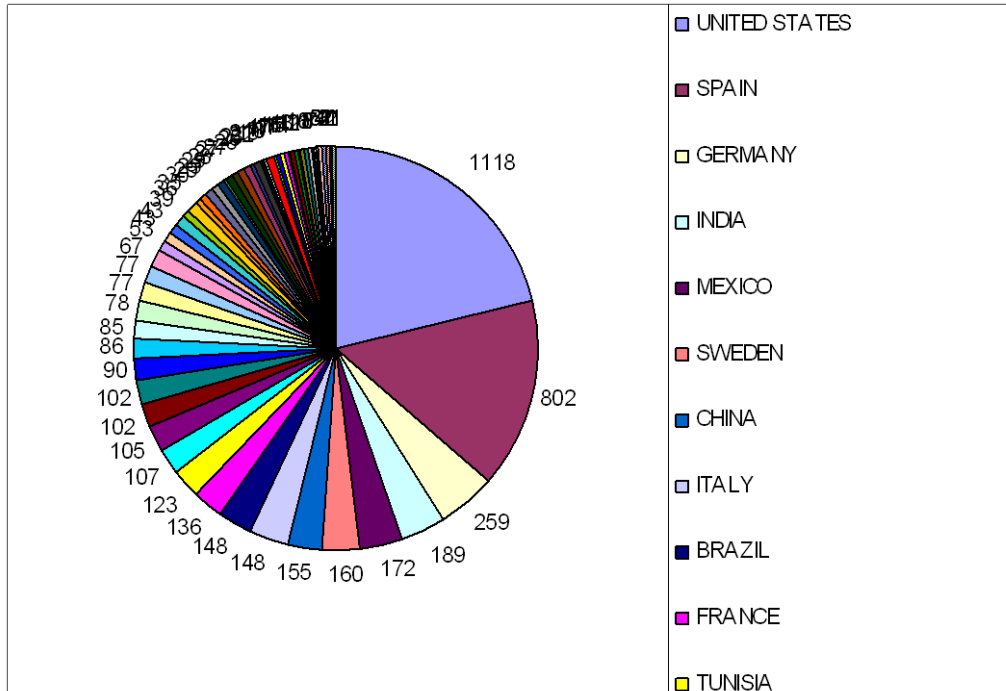
## Index

<a href="#">Introduction</a>	7
Recognition of data formats.	8
What can you do XPowder?	10
XPowder Installation	11
Database installation	11
PDF2.dat	12
<a href="#">Difdata.txt</a>	13
<a href="#">My database</a>	13
<a href="#">Chapter 1</a> . The main screen	15
How do you open a file?	16
Main commands	17
<a href="#">Chapter 2</a> . Advanced Searching Options	23
Matching criteria	24
<a href="#">Chapter 3</a> . Pattern filtering	27
1. Zero 2 $\theta$ offset angle correction	27
Correction with internal standard	27
Correction with harmonics	28
2. Elimination of noise.	30
3. Background subtraction.	31
4. K $\alpha_2$ stripping	32
5. Changing 2 $\theta$ step	32
6. Merging diffractograms	33
<a href="#">Chapter 4</a> . Subfiles and chemical restrictions	35
Chemical restrictions:	35
Boolean conditions	36
Example	36
<a href="#">Chapter 5</a> . Searching and matching	39
'Matching' commands	42
Launching 'MyDatabase.Myd'	44
<a href="#">Chapter 6</a> . Quantitative analysis by RIR (Reference Intensity Ratios) methods	47
Description of the <a href="#">RIR tool</a>	49
Auxiliary buttons	52
<a href="#">Chapter 7</a> . Quantitative analysis using experimental standards	53
Edit/Create group	54
Select group	55
The agreement factor	57
<a href="#">Chapter 8</a> . Pattern stacking	61
3D Screen	61
2D Screen	64
<a href="#">Chapter 9</a> . Unit-cell refinement	69
Example: <a href="#">The determination of the ratio Ca/Mg in Mg carbonates</a> by PXRD	74
<a href="#">Chapter 10</a> . Profile Analysis	77
Absolute and relative values of the integrated intensity	77
Line broadening	79
The distribution function	80
Profile analysis methods based on <a href="#">width and shape</a> of the diffraction profiles	81
1. Scherrer Method	81
2. Williamson-Hall Method	84
<a href="#">Warren-Averbach</a> method	87
General procedure in W-A analysis	88
Log-normal distribution	91
How does XPowder do this?	91
Selecting profiles	92
Definable parameters and computation	92
Warren-Averbach Quick Start User Guide	94
<a href="#">Chapter 11</a> . Caglioti equation calculation	95
<a href="#">Chapter 12</a> . Additional files	97
XPowder.ini	97
Std.txt	98
Favorites.txt	99
SolSol.txt	99
Default.cnf	100
<a href="#">Chapter 13</a> . Data collection from the diffractometer	101
Setting the experimental conditions	104
Setting the 2 $\theta$ angle zero mark	106
Recording strategy	106
<a href="#">Updates</a>	109
<a href="#">New features version 2010.01.10</a>	112
<a href="#">Xpowder12 (version 2012.01.01)</a>	123
Search and macth	126
Quantification using databases	128
Quantification using experimental patterns	129
Program window size	130
Transformation of 'Chemin' images to (x,y) text files	131
K $\beta$ stripping	134

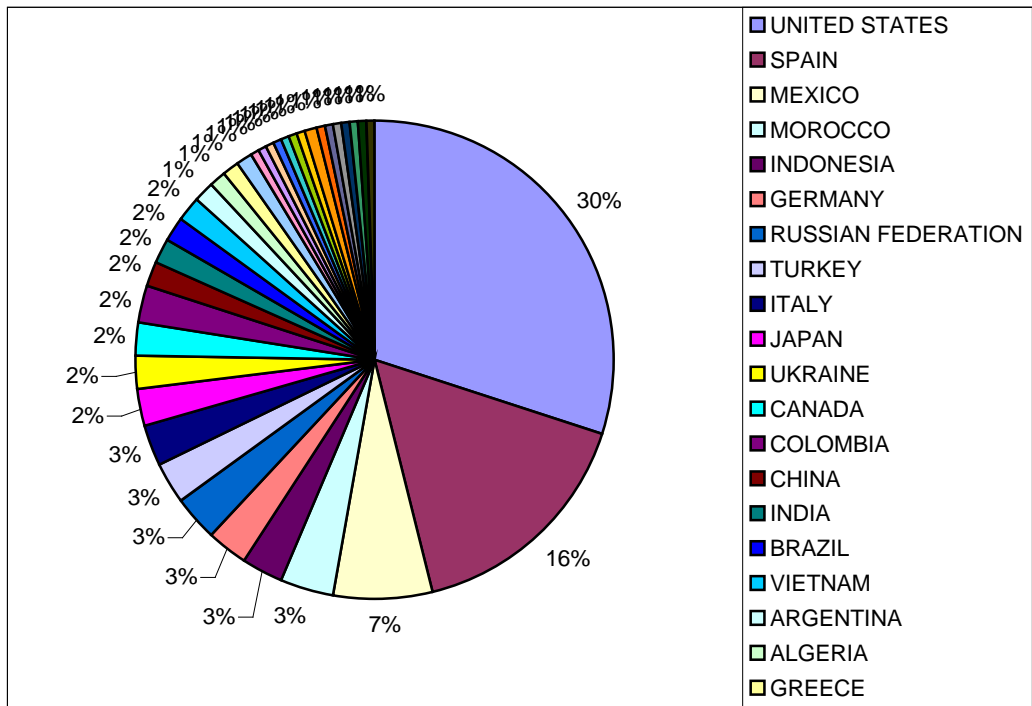


Introduction

XPowder is a widely used program (Figures 1 and 2) that was created for the operating system Windows™, to facilitate the analysis of Powder X-ray diffraction patterns.



**Figure 1.** Number of downloads of the program XPowder from [www.xpowder.com](http://www.xpowder.com) between January and September 2008. The data are from 'Advanced Web Statistics 6.6' (build 1887) - Created by AWStats (GNU General Public License) and do not include downloads from unknown or repeated IP addresses.



**Figure 2.** Geographic distribution in % of downloads of the program XPowder in the first half of October 2008, which corresponds to the start of the academic year 2008-2009.

This program recognizes files from most diffractometers, and handles a number of simple ASCII formats that can easily be generated for import. XPowder also lets you acquire data directly from some older diffractometers who did not have proper digital control for Windows operating system. Automatic sample-changer and monitoring of temperatures, are also handled by XPowder.

Files may contain data in the form of a list of intensities (counts, cps, absolute or relative intensities, etc.) from an initial angle  $2\theta$ , and constant  $\Delta 2\theta^0$  step in a txt formats.

XPowder can also read 2D images (jpg, tiff, bmp, mccd, etc) obtained by instruments with CCD detectors and directly calculate their powder diffractograms.

### Recognition of data formats.

- \* RAW Binary. Siemens – Bruker diffractometers (1 to 4 versions)
- \* X'Pert Html. Philips diffractometers
- \* RD Binary. Philips diffractometers
- \* UDF ASCII. Philips diffractometers
- \* CCD All type of file images: jpg, bmp, etc. TERRA Diffractometers have a specific modulus.
- \* Ascii 20 [separator] Intensity (.txt, .asc, .xy)
- \* POW
- \* GSAS
- \* DBWS
- \* DAT
- \* UXD Several kinds
- \* GRF Cerius program calculated diffractograms
- \* Xye Mercury program calculated diffractograms
- \* Sietronic cpi
- \* Seifer nja
- \* Etc.

The program will recognize additional file formats in future versions. Please contact the author to request the inclusion of any specific format.

The conversion of any data file into one of the formats recognizable by **XPowder** is usually straight forward: PLV, the native format of XPowder (P,L and V are the consonants in *polvo* -powder in Spanish) is an ASCII text format with a very simple configuration containing the following information:

- \* First line: Information about the specimen.
- \* Second line: Starting  $2\theta$  angle at the beginning of the experiment.
- \* Third line:  $2\theta$  step between successive intensity measurements.
- \* Fourth line:  $K\alpha_1$  wavelength in Å. The precision of the value in this line is not important since **XPowder** normalizes all the  $K\alpha_1$ ,  $K\alpha_2$  and  $K\beta$  values according to the content of 'xpowder.ini' file.
- \* Fifth line to end: Experimental diffracted intensities (one per line).

An example of PLV file is given below:

```
RENDIJA=AUTOMATICA. CALCITA. Intensidad máxima: 10732.  
3.00  
0.06  
1.54051  
1  
3  
7  
...
```



Other richer PLV formats (versions 2 and 3) contain additional information about the experimental conditions. The example below shows a PLV version 3 file.

```
XPowder diffraction software. PLV file format Ver. 3.0
Sample= Fluorita0.PLV
Site= Universidad de Granada (Spain)
User= Crista-Mine-Gr
Date= 18/06/2004
Time= 13:32:38
Start 2-theta scan= 3.000
End 2-theta scan= 80.000
Step size= 0.040
Scan mode= Continuous
Integration time(sec)= 0.4
Anode= Cu
Filter= None
Monochromator= Graphite 2°
K-Alpha 1= 1.54051
K-Alpha 2= 1.54433
Ka2/Ka1 Ratio= 0.5
K-Beta= 1.39217
Automatic sampler changer= NO
Single Gobel mirror= NO
Divergence slit= AUTOMATIC
Receiving slit= 1/0.1/1
Generator voltage(Kv)= 40.00
Tube current(mA)= 40.00
Maximun counts= 5194
Line 26
Line 27
Line 28
Line 29
Line 30
Line 31
Line 32
Temperature = 22
Line 34
Line 35
Line 36
Line 37
Line 38
Line 39
Line 40
Line 41
Line 42
Line 43
Line 44
Line 45
Line 46
Line 47
Line 48
Line 49
Data
  3.000      22
  3.040      20
  3.080      19
  3.120      15
  3.160      16
  3.200      21
  3.240      20
```

This file type uses 'keywords' (*Start 2-theta scan* for example) followed by the sign '=' and the value of each argument (= 3.000). The lines that contain the keyword 'Line' are ignored by the program. From the keyword 'Data' are tabulated values of '2θ' and 'intensities'. It can contain any number of lines of header and the order is irrelevant, except that the first line should contain the key 'PLV file format View. 3.0' or 'View PLV file format. 2.0'. Version 2.0 is equal to 3.0 except that the data list can only contain intensity values (no 2θ angle).

## What can you do XPowder?.

The main operations, as described in the following five points, are made by pressing buttons or selecting from pull-down or contextual menus. The latter appear when right-clicking the mouse on the graphic or object of interest:

1. Identification of crystalline compounds (Search-Match). It is necessary to have a database, such as 'PDF2.DAT' of the ICDD (International Center for Diffraction Data) and, or, the 'Difdata.txt' of AMSCD. The latter only contains minerals.

The phase identification of samples with one, two or three major components is usually done with a single 'Click'. With more complex samples, either with more phases or minor components, the complete identification is achieved easily by using various tools such as subtraction of patterns already identified. All these tools are detailed in Chapters 2, 4 and 5.

2. Quantification of compounds. The quantification is done on full profile of the experimental diffractogram by non-linear least squares regression based on parameters such as  $2\theta$  displacement and profile function (Gauss, Cauchy, Pseudo Voigt, Pearson VII and asymmetry). All calculations are accompanied by statistics. The reference data for each phase can either be full patterns (experimental or calculated) or database records (positions and relative intensities). When using a  **$2\theta/I_r$**  database, a Reference Intensity Ratio (RIR) must be used for each phase, and can manually entered if not provided in the database, or if particular experimental conditions require their adjustment. The calculation takes into account the absorption correction based on the chemical composition provided by the database. It also takes into account a parameter that represents an approximate percentage of amorphous phase in the sample. The program is designed to automatically carry out up to fifty simultaneous quantitative analyses. The results are presented in tabular form within the 'log file' of each session. The quantification of compounds is detailed in chapters 6 and 7.

3. Crystal size, 'strain', thermal expansion tensor. Tools are provided for crystal sizes and 'strain' calculations using the 'Williamson-Hall' and 'Warren-Averbach' methods, in addition to the classic 'Scherrer' method. A specific tool allows calculating 'log-normal' distribution in very low crystallinity materials. This is detailed in Chapter 10. If the diffractogram records are made with temperature control, the thermal tensor can also be calculated (Figure 8.9).

4. Assorted tools.

- a. Automatic unit-cell refinement of identified phases (Chapter 9).
- b. " $K\alpha_2$  stripping" by a highly optimized Rachinger method.
- c. Automatic background subtraction. Smoothing (elimination of excessive vibrations and noise) by Fourier transform and functional filters.
- d. Calculation of powder diffractogram from electron or X-ray diffraction 2D images.
- e. Calculation of the diffractometer instrumental profile.
- f. Calculation of the Caglioti equation for real samples (Chapter 11).
- g. Calculation function of profiles and theoretical mixing patterns.
- h. Addition and subtraction of diffractograms.
- i.  $2\theta$  offset correction using standard pattern or harmonic peaks (Chapter 3).
- j. Logarithmic/Arithmetic scaling.
- k. Calculation of reciprocal histograms.
- l. Reporting text ('log file').

5. Graphic tools.

- a. Zoom.
- b. Choice of color palette and active diffractogram.
- c. Copy and paste images.
- d. Generation of graphics (bitmaps) and vectorial (hppl) files.
- e. Dynamic 3-D representation of up to fifty patterns.
- f. 2D representation of diffractogram series (diffraction maps) with calculation of curves and level, or false color very useful for studies of phase changes and crystallinity (Chapter 8).

## **XPowder Installation**

A single installation file (' *xpowder\_setup.exe* ') is used for all program options (Trials, Academic, Professional, PLUS, etc.). It is available from [www.xpowder.com](http://www.xpowder.com) (download) and can be freely copied or distributed.

### Instructions:

1. Download the latest file version (2004.04.xx) of *xpowder\_setup.exe* from [www.xpowder.com](http://www.xpowder.com)
2. Double click on then *XPowder\_setup.exe* installation icon.
3. Follow the instructions that will appear on the screen (figure 3).
4. If you have the license code of the program, insert it (preferable copy/paste) into the box

[Main menu -> Help -> XPowder registration code](#)

Please, backup this registration code because it is valid for future installations and/or updates. The XPowder program will be licensed and may be updated without having to re-input the code (this code is recorded in the text file 'Folder program / Code.txt'). If this file is deleted, the program will behave as a 'trial version' valid for 20 days, for analysis of up to 500 diffractograms.



Figure 3

## **Database installation**

The databases are not attached to the program and must be purchased separately. The databases recognized by XPowder 'PDF2.DAT' (between 500MB and 550MB or so, depending on the version) and 'DifData.txt' (approximately 65 MB). You can install both in parallel from the main menu:

[Database-> Database install \(or Database Update\)](#)

Select database file and then pulse [Install](#) (figure 4).

Database files could be:

- ICDD: 'PDF2.dat'
- [AMCSD](#): 'cifdata.txt' (optional) + 'difdata.txt' (required). In any case, 'cifdata.txt' must be installed before the 'DifData.txt'. 'cifdata.txt' (approximately 31 MB) is an auxiliary file of 'difdata.txt', its use is optional and it can be deleted once the setup has been completed.

It is desirable that the databases are on your hard drive rather than on a CD-ROM or DVD in order to optimize the searching speed.

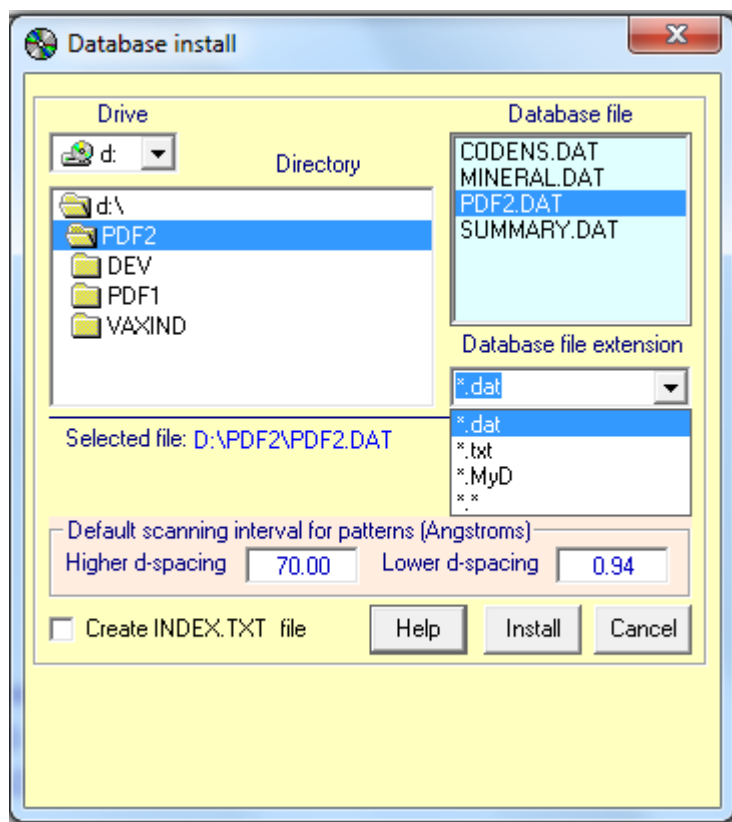


Figure 4

**PDF2.DAT.** It is the most popular database and is sold by the ICDD. For installation in XPowder only need the file 'PDF2.DAT', because XPowder creates its own index. PDF2 contains several sub-files that include all branches of solid materials used in science and technology:

- |                                 |                            |
|---------------------------------|----------------------------|
| Inorganics                      | Super conducting materials |
| Organics                        | Cements                    |
| Minerals                        | Corrosive materials        |
| Metal and alloys                | Polymers                   |
| Common phases                   | Detergents                 |
| NBS (National Bureau Standards) | Pigments                   |
| Forensic                        | Pharmaceutical             |
| Educational                     | ICSD                       |
| Zeolites                        | Ceramics                   |
| Explosives                      |                            |

PDF2 can be purchased at:

ICDD Internet site:	<a href="http://www.icdd.com">www.icdd.com</a>	E-mail: <a href="mailto:info@icdd.com">info@icdd.com</a>
Postal Address:	International Centre for Diffraction Data 12 Campus Boulevard Newtown Square, PA 19073-3273 U.S.A.	
Telephone	(610) 325 9814 (610) 325 9814 (General information) (610) 325 9810 (Sales)	

The quality of the PDF2 records is very heterogeneous, since there are diffractograms obtained with different radiation, different geometries or instrumental conditions. There are even not indexed or wrongly indexed phases. They also contain theoretical diagrams calculated from their crystal structures. In general the quality of the records is good and the file is completed and improved year after year.

In order to install the ICDD database, only 'PDF2.DAT' file from PDF-CDROM is necessary without any other file index.

**DifData.txt.** AMSCD database (American Mineralogist Crystal Structure Database) a free database created in University of Arizona. It is limited to minerals. Diffractograms were

calculated from the crystal structures published in the scientific literature. In general the quality is high and the database includes many entries of isomorphous series at high temperatures and high and very high pressures.



The records have a homogeneous quality and, although these are calculated, fit well with experimental diffractograms. The biggest errors occur in minerals whose structure and unit-cell were published long ago, as they were based on values of inadequate wavelength or inaccurate tools. This results in systematic errors on calculated d-spacings and hinders the identification. By contrast, diffractograms based structures published in the last few decades are very accurate. The Difdata.txt file does not include chemical formulas in itself (it only indicate the name of a mineral). However, the composition is found in the 'CifData.txt' file provided in parallel and can be loaded prior to difdata.txt installation. Even without this operation, XPowder assigns a chemical formula to correct 96% of the records. Another handicap of this database is the lack of the 'l / lcor' parameter, so XPowder automatically and temporarily assigned a value of 1 to RIR parameter for quantitative analysis.

[CifData.txt](#) is a complementary AMSCD database (American Mineralogist Crystal Structure Database) . It contains the structural and compositional data that have helped generate sheets of diffractograms database 'DifData.txt'. The installation under the program XPowder is not necessary (but desirable). In any case must be installed before the 'DifData.txt'.

[MyDatabase.MyD](#). It is a database that can easily be created and customized by the user, as shown in Chapter 5.



## Chapter 1. The main screen

The image of the figure 1.1. appears when you run X Powder.

At the top are provided a drop-down menu (File Edit ...) and tool bar with buttons that perform the main functions of the program.

Under the tool bar is provided the main graph area.

In the middle of the window (blue background) are shown various options and default values (data file, 2 $\theta$  limits, database options in the main chart, etc.).

At the bottom (orange background) is a second graph area

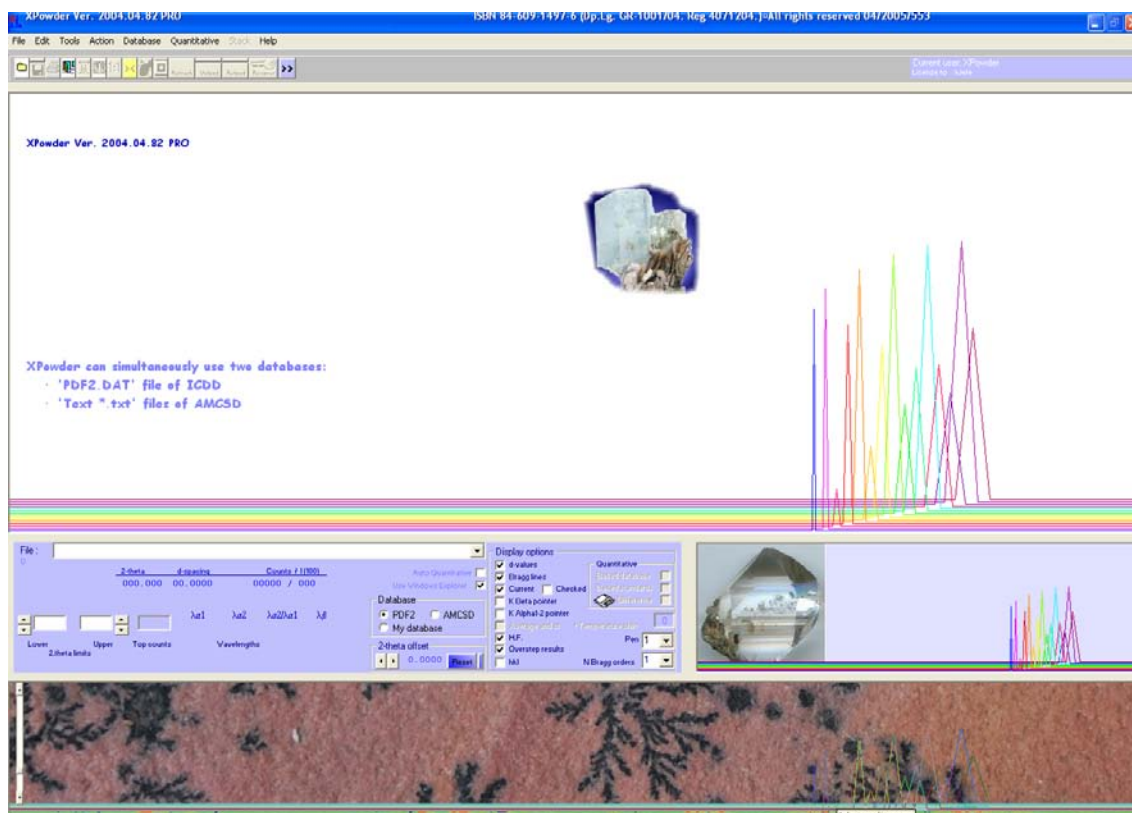



Figure 1.1. X Powder home screen.

How do you open a file?

From the main menu (**File -> Open file** or pressing the second button  (figure 1.2.)

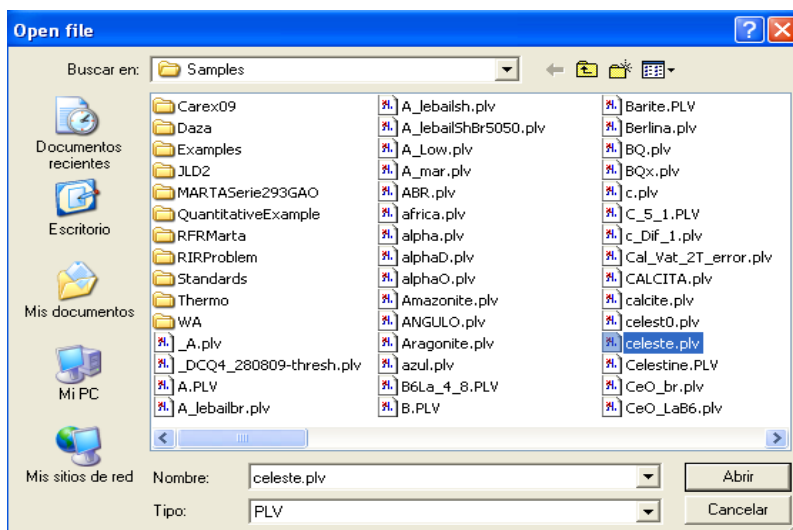


Figure 1. 2.

You can select one or more file samples (A.plv ... D.plv in this example). After clicking **OK** , you get the figure 1.3.

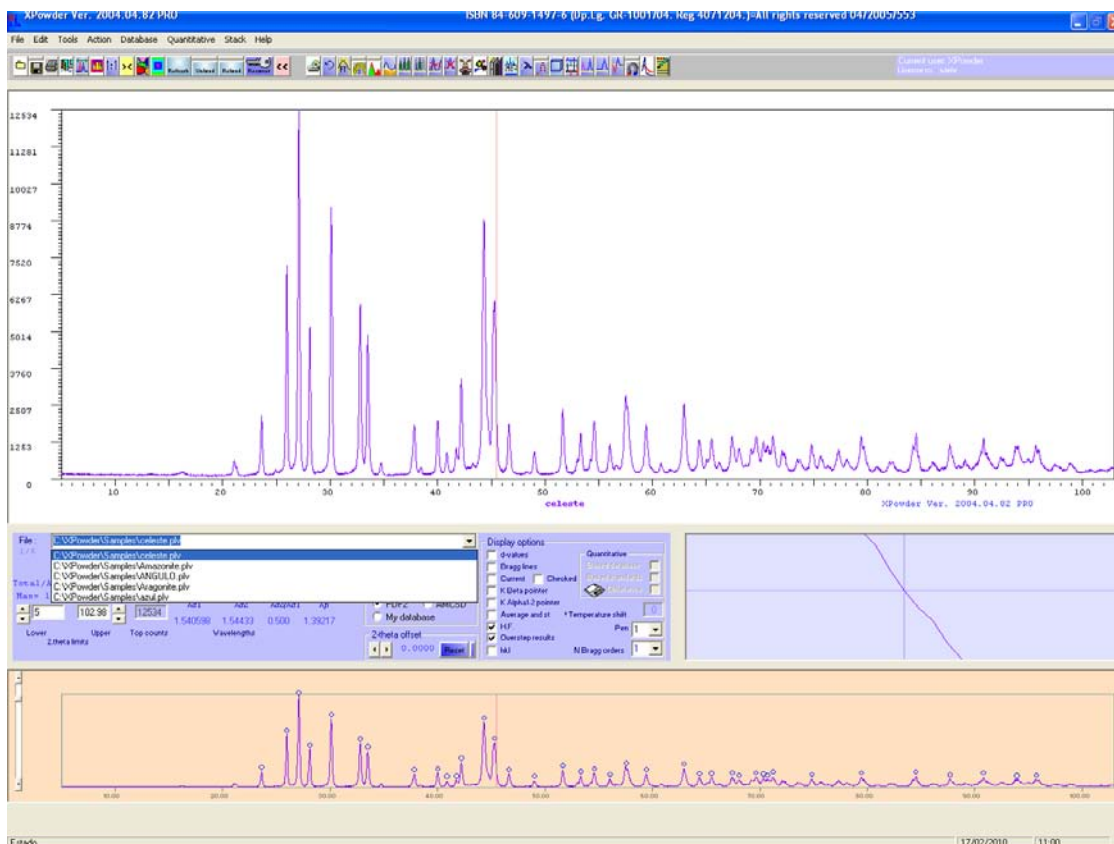


Figure 1.3. Main screen

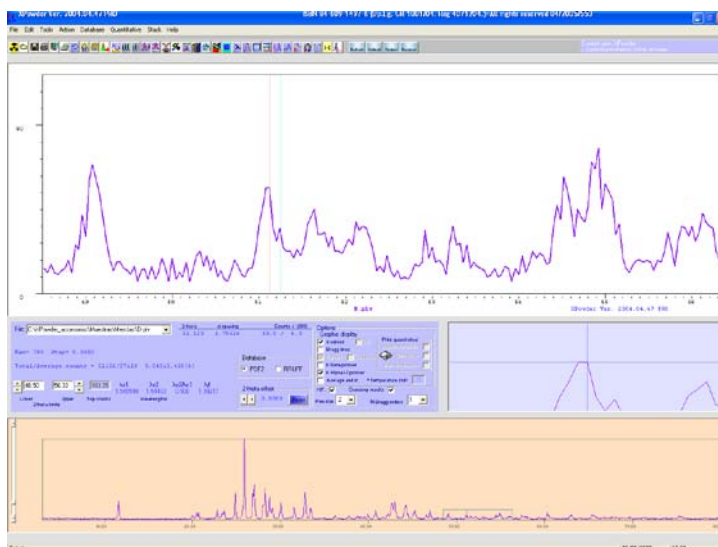


## Main commands.

Once the files are loaded, a diffractogram is shown in both the upper and lower graphs, while they are activated **menu options** and some buttons that until now were disabled. On the 'Zoom' screen is drawn in detail the diffractogram in position near the cursor. The cursor consists of two lines when the box **Kalpha 1-2 pointer** is marked: The red mark the position  $K\alpha_1$  and the green  $K\alpha_2$ . In the **File** box have been deployed all four files are loaded. You can select any of them with the left mouse button.

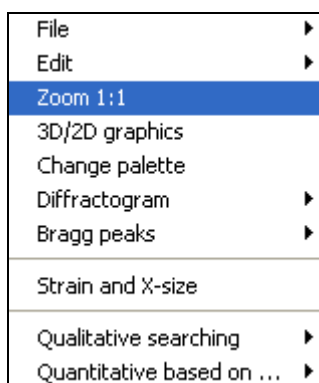
The lower graph shows the entire diffractogram and allows zooming using a 'click&drag' of the mouse. The region of interest is then displayed on the upper graph (for example  $49 < 2\theta < 56$  in the example of figure 1.4). To zoom directly in the upper graph, the **Shift** key must be pressed during a left click & drag of the mouse.

On the main graph, a left click of the mouse button adds a peak position that will be taken into account in subsequent calculations (the program can also find peaks automatically).



**Figure 1.4.**

To restore the full-size diffractogram, click on the button **1:1** or use the contextual menu appears by right-clicking the mouse, as in Figure 1.5.

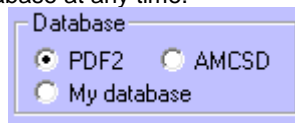


**Figure 1.5.**

The button **><** can also be used for zooming out.

In a similar way many routine tasks can be performed within this graph. For example:

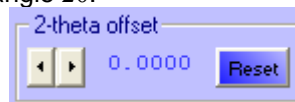
- Activate the cursor to display the position of  $K\alpha_2$   K Alpha1-2 pointer, and  $K\beta$   K Beta pointer. Also to display simultaneously several Bragg's orders  N Bragg orders 1
- Select or change the active database at any time.



- Enter the lower and upper  $2\theta$  limits.



- Show the values of the d-spacing  d-values and positions of the peaks  Bragg lines in the main graphic, where they have been previously calculated.
- Show HKL indices of the components previously identified  hkl in the main graphic.
- Correct the position of zero angle  $2\theta$ .



- Calculate the average intensity of a diagram and its standard deviation (useful for estimating the 'crystallinity' overall sample in a simple way) .  Average and st
- Identify with one click crystal components in the database with the active restrictions (chemical composition, subfiles, pressure, temperature, etc.).
- Advanced identification of crystalline compounds through restriction of chemical composition, observation window, Euclidean criteria, Boolean criteria, etc.
- Set the chemical and subfiles searching conditions. (Chapter4).
- Display peak positions and intensities of the phase highlighted in the search result window  Current
- Display peaks positions and intensities of all mineral selected in the search result window.  Checked
- Strip  $K\alpha_2$  (Chapter 3).
- Subtract the background. (Chapter 3).
- Smooth the data using Fourier transform smoothing or functional smoothing . (Chapter 3).
- Crop the  $2\theta$  interval of the main graph . This action removes the rest of diffractogram from the computer memory.
- Calculate the average intensity and standard deviation of full intensities  Average and st .
- Refine the unit cell without operator intervention  H.F. .

- Show the results of quantitative analysis and differences on the main screen.



- Save difference diffractogram with text PLV format.
- Acquire data from diffractometer (PLUS version only).
- Calculate or clear the values of d-spacings of full diffractogram. You can also add a peak with a left click or remove a peak by double clicking on it.
- Calculate or clear only the values of d-spacings of main screen selected zone.
- $2\theta$  zero shift correction by standard patterns or harmonic reflections methods (Chapter 3).
- Profile calculations, which include determining the Caglioti function for the sample (or instrument profile), quantitative analysis from the database, depending on the calculation of mixing, Williamson-Hall plot, and so on. (Chapters 10 and 11).
- Estimates of domain size and strain by means of Warren-Averbach methods. Calculating log-normal distribution. It is possible to apply automatically instrumental correcting by using a very crystalline standard or by calculation on the basis of the Caglioti and profile functions. (Chapter 10).
- Select active diffractogram color.
- Palette for diffractogram series.
- Select wavelength values.
- Interpolate experimental data using cubic splines that do not alter the shape of the profiles. It is useful in analyzing profile, unit-cell refinement, etc. (Chapter 3).
- Refine Unit-cell refinement. This option is best done when the samples have been previously identified and also the component  $K\alpha_2$  has been eliminated.
- Show pattern series in 2D and 3D (Chapter 8).
- Refresh screen, unload, reload and restore previous search data of actual diffraction pattern, with the buttons respectively.
- Reverse or eliminate negative intensities, reverse values, respectively . These are useful for manipulating calculated or differences diffractograms.
- Open files, print graphics and reports, save files, exit program respectively.
- Database install or update.
- Añadir una nueva ficha a 'Mydatabase.MyD'

- Occasionally undo the last change 

Small horizontal bars that appear on some command buttons perform the same operations as these, but above all the loaded diffractograms



Menu bar. Is at the top of the screen. It performs many of the button actions described in the preceding paragraph. Most actions can be selected using either method.

File Edit Tools Action Database Quantitative Stack Help

Clicking on any entry in this bar, opens a scroll-down menu:

### File

New	
Open	
Acquire	
Print	
Save changes	
Save changes as...	
Save graphic	
Export graphic as HPGL	
Save Log File as TXT	
Unload	
My favorite compounds	
Exit	Ctrl+F4

**New:** Start session.

**Open:** Load a diffractogram file.

**Acquire:** Load data from diffractometer (only PLUS version).

**Print:** Print graphics and scripts..

**Save changes:** Save changes of diffractogram data.

**Save changes as...:** Save changes a diffractogram data with a different file name.

**Save graphic:** Save BMP image of active graphic with the computer screen resolution.

**Export graphic as HPGL.** Create and save a HPGL (plotter file) that can be exported from some graphics programs like Corel Draw.

**Save Log File as TXT.** Create a text file that contains an echo of the calculations made and the results,

**Unload.** Download the actual diffractogram of the computer's memory.

**My favorite compounds:** To retrieve results of prior qualitative analysis (.RES for the PDF2 database and .RUF for the AMSCD database)

**Exit:** closes the application

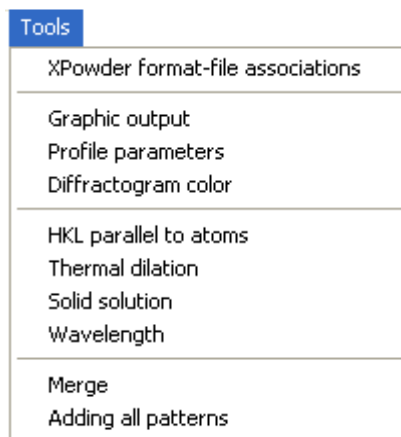
### Edit

Undo	Ctrl+Z
Copy	Ctrl+C

**Undo Ctrl.+Z:** Undo last change

**Copy Ctrl.+C:** Copy the diffractogram graphic on the clipboard.


## Tools



**XPowder format-file associations:** Allows associate files with extensions of the program XPowder so they can be opened automatically when you double-click on them in Windows Explorer or the desktop.

**Graphic output:** It sets up the options and features to be included in graphics printouts.

**Profile parameters:** Shows the parameters of the profiles of the reflections, both the active as the profile of the instrumental diffractometer. The values can be changed, but are not calculated from this option (for this we must use the

button  (Chapters 10 and 11).

**Diffractogram color:** Set de active diffractogram color.

**HKL parallel to atoms:** Calculates the indices HKL of a face parallel to two structural or morphological addresses.

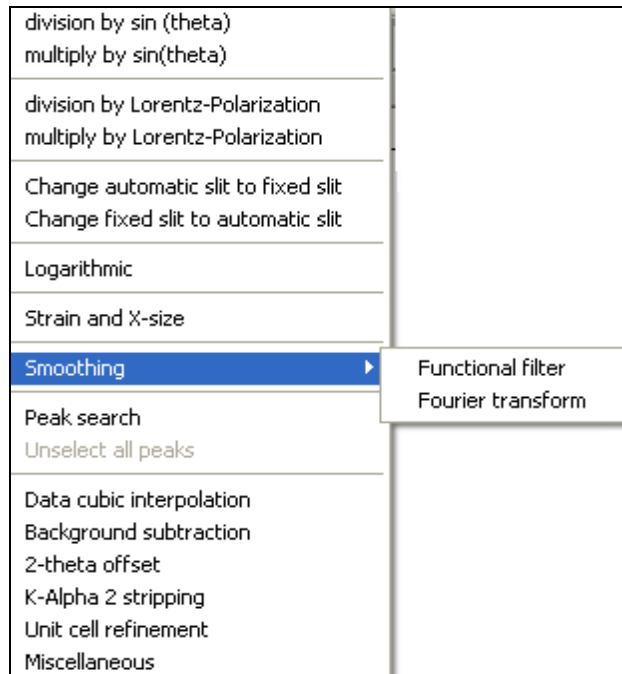
**Thermal dilation:** Calculates the thermal expansion coefficients if diffractograms are obtained at different temperatures. This tool operates automatically on the screen 2D, when used thermodiffraction.

**Wavelength:** Set wavelength values

**Merge:** Graphically sum or subtraction of diffraction patterns.

**Adding all patterns:** Calculate the average diffractogram of all loaded patterns.

## Action



**division by sin(theta):** Can simulate a change from fixed to automatic slit.

**multiply by sin(theta):** Can simulate a change from automatic to fixed slit.

**División by Lorentz-Polarization:** Performs Lorentz-polarization factor correction of powder diffractograms. It is useful in profile analysis.

**Multiply by Lorentz-Polarization:** Reverse of the previous operation.

**Change automatic slit to fixed slit.** Simulates the change from automatic to fixed slit in Bragg-Brentano geometry. The used function is  $I_f = \Delta^0 \cdot 0.20268 \cdot I_a / \sin(11.16 + \theta^0 \cdot 0.88 - 0.19)$

( $I_f$  = Intensity measured with fixed slit,  $I_a$  = Idem automatic slit,  $\Delta^0$  = divergence fixed slit).

**Change fixed slit to automatic slit:** Reverse of the previous operation.

**Logarithmic/Arithmetic:** Puts the intensities axe in logarithmic/arithmetic scale. Its use is highly recommended to localize reflections of low intensity, on very low crystallinity materials or having a great orientation. Use the arithmetic scale for qualitative and quantitative analyses. Do not carry out operations such as 'Ka2 stripping, subtraction of database profile cards, etc., when using the logarithmic scale.

**Strain and Size:** Profile analysis general tools.

**Smoothing:** Removes noise through functional and Fourier transform filters.

**Peak search:** Search maxima of Bragg reflections

**Unselect all peaks:** Unselect Bragg reflections.

**Data cubic interpolation:** Make a spline cubic not distorting, which allows interpolate experimental data without changing the shape of the profiles. It is a very useful filter.

**Background subtraction:** Perform background subtraction automatically.

**2-theta offset:** Tool for the correction of zero on the scale of  $2\theta$ , using internal standards or harmonics.

**K-Alpha 2 stripping:** The component  $K\alpha_2$  of diffractograms obtained with X-ray tube is removed. It is necessary for many calculations profile based on widths of reflections and highly advisable before unit-cell refinement.

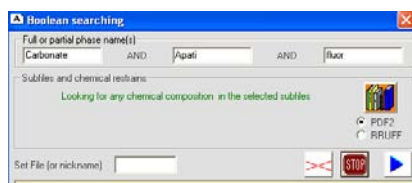
**Unit cell refinement:** Automatic unit-cell refinement.

**Miscellaneous:** Profile calculations, which include the Caglioti function fitting for the sample (or instrument profile), quantitative analysis from the database, depending on the calculation of mixing, Williamson-Hall plot, and so on. (Chapters 10 and 11).

## Database

Database Boolean searching
Advanced searching
One click searching
Recover searching
Database options
Database Update

**Database Boolean searchig:** Allows a manual search of records from the database by 'Set-File', key words, names, chemical composition, and so on. This example shows how to search apatite containing fluorine and carbonate anions



in the base PDF2 with the options active (PDF2) which are explained in Chapter 4. If the PDF2 set and file '5 586 ' are introduced in the box [Set File \(or nickname\)](#) , the program will return the record of the mineral calcite. If this box is introduced any nickname, described in the file 'Favorites.txt', or part of it, the program will return the record with the same nickname (Chapter 12).

**Advanced searching:** Advanced identification of crystalline compounds through restriction of chemical composition, observation window, Euclidean criteria, Boolean criteria, etc. (Chapters 2 and 4).


**One click searching:** Identify with one click crystal components in the database with the active restrictions (chemical composition, subfiles, pressure, temperature, etc.).

**Database options:** Set the chemical and subfiles searching conditions. (Chapter 4).

**Database install (or Database Update):** Allows you to install (or reinstall) a database (PDF2.DAT or DifData.txt).

[Home](#)

## Chapter 2. Searching advanced options

This section (Figure 2.1.) is accessed from the main screen(Figure 1.3.) by clicking on the button .

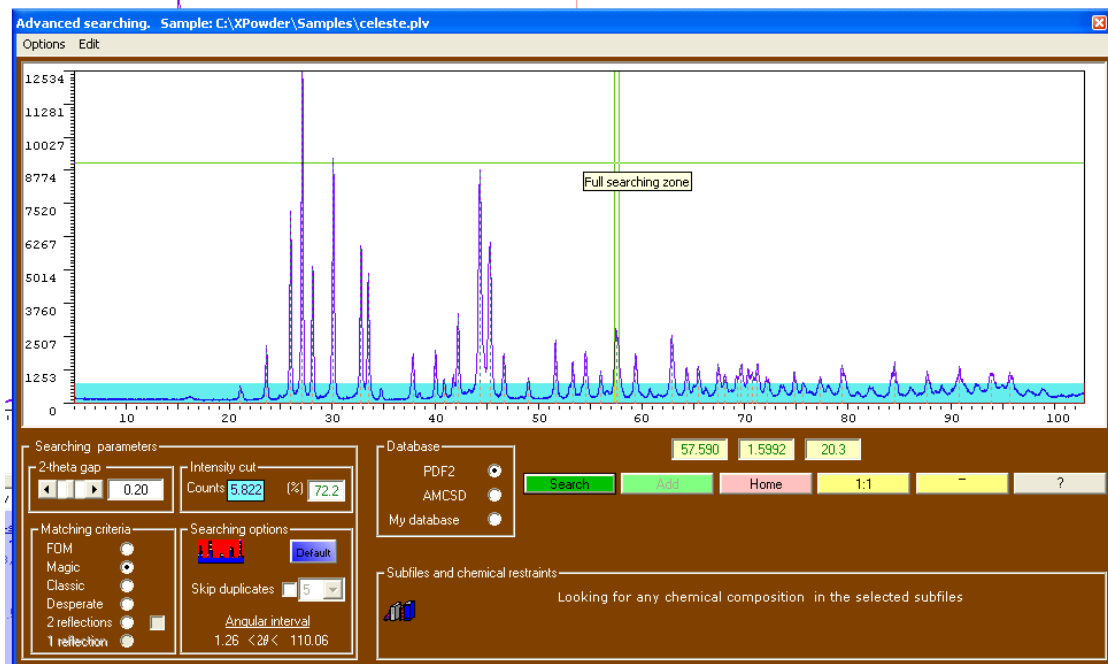



Figure 2.1.

The graph of this screen shows the diffractogram with the zoom level used in the main screen. You can get a greater detail by pressing the **Shift** key and dragging with the left mouse button on the chosen area. The button **1:1** rescale the diffractogram to full size, while the button **-** diminish the scale gradually.

When you move the cursor on the graphic the values  $2\theta$ , spacing and intensity show respectively in the three boxes (back yellow, green numbers) are located above the key **Main**.

The **sky blue area** of the bottom of diffractogram 'hidden' reflections of lesser intensity. The optimum height is calculated by the program itself. The peaks hidden will be taken into account during the search but as an incidental, so that components minority might go unnoticed in these conditions. The height of the blue zone can be changed by clicking on the desired height with the left mouse button. The value of cut is reflected in the box **Intensity cut**. The **sky blue area** can be overridden by pressing the button , or restored to its original value with **Default**. It is convenient to use the blue zone during the early stages of identification in samples with many components. In later stages, and without it you can establish the components minority.


When you check the box **Skip duplicates**  **5**, you can select the first N letters of the name of a crystalline phase, so that the program will choose the best card in the database for that chain letters. In the example, assume that the sample contains the mineral 'Celestine', which is ten or more records in the PDF database, and five in the AMSCD database, will show only the best suited and whose name begins with the string 'Celes' (5 characters). The program distinguishes between phases removed from the database (Deleted in PDF2) of the active. Thus, identifying where the criterion be applied **Skip duplicates** show results as possible 'Celestine' and 'D Celestine' in the example above. The first letter D is used to mark the card as deleted. If during the search you want to discard the deleted records see Chapter 4.

Within the framework of search parameters **Searching parameters** you can select the interval **2-theta gap** that the program used to consider as a reflection observed.



This value corresponds to the width ( $2\theta$ ) of the distance between the two vertical green lines in Figure 2.1. It is appropriate that this value is given to excess. Very small values may prevent some compounds are not 'observed,' what happens when diffractometers are poorly aligned or records from the database are of low quality. The default value (0.20) is usually valid for the majority of cases.

On this screen you can select the active database (PDF2 o AMSCD).

The order  allows you to select specific subfiles within each database (minerals, organic compounds, and so on, inside PDF2, or PT conditions within AMSCD) and chemical restraints (for example, you can search for Fe, Mg or Ca carbonates). The use of this tool is shown in Chapter 3. The restrictions were activated show next to this icon ([looking for...](#) en la Figure 4.1.).

[Matching criteria](#) box lets you select between four criteria for identifying phases. All of them are based on numerical taxonomy methods in a multidimensional space where, the minimum Euclid hyperdistances ( $H$ ) between the data of problem diffractogram ( $M_o$ ) and of the database ( $M_c$ ) are calculated. The differences between the methods lies in the different ways in which defines the axis of multidimensional space:

$$H^2 = \sum (M_o - M_c)^2$$


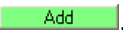
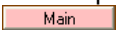
To find  $H$ , you must use only reflections inside the  $2\theta$  selected interval. Therefore, the zoom should not be used to analyze the complete diffractogram in searching procedures. The zoom should be used only when you want to identify reflections and isolated minority phases.

- **FOM** . The axes contain 'figures-of-merit' dependents of  $2\theta$ -zero error of diffractogram. Should not be used when the diffractomet is badly aligned or the database records are poor quality.
- **Magic** . The axes contain 'figures-of-merit' independents of error of zero diffractometer, the database and the coincidence of reflections from various crystalline phases. **Often the most effective approach for identification.**
- **Classic** .The axes contains d-spacing values, although XPowder automatically corrects the corresponding values of the databases, agree to normalized experimental conditions, before proceeding to the calculation of hyperdistances. This criterion should not be used this approach when there are many similarities between  $2\theta$  angles of different components, the diffractometer is poorly aligned or database records are of poor quality.
- **Desperate**. The program uses only two reflections of experimental diagram and optimizes its agreement with the database. Should be used only in diffractograms of very low quality or for minor phases. The second option approach '**Desperate**' is not affordable by the user, but is selected exclusively by the program itself in cases that do not appear obvious solutions or when you have selected a single reflection of the experimental diagram.
- **2 reflections**. Since version [2004.04.54](#) has been including a new approach that uses only two of the diffractogram reflections to maching with the high intensity reflections of database records. When this option is used, the number of possible solutions is high in general, due to the lack of information used in the calculations. It is therefore appropriate to provide supplementary information to the program (about chemical composition, for example). This approach should be used in diffractograms having small scanning intervals (eg  $2 < 2\theta < 50^\circ$ ), or for identification of minority phases. Also, from version 2004.04.54, the second searching options of '**Desperate**' has been



renamed to '1 reflection' , because it uses in searching one selected reflection only. (See [updates](#)).

The hyperdistance value (H) is considered by the program as a key criterion for the identification and its value appears in the output table ('Matching' tool, Chapter 5).

The search begins when you press the button . Alternatively you can complete the list of subsequent phases identified with the button . The button  does the program go back to the initial screen without performing any search.

The ability of this program to search for and identify compounds is high because of their special characteristics:

- The algorithm that uses the approach *Magic* improves, more than any other, both the quality of experimental data as those from the databases.
- During the search process (searching), XPowder standardizes the value of the wavelength. To do so reads the value of radiation used in each database record and correcting the position of maximum for the radiation used in the diffractogram problem, regardless of d-spacings write in the database. The process takes place even if the discrepancies in values of wavelengths are minimal. For example, some records have been obtained with wavelength  $K\alpha_{\text{average}}$ , while others have been developed with  $K\alpha_1$  or even with other radiation differently. This does not affect the algorithm for calculating used by XPowder, but the criteria used by other searching programs.
- After obtaining the best match by calculating hyperdistances, a second approach is performed. Then, each database records is adjusted to the experimental by nonlinear least-square methods. The their possible misalignments of  $2\theta$  are refined again. The standard deviation obtained during the procedure allows to specify the phase, within the list of substances identified by the calculation of **H**. Furthermore, adjusting the fractions (**f**) of the mixing function (**F**) of each component (**c**) for each angle  $\theta$ , so that:

$$F_{\theta} = (\sum I_{c\theta} \cdot f_c) / \sum f_c$$

$I_{c\theta}$  are the intensities of each component in the angle  $\theta$ . Therefore, allow  $f_c$  values estimated preliminary weighting of each component between 0 and 1 (see Figure 5.2:  $f_c = \text{Weight} = 0.75$  corresponds to the weight of celestine in the global mix function).

These operations, unlike those used in the calculation of **H**, are made on the whole diffractogram, whatever the used zoom.

- The results are displayed in a single list (Chapter 4) that can interact graphically (matching) with the experimental diffractogram. Optionally, you can subtract gradually phases identified in the original diffractogram (see Chapter 5. [Card profile](#) , Figure 5.7). This, which is not normally required, can occasionally facilitate the identification of minority components. On the other hand, can be superimposed graphically diagram experimental records from this list, one at a time, or all considered correctly identified.

[Home](#)



### Chapter 3. Pattern filtering

In general there is no need to make any special treatment from the diffraction data, but when the experimental conditions are not ideal, some tools can be used to improve quality.

#### 1. Zero 2θ offset angle correction.

(See also update 2010.01.10: [Planar CCD geometry](#), [Polynomial 2θ fit](#))

XPowder has two methods to to correct the error of 2θ zero:

- Correction with internal standard.

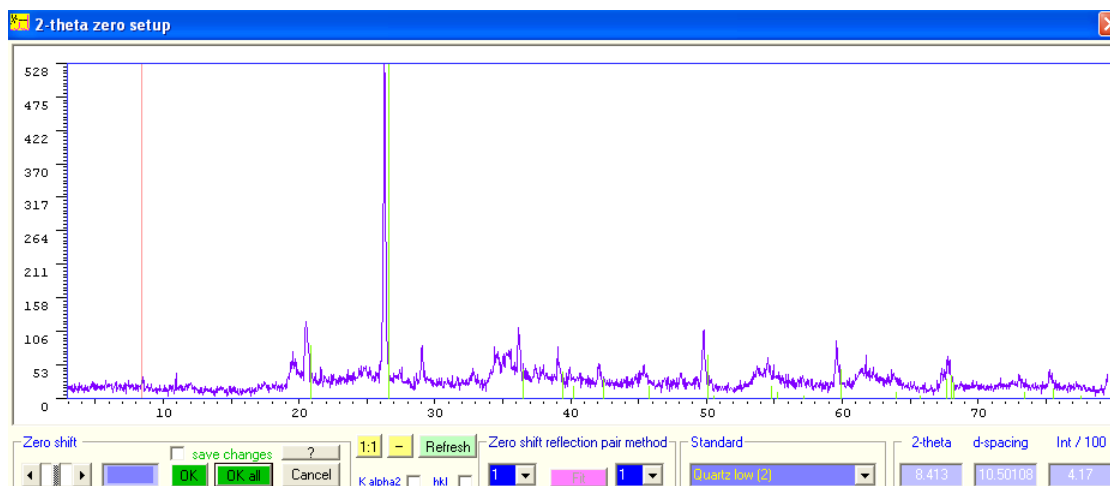


Figure 3.1

In Figure 3.1. an internal standard, which can be selected from the list of the frame **Standard** (*Quartz low (2)* in the example), is used to verify experimentally the displacement of 2θ. The internal standards can be included in the file manually 'std.txt' as described in chapter 12.

You can 'zoom' on the area  $20 < 2\theta < 30$  for more precisión (Figure 3.2).

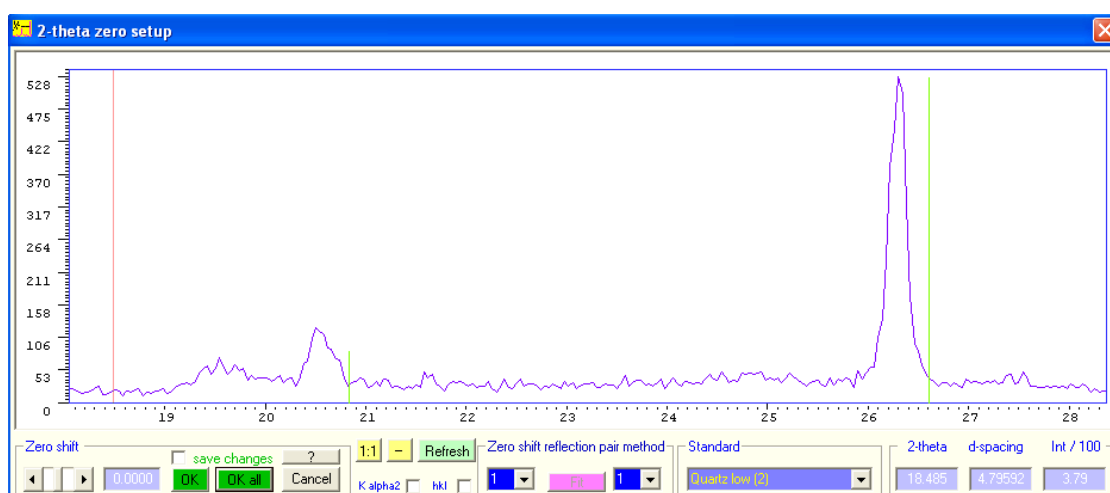



Figure 3.2.

With the tool  can move the diffractogram its true position (Figure 3.3) and shows the movement made (-0.0480) in the framework **Zero shift**.

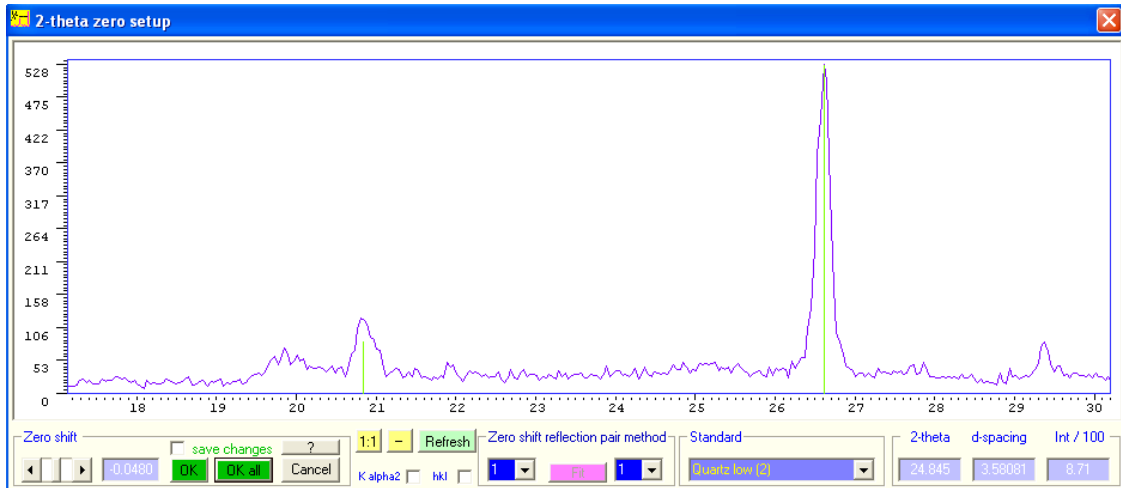


Figure 3.3

- Correction  $\Delta 2\theta$  through harmonics.

To apply this method will require two different orders of a reflection, that appear on the angles  $\theta_1$  and  $\theta_2$  respectively.

When there is a shift of the origin  $\Delta_0$  of the scale of the angle  $\theta$ , the equation of Bragg requires:

$$n_1 \cdot \lambda = 2 d \sin(\theta_1 - \Delta_0)$$

$$n_2 \cdot \lambda = 2 d \sin(\theta_2 - \Delta_0)$$

$$N = n_1/n_2 = \sin(\theta_1 - \Delta_0) / \sin(\theta_2 - \Delta_0)$$

$$N = (\sin\theta_1 \cdot \cos\Delta_0 - \cos\theta_1 \cdot \sin\Delta_0) / (\sin\theta_2 \cdot \cos\Delta_0 - \cos\theta_2 \cdot \sin\Delta_0)$$

If numerator and denominator are divided by  $\cos(\Delta_0)$

$$N = (\sin\theta_1 - \cos\theta_1 \cdot \tan\Delta_0) / (\sin\theta_2 - \cos\theta_2 \cdot \tan\Delta_0)$$

$$\tan\Delta_0 = (\sin\theta_1 - N \sin\theta_2) / (\cos\theta_1 - N \cos\theta_2)$$

it appears the error of angle  $2\theta$ .

$$\Delta_{2\theta} = 2 \cdot \Delta_0$$

To carry out the correction, you should select two orders of a reflection of Bragg (could be any, even non-consecutive reflections) within the frame [Zero shift reflection pair method](#). In Figure 3.4, have been selected respectively orders 1 and 2 (you'll see the cursor corresponding graphs from  $n = 1$  to 2). By placing the cursor  $n = 1$  on the first reflection (approximately 18.6 degrees) shows that the position of second order is not correct (the second cursor, approximately 17.7 degrees). Pressing [Alt + left mouse button](#) is automatically carries out the correction, as shown in Figure 3.5.

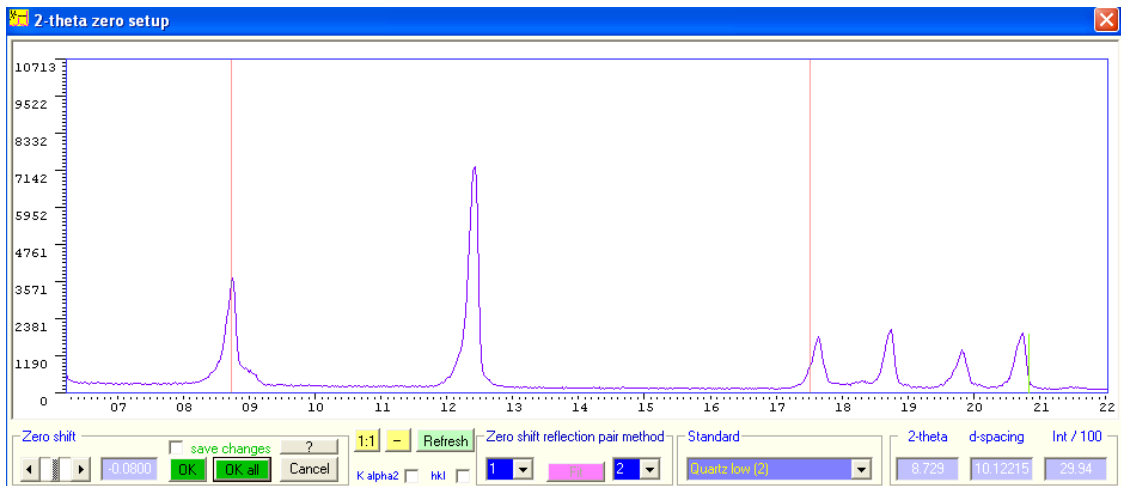


Figure 3.4. Before correction of zero 2 $\theta$ .

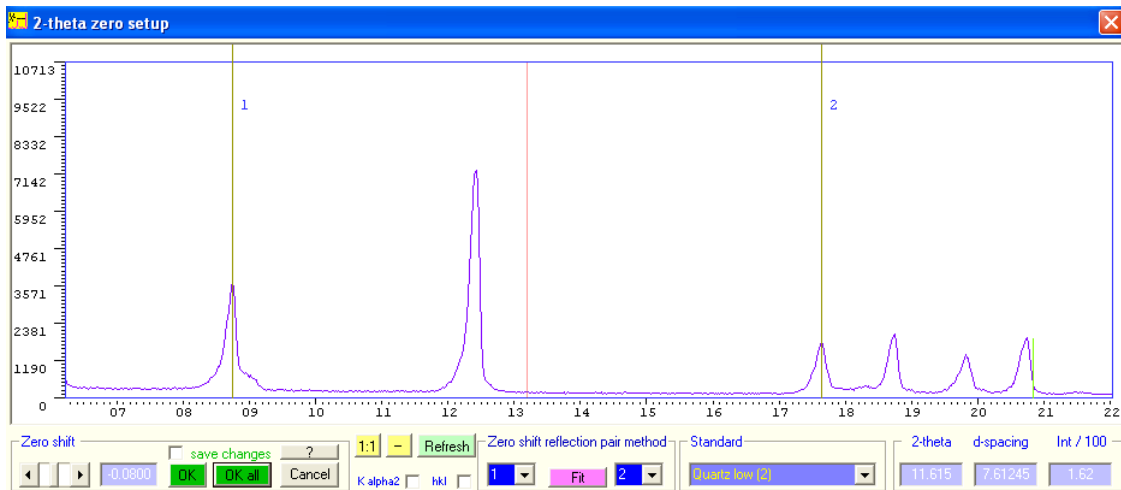
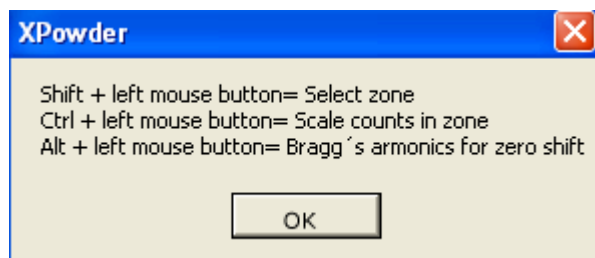




Figure 3.5. Has been detected and corrected a displacement of  $-0.0800^\circ$ . The correct positions of the two reflection orders are marked with their respective values of  $n$ .

In either of the two methods described, when pressed **OK**, the program returns to the main screen. **OK all** states the same correction for all samples are loaded into memory (up 50). If the box **save changes** is selected, in addition to the above, the data files are saved on your hard drive. **Cancel** reject the changes. **?** shows a help on using this screen).



## 2. Elimination of noise.

Lets remove small and frequent fluctuations of the diffractogram registration. Any action of this type should retain the geometry of the profiles, which otherwise would leave inoperative diffractograms in order to study of profile analysis. X Powder uses two methods:

- Functional filter. There is an average weighted by a continuous distribution function characteristic of the diffractogram. Every calculation is done automatically by pressing the button  or menu '*Action -> Smoothing -> Functional filter*'
- Fourier transform. Removes higher frequencies in the Fourier transform using a cutoff value and then calculates the inverse transform, which gives us the filtered diffractogram. Is accomplished by pressing the button  or menu '*Action -> Smoothing -> Functional filter*'. The Figure 3.7 shows how to handle tool for the Fourier filter.

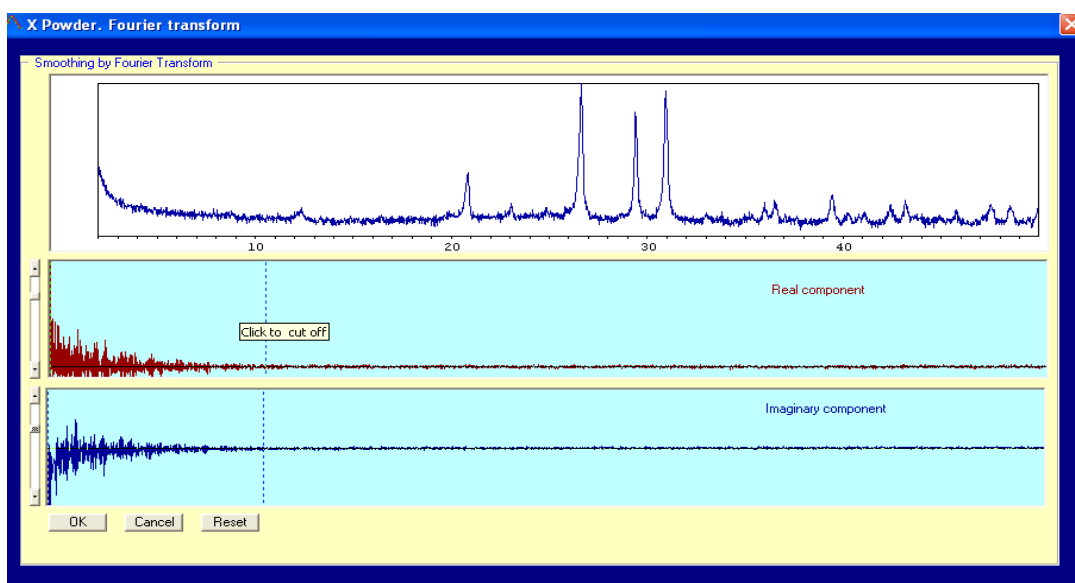


Figure 3.6. Clicking on the position of the cursor eliminates the frequencies located on your right and you get the filtered image of Figure 3.8.

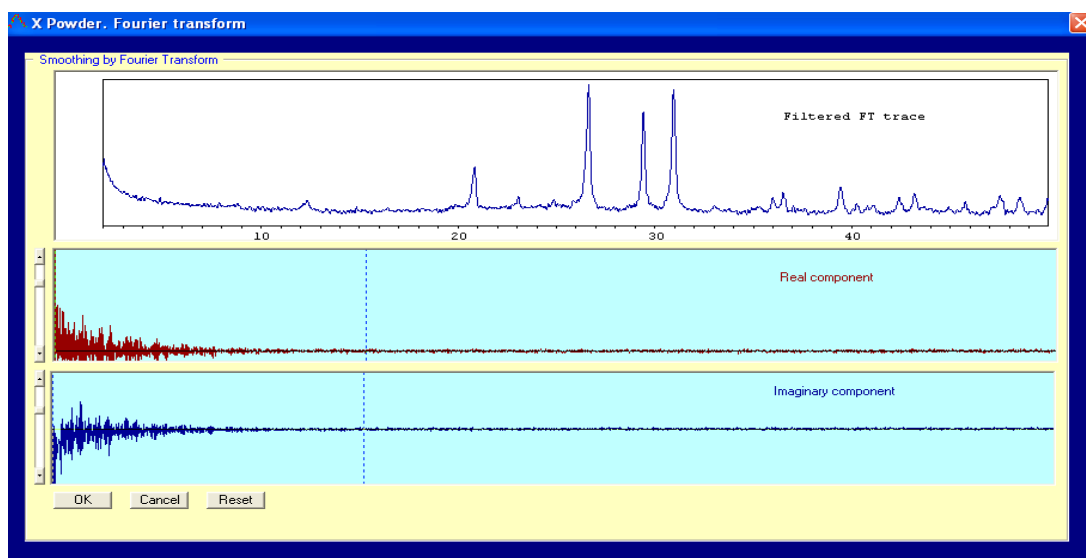


Figure 3.7. The smoothed diffractogram can be seen at the top.

[Home](#)

### 3. Background subtraction.

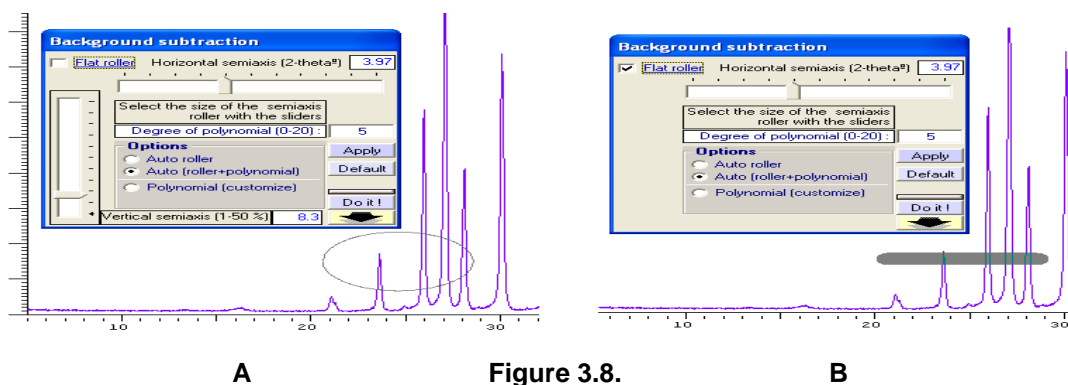


Figure 3.8.

An **ellipse** (Figure 3.8A, **Flat roller** box unchecked) or a **segment** (Fig 3.8B, **Flat roller** box checked) can be used interchangeably, to automatically search for points where the background polynomial will be calculated by LS methods. The horizontal cursor (*and/or* vertical) provide the magnitudes of the semiaxes of the ellipse (*or segment*) that will cross the lower diffractogram and whose contact points will be used to calculate the background function by *splin* (**Auto roller**), *splin* + *polynomials* up to grade 20 (**autoroller+polynomial**) or tracing the background of manually selected points (**Polynomial customize**). The buttons **Do it!** perform background subtraction on the active diffractogram (*large button*) or on all diffractograms loaded (*top bar*) with the selected options. Figure 3.9. and 3.10. Large ellipses yield a soft elimination of the background while small ones suppress the background completely. Different ellipse sizes should be tried.

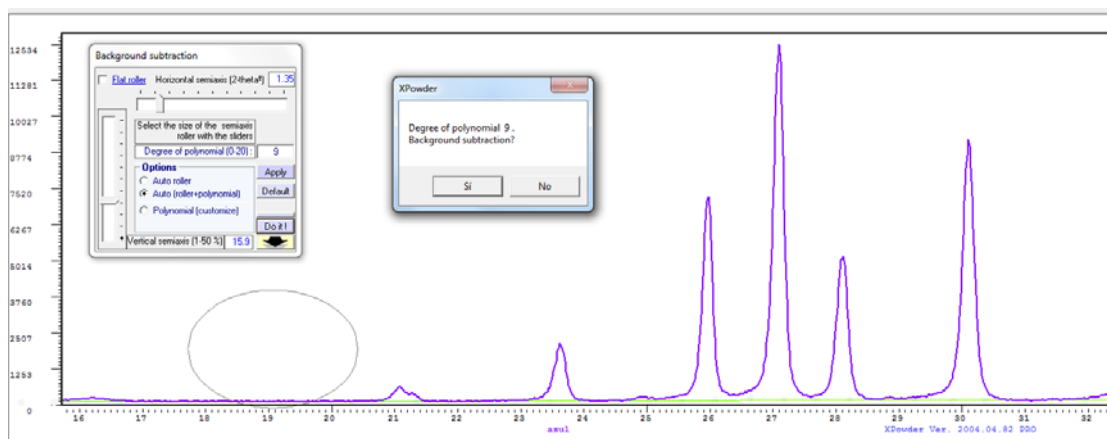


Figure 3.10.

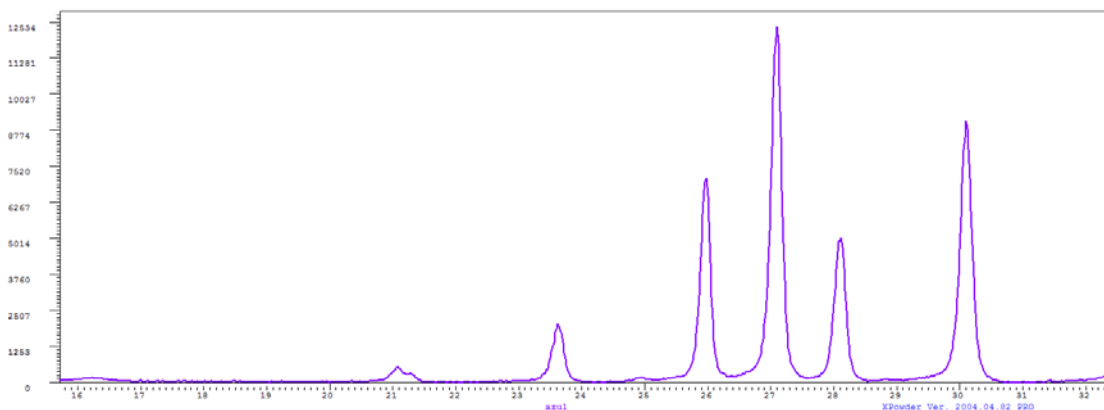



Figure 3.11.

#### 4. $K\alpha_2$ stripping.

It uses the Rachinger method in its classic form, or in a dynamic modification that optimizes the adjustment of the distribution functions of the profiles that are  $K\alpha_2$ -stripped in succession during the  $2\theta$  scanning. The method 'Advanced', which uses methods of Fourier on reciprocal histogram, is temporarily out of order in the current version.

For proper  $K\alpha_2$  stripping, use very accurate values of  $\lambda_1, \lambda_2$  and  $[I\lambda_2 / I\lambda_1]$  (use  when necessary).

The process is applied to a diffractogram (XPowder\_program\_dir\Examples\Quartz60\_70.plv) that shows the quartz reflections 113, 300, 212, 203 and 301 (figures 3.12 to 3.14).

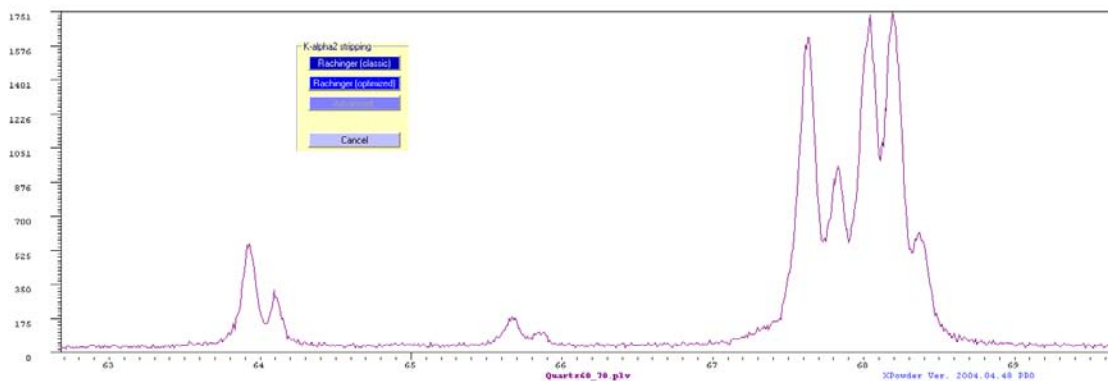


Figure 3.12.

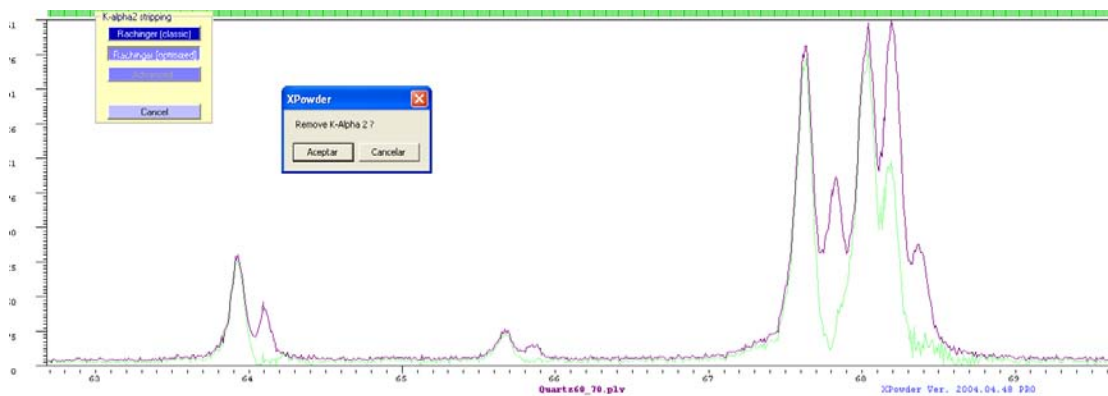


Figure 3.13.

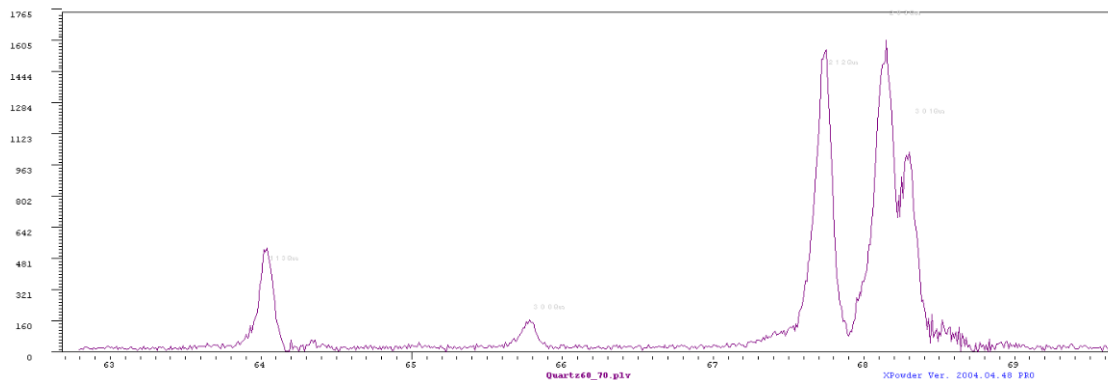


Figure 3.14.



## 5. Changing 2 $\theta$ step.



This procedure significantly improves, without the slightest deformation of the profiles, the quality of measured with an excessive step diffractograms. This operation is very useful, as it happens prior, to improve the quality of  $K\alpha_2$  stripping, profile analysis or unit-cell refinement (Figures 3.15 and 3.16).

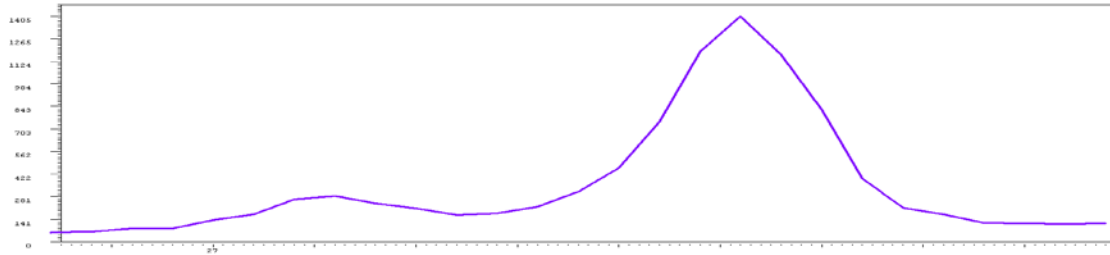


Figure 3.15.

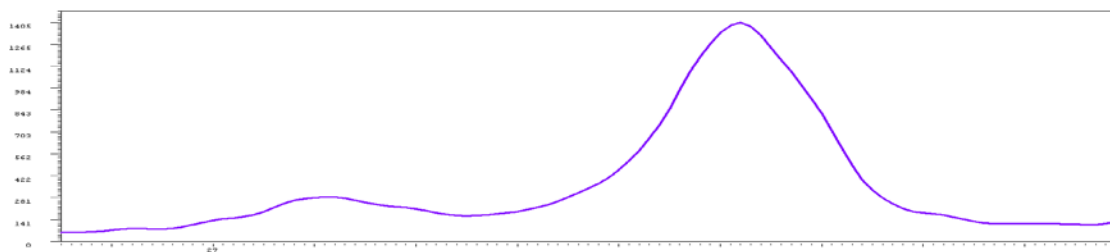


Figure 3.46.

## 6. Merging diffractograms (Main menu $\rightarrow$ Tools $\rightarrow$ Merge)

This routine makes weighted additions and subtractions of diffractograms.

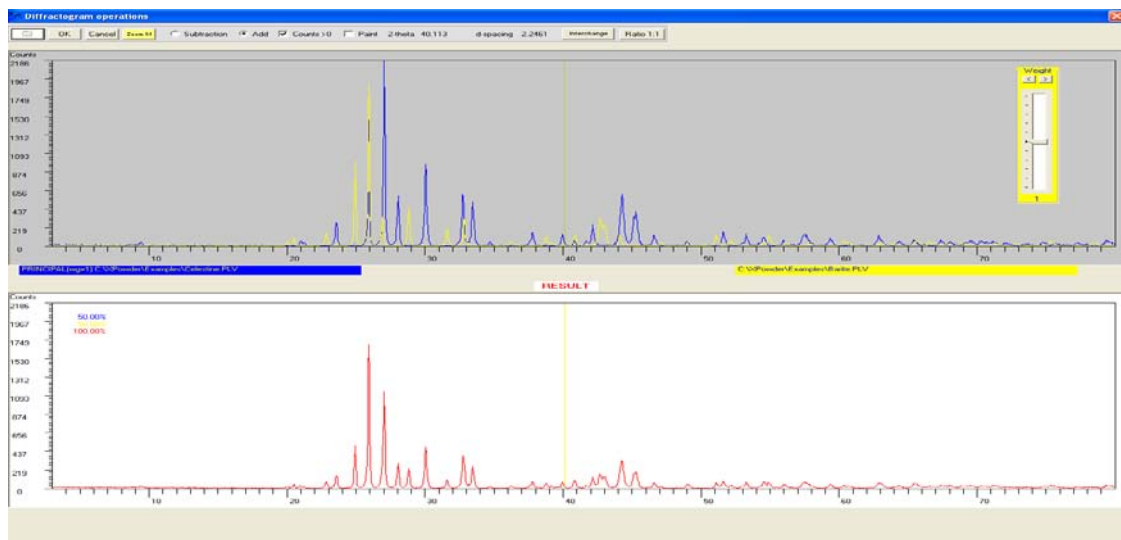


Figure 3.17.

You can add **ADD** or subtract **Subtraction** diffractograms. The top of the Figure 3.17 shows the main diagram in blue and the secondary in yellow. The bottom image shows the sum of 50%.

**OK** Moves diffractogram calculated to the main screen. Caution: The program maintains the same file name that was the main diagram.

**Cancel** Discard all operations and returns to the main screen.

[Zoom 1:1](#) Lets scale the charts to the original size. It is used when it has made 'zoom' up on this screen.

[Paint](#) Fill color the main diffratogram.


[Interchange](#) Swap the main and secondary diffractograms.

[Ratio 1:1](#) The two original diffractograms have the same weight.

[Weight](#) Slider cursor that lets ponder the diagram secondary.

[Home](#)

## Chapter 4. Searching subfiles and chemical restrictions.

The entrance to this screen (Figures 4.1. y 4.2.) from the 'main screen' or from other parts of the program by clicking the button  (Advanced Options on qualitative analysis).

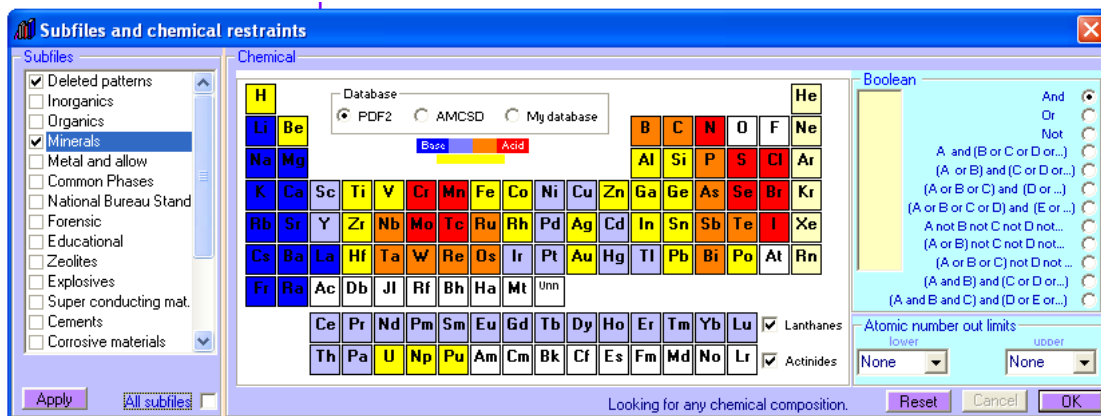


Figure 4.1. PDF2 advanced searching options

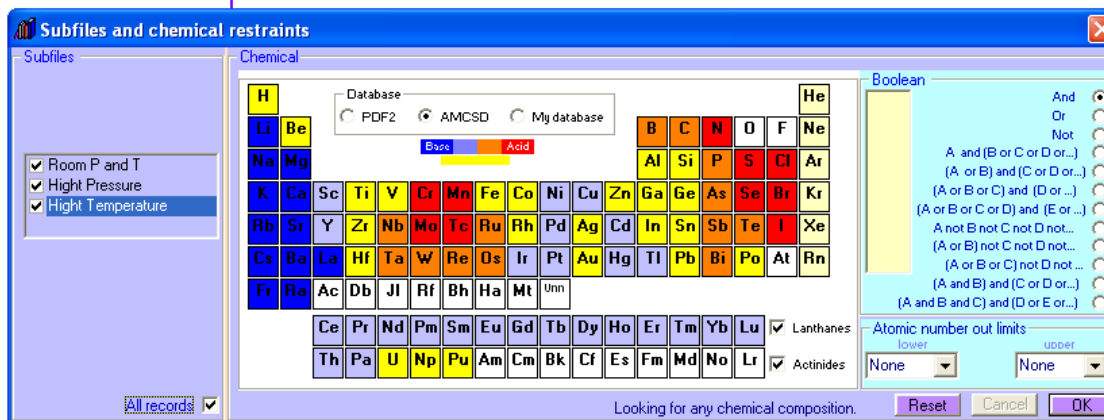


Figure 4.2. AMCSD advanced searching options

On both screens, the database can be exchanged, select subfiles or put restrictions on chemical composition using Boolean logic (And, Or, Not and combinations).

The subfiles of each database are selected in the box **Subfiles**. The **Apply** button in Figure 4.1. establishes what the selected subfiles will be loaded the next time you start XPowder (default setting when using PDF2).

### Chemical restrictions:

In a general way you can discard previously in searching phases containing elements lanthanides or actinide (leaving unmarked respective boxes), elements with atomic number **Lower** than stated, or higher than those given in **Upper** box. The hydrogen is excluded from these restrictions.

## Boolean conditions:

You can choose up to 11 different chemical elements that are involved in the search for components of the sample. To select just click on the symbol in the periodic table of Figures 4.1. or 4.2. A new push on the box, delete the item from the list. **Reset** button removes the list. All items selected must into the chemical composition of the crystalline phase.

- **And:** All selected elements must into the chemical composition of the crystalline phase.
- **Or:** At least some selected element should belong to the chemical composition of the crystalline phase.
- **Not:** None of the selected elements must belong to the chemical composition of the crystalline phase.
- **Logical combinations:** The three previous operators can be combined by selecting one of the options under **Boolean** framework. It should be noted that the brackets have priority over the logical operators and therefore, any operation between parentheses will be carried out before the rest. The order in which chemical elements are selected is the same generic sequences of A, B, C, etc. displayed within each of the options under **Boolean**.

## Example

Figure 4.3 shows, for example, how to find carbonates Mg, Ca, Fe or Mn in the subfile 'Minerals' of the database PDF2. The deleted patterns will be taken into account during the search, as indicated in the **subfile** framework. The selected items are drawn with black background in the periodic table and the sequence is on the list of yellow background, under the title of **Boolean** framework. The complete logic condition appears developed in the bottom of the screen:

Searchig for ... (C and O) and (Ca or Mg or Mn or Fe)

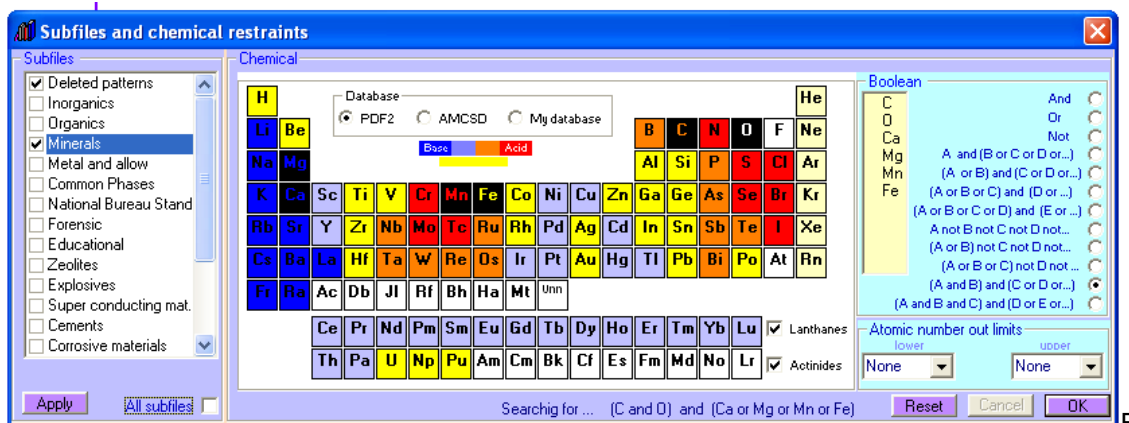


Figure 4.3. Chemical searching restriction with PDF2.

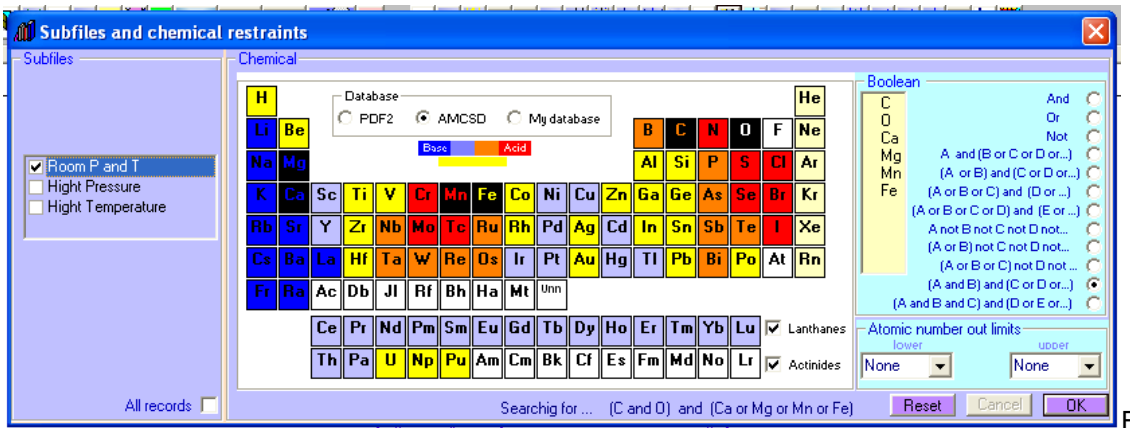


Figure 4.4. Chemical searching restriction with AMSCD.



Figure 4.4 shows the same as in Figure 4.3, but with AMSCD database. In this case, the searching will be made on minerals formed at room temperature and pressure.


The **OK** key confirms the search conditions selected, while **Cancel** ('disabled' in the examples) ruled out any changes made, but does not affect the selection of subfiles.

[Home](#)



## Chapter 5. Searching and matching.

The identification (searching) of substances can be obtained from the home page (Figure 1.2) manually by using the 'Database-> Database Boolean Searching' and automatically with the keys  (One click searching) or  (Advanced searching):


 This button performs the search completely automatically, using the search options active at that time (see Chapter 4).

 This button will display 'Advanced Options' described in Chapter 4, before performing the search.

In all cases, the results appear on a 'floating' list into the tool **Matching**, critical to correctly identify and confirm the crystalline components (Fig. 5.1).



Figure 5.1.

Figure 5.2 shows the tool Matching (ver 2004.04.57) in detail. The example was created from a sample of monomineric Celestine - Sr (SO<sub>4</sub>) after using the key  (One click searching) on the mineral PDF2 subfile, including the *deleted phases*. Each file contains from left to right, a check box where it should be confirmed () the presence of the mineral. Then there are a six number string that correspond to the 'Set' (first two digits) and 'File' (the other four) of the database. The following is the *Euclidean hyperdists* that has allowed the identification (smaller is better in terms of the adjustment). Following is the name of the previous stage, or not, the letter D, indicating that the file has been deleted from the database. The **blue flag** is on the first line because is the best full least-squares fit of the possible records. It is noted that all first solutions are 'Celestine', because this mineral appears repeatedly in the database.

It can select (or discard) the crystalline phases identified correctly by ticking the appropriate box, or pressing the keyboard **space** on the active line. You can also use the **Del** key to remove lines and keys **Up**, **Down**, **Page Up**, **Page down**, **Home** and **End** to move on it.

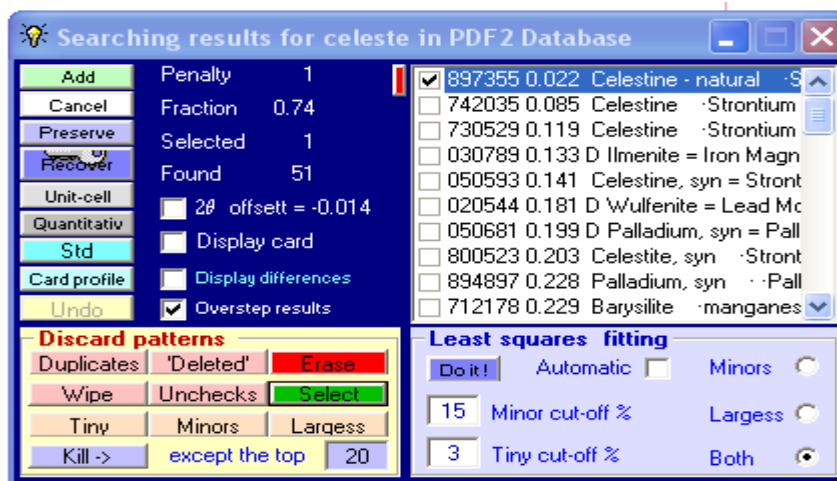


Figure 5.2. 'Matching' tool. Results with PDF2 database. (Please see updates Chapter)

To avoid the recurrence of similar results, ticking into the box [Skip results](#), as explained in Chapter 2, figure 2.1. In this case, the best solution is shown as in Figure 5.3, where the mineral 'Celestine' appears only once.

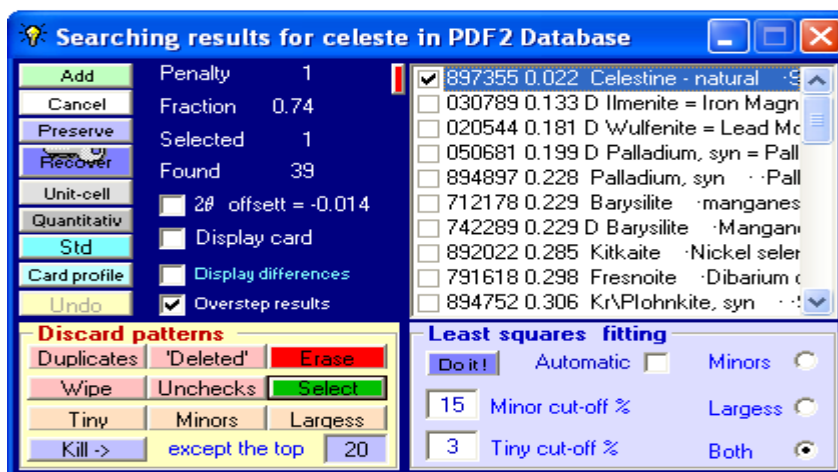


Figure 5.3. The box [Skip duplicates](#) was ticked in advanced searching options.

The remaining suggested phases (D Bopurnonite, etc.) have an excessive hyperdistance, so it will be to select as the most likely phase "Celestine" (box is marked ✓). To discard the rest has been pressing [Uncheck](#).

Similar results can be obtained with the database AMSCD, which displays the list this time with blue color (Figure 5.4).



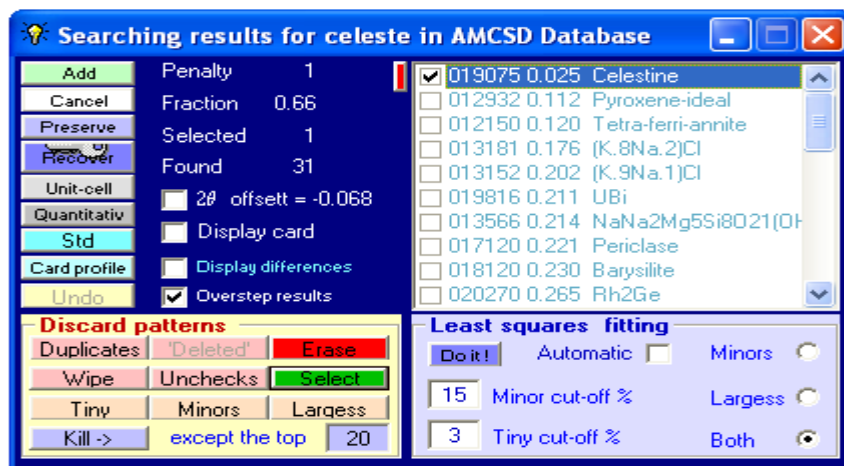


Figure 5.4. Results obtained from the database AMSCD. The Skip duplicates box is unchecked.

By clicking on any of the lines of the list, with shades of gray, a graphic overlay of the active record on the graphic pattern is made. If on the main screen ticked the  K Alpha1-2 pointer box also shows the positions of the bars for  $K\alpha_2$ . If, moreover,  K Beta pointer is marked, are shown in orange clear the positions of the bars  $K\beta$ .

In polimeric samples is the same way, but the list of suggested phases includes incorrect solutions and it should be analyzed using the 'matching' tool. The example of the Figures 5.5 and 5.6 shows qualitative analysis of a sample with four mineral components (etc.) on the subfile 'Minerals' of PDF2, without taking into account 'Deleted' cards and Skip duplicates with the option selected.

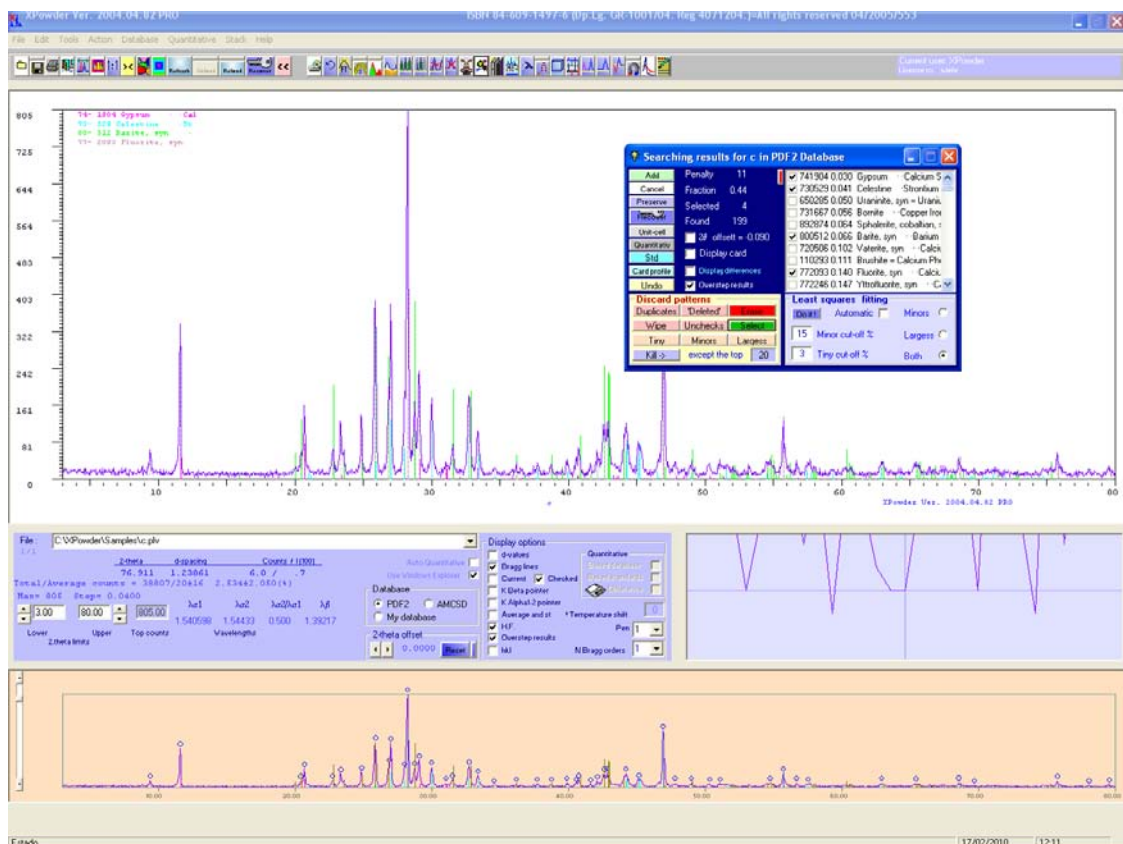


Figure 5.5

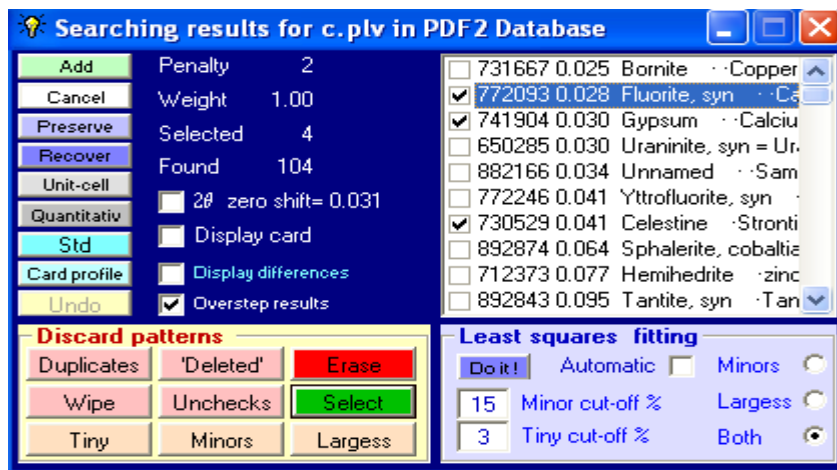


Figure 5.6.

Figure 5.7 shows the result list. It is noted that the phase with lesser Euclidean hyperdistance (0,025 bornite) does not match the one that best fits by least squares (0,028 Fluorite syn). It is for the user decides which ones are the most appropriate allocations. In this case, and given that some phases can be identified really isostructural terms of those obtained after a detailed analysis with this tool we reach the conclusion that these are shown in Figure 5.8. To be ticked the  Checked box, the bar charts of the database, automatically weighted, overlapped with the original using color codes. To stop the cursor on reflection, they show the rates of the reflections of each component (box with a yellow background on  $2\theta=26^\circ$  in Figure 5.6).

In addition to 'Set', 'File' and hyperdistance, the tool 'Matching' figure of 5.6 contains the following messages:

**Penalty**: Order on the list according to the hyperdistance.

**Weight**: It varies between 0 and 1. Is the fraction of heavy intensities of the database record that best fits the experimental.

**Selected**: Number of cards accepted and marked ( $\sqrt{\quad}$ ). The maximum value is 11.

**Found**: Number of phases suggested during 'searching'.

'Matching' commands (Figure 5.5.)

**Add**. It allows you to add to the list new results through new qualitative analysis.

**Cancel**. Rejects all the results and hide the tool.

**Preserve**. Saves the current results, which could be recovered, to be charged the same diffractogram subsequently, through the order **Recover**. Both orders appear repeatedly in other parts of the program. It also can be retrieved at any time from the menu on the homepage (for example to contrast or implement the results of this sample other of the same nature):

**File -> Mi favorite compounds**

**Unit-cell**. Lets unit-cell refinement of the crystalline phase corresponding to the actual card, both automatic or controlled way. (Horizontal blue flag in Figure 5.6). (See Chapter 9).

**Quantitativ**. It allows the non linear least squares quantitative analysis for of the phases identified including statistical and global amorphous stuff, overall from the database records. The program takes chemical composition and density from the database in order to calculate the linear mass absorption coefficients. If these data are not present in the database, the program assigns

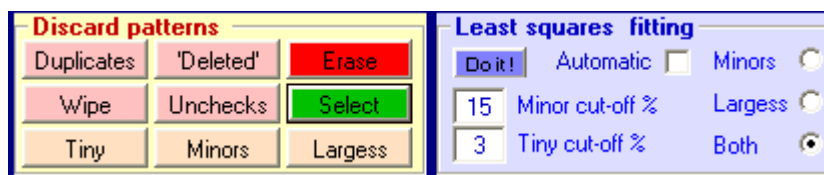
approximate coefficients. The overall mass absorption coefficient of the sample is calculated during the process. The program assigns the RIR factor (*Reference Intensity Ratio*) value of the card in the database. PDF2 use in this sense the coefficient 'I/Icor', which is usually wrong in most cases, as documented by the fact that there are numerous examples in which a single crystalline phase shows variations of up to an order of magnitude in the same database (for example, a mineral composition as invariant as is the quartz 'I / Icor' ranges from 2 to 20, leading to errors of up to 50% by weight and even mayors). Other times this factor is not included in some chips from the database. In conclusion, to ensure proper quantification each investigator must use their own values of the RIR coefficients. The best way to calculate it is through registration Diffractometer setting of a 'pure pattern' of each substance to quantify, 50% mixed and homogenized with another 'standard reference' stable (as far as possible and crystallinity homogeneous mass absorption coefficient similar to set of mixing problem). This often sometimes unlikely. The Corundum or synthetic (Al<sub>2</sub>O<sub>3</sub>) powder are often used as standard reference, after being passed through a 20 μm sieve. The RIR factor is calculated by dividing the maximum intensity of the reflection phase of the pattern pure by the intensity of the reflection maximum of corundum. But it is much better, though more laborious, making the ratio of the integrated intensities of all reflections of each phase. More details on the quantitative analysis are shown in Chapter 6.

**Std** It incorporates the record to the list of standard patterns (text file 'std.txt').

**Card profile** Allows the estimated diffractogram of the actual card for the active database (horizontal blue flag) in accordance with the standard profile of lines and Caglioti equation (see Chapter 10). Not included in calculating the asymmetry of the peaks, but if the box Kα<sub>2</sub> and, or, Kβ are activated in the initial screen, the corresponding profiles are calculated. Subsequently, the profile can be calculated subtracted from the original diagram. The latter can be used to highlight the remaining components of the experimental diffractogram residual. The asymmetry of the peaks is not included in the calculation, but if case of the Kα<sub>2</sub> and, or, Kβ boxes are activated in the main screen, the corresponding profiles are calculated. Subsequently, the calculated profile can be subtracted from the experimental pattern.

**Undo** It let recover the last database pattern erased by **Erase**.

Within the framework **Discard pattern** are buttons that enable solutions to eliminate recurring patterns (**Duplicates**), PDF2 'deleted' patterns (**'Deleted'**) or a particular solution (**Erase**). This last, clears the list of the active row (horizontal blue flag). Can be replaced by the key **Del** of keyboard.



**Wipe** Discard all results from the list.

**Unchecks** Erase all the results from the list that have not been marked. Can be replaced by the **Esc** keyboard.

**Select** It let select the actual pattern on the list. It is equal to clicking on the box  of the pattern list. Can be replaced by the **Espace** keyboard.


**Tiny** **Minors** **Largess** They eliminate respectively the tiny, minors and largess components according to values into the boxes **Tiny cut-off 5** y **Minor cut-off %**

**Do it!** Perform least squares fitting of better database pattern of list according to the selected button option (**Minors**, **Largues** or **Both**) . This button is unable in the case of **Automatic**  is checked.

**Others options:**

**Launching "MyDatabase.Myd"** (See also update 2010.01.10)

Following commands are used:   

 (Main menu). Write the actual experiental Bragg reflections in a new record in 'Mydatabas.MyD' (fig. 5.7)

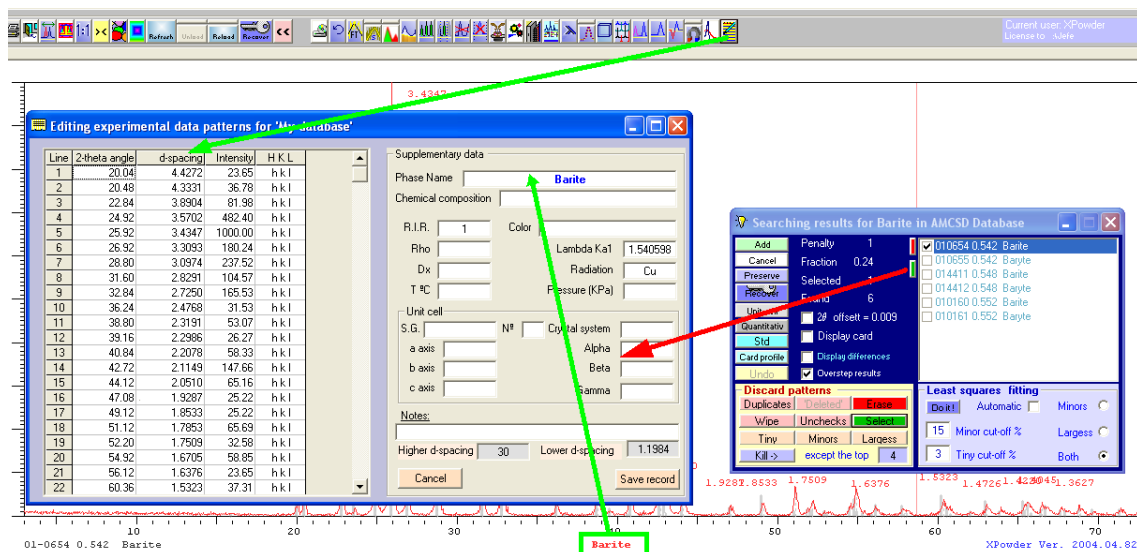



Fig 5.7

 Exports the crystallographic data of active database (no reflections) to the new experimental record file (Figure 5.8, data in red). This data can be edited before finally being recorded in 'Mydatabas.MyD' with the order **Save record**

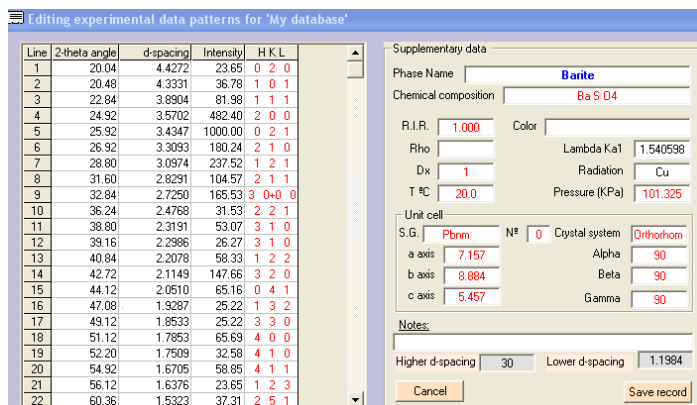


Fig 5.8

 Export directly the actual record of the active database to 'Mydatabas.MyD'.

The first pattern of "mydatabase" should be created with a diffractogram of our own laboratory diffraction. Thus, the experimental model for the rest of the database will be related to it.

**Display card**. When marked, the database record appears on a floating screen (Figure 5.7).

Others options :

**zero shift= -0.007** When marked, check the database record and corrects original 2θ error scroll (-0.007 in the example). Corrected values are graphically displayed on the main screen (*matching*).

**Display card**. When checked, the main features of database pattern are displayed (figure 5.7).

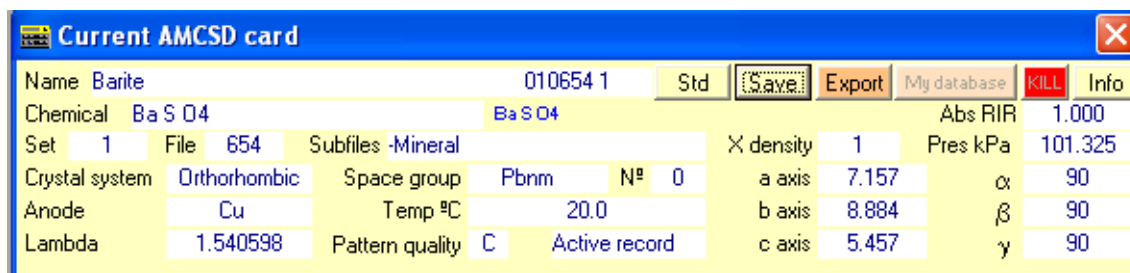


Figure 5.7.

**Export** Equal to

**Std** It incorporates the record to the list of standard patterns of the program (text file 'std.txt'). It is equal to

**Save** It creates the file 'Card.txt' with the actual data record information in the directory of the program.

**Info** Displays the full content of the original database record:

```

5.46378          N010772093  F  A772093C1 ^
0.00008          1  A          A772093C2
Fm-3m      225      4      3.179      163.11  A772093C3
Fm-3m      225      4      3.16A  3.179      78.08   163.11  A772093C4
I M FIZ          A772093C5
Calcium Fluoride          F  1A772093C6 v
  
```

**Display differences** When checked, and click the button , the difference diffractogram between the experimental and calculated patterns is drawn.

**Overstep results** When marked, the results list will apply to all diffractograms loaded. This option can be also selected on the main screen.

[Home](#)



## Chapter 6. Quantitative analysis by RIR (*Reference Intensity Ratios*) methods.

**Preliminary:** The phase quantification by X-ray powder diffraction methods is a complex process due to factors that mainly depends on dealing methods used in the diverse laboratories. Factors such the alignment diffractometer, type of slits, linearity in the response of radiation counters, uniformity in the size of grains of the sample, orientation linked to how to prepare the sample or the habits, etc make many published results are of an error greater than the one intended. Spectacularly wrong can be some results based on the measurement of the intensity of a single reflection corrected by factors of proportionality, in some cases obtained by different laboratories to own or taken from literature (*'Easy quantitative Analysis'*). Other more sophisticated methods, including the Rietveld method, can provide more precise solutions, but require an exquisite care in sample preparation, registration and in parameterization of diffractogram models, both instrumental and structural components. X Powder uses non-linear least square methods for full diffractogram opposite of a weighted combination of diffraction diagrams taken directly from the database (another method that will explain later -Chapter 7- is based on adjustment for diagrams Experimental patterns). It was subsequently corrected, within the possibilities it raises awareness of the pure phases, factors such as components and amorphous absorption. The same definition of 'component amorphous global' (Global Amorphous Stuff) should be taken in any case as an approximation to a reality that is described with difficulty. By using all reflections of each component makes it minimizes effects such as the preference orientation, but there is no doubt that not just the problem completely. So it is desirable, select those standard cards that fit the diffractograms, among the possible solutions found identical. It is very interesting in this sense to use the option [\[Skip duplicates\]](#), as the program adjusts the best database records among identical results. No less important is the election of appropriate RIR factors because they involved directly % weighting of each phase. Finally X Powder indicated that performs the calculations properly, according to well-established methods in general treaties of Statistics and Crystallography, so the quality of the final quantifications depends only on the modes of operation of each user.

Beginning with the 2004.3.1 update, X Powder incorporated into the professional versions a powerful tool that allows precise quantitative studies done by methods of nonlinear least squares on a full profile of the full diffractogram and that takes full advantage of the information contained in the database records. The analysis can be conducted on a isolated specimen or groups of up to 50 samples simultaneously. The weighting is achieved with the standard method RIR (Normalized RIR Method), described by Chung (1974: "Quantitative interpretation of X-ray diffraction patterns. I. Matrix flushing method of quantitative multicomponent analysis. Jour. Pf Applied Crystallography, v.7, 519-525). Another method much more accurate quantification will be explained in Chapter 7.

Although the initial versions, the amorphous components were excluded from this quantitative analysis, the program X Powder has the ability to generate a pseudo-RIR factor for the Global Amorphous Stuff that is optimized for each type of overall chemical composition, so that the program uses the 'experience' of previous analysis and optimizes the ratios as an 'historic' (this must be taken into account in cases where the program optimizes your values in the midst of an experiment in quantitative analysis, in which case it is recommended repeat all the calculations made in the same session). The pseudo-factor of amorphous RIR is calculated from statistics that include the standard deviation of the full accounts of the diffractogram and the relationship of 'accounts crystalline / background accounts', from an initial value definable preferably in each lab. The results of analysis of amorphous mtanto are more valid in terms of analyzing samples of similar composition. The results are better when amorphous samples are similar composition. The results are invalid in any case when the crystalline composition is incorrect. Complementary uses the 'Absorption-Diffraction Method' that involves calculating the *absorption mass coefficients* of each component and the total sample. The latter is calculated on the composition of the departure from the standard method RIR. The automatic use of these methods assumes that the database contains the chemical composition of each phase. In other cases X Powder provisional values assigned to the parameters  $m / r$ , which can be modified by the user. The composition ( $C_i$ ) of the component ( $i$ ) is obtained in the mixture ( $s$ ) from the fraction of the mix function ( $X_i$ ) of each partial diffractogram, which is obtained by non-linear method of least squares (Heavy optional) on the full profile:

$$C_i = X_i (\mu/\rho)_i / (\mu/\rho)_s$$

2 $\theta$  instrumental deviations optionally can be corrected during the refinement process.

The procedure that the user should be further simplified to the maximum, because it is not necessary to sample preparation patterns or the construction of curves and abacus for obtaining the weight percentages. The only requirement is that the database records used in the evaluation include information on the chemical composition and value of the RIR (*Reference Intensity Ratios*), which is customary in the latest versions of PDF2, but are not included in the database *DifData-AMSCD* database. In another case, these values can be added by the user with data measured in the laboratory or estimated from samples of known composition. The quality of the results is generally good and depends only on the quality of the diffractogram, the database patterns, the value of the RIR and its universality. It is always preferable to use mixes of patterns and corundum with particle size of 20  $\mu\text{m}$  to about 50% by weight and measure own RIR values.

The protocolose shown in the following example (corresponding to the sample C. PLV of the sub-directory \EXAMPLES that is installed with the program):

1. We must never subtract background (this will differ in recent versions of the program of previous ones).
2. It should be read automatically or manually peaks of the diffractogram pattern in order to calculate the d-spacing of the most accurate manner.
3. We have to make a correct identification of crystalline phases and select them  in the window **Results** of tool '**Matching**' (see Chapter 5, Figure 5.7 and 5.8).
4. We must come to the window of quantitative analysis (Fig. 6). This can be done from the tool '**Matching**' (**Quantitative**) or from any other part of the program (for example, Menu on the main page -> **Quantitative** -> **LS RIR Database cards**).

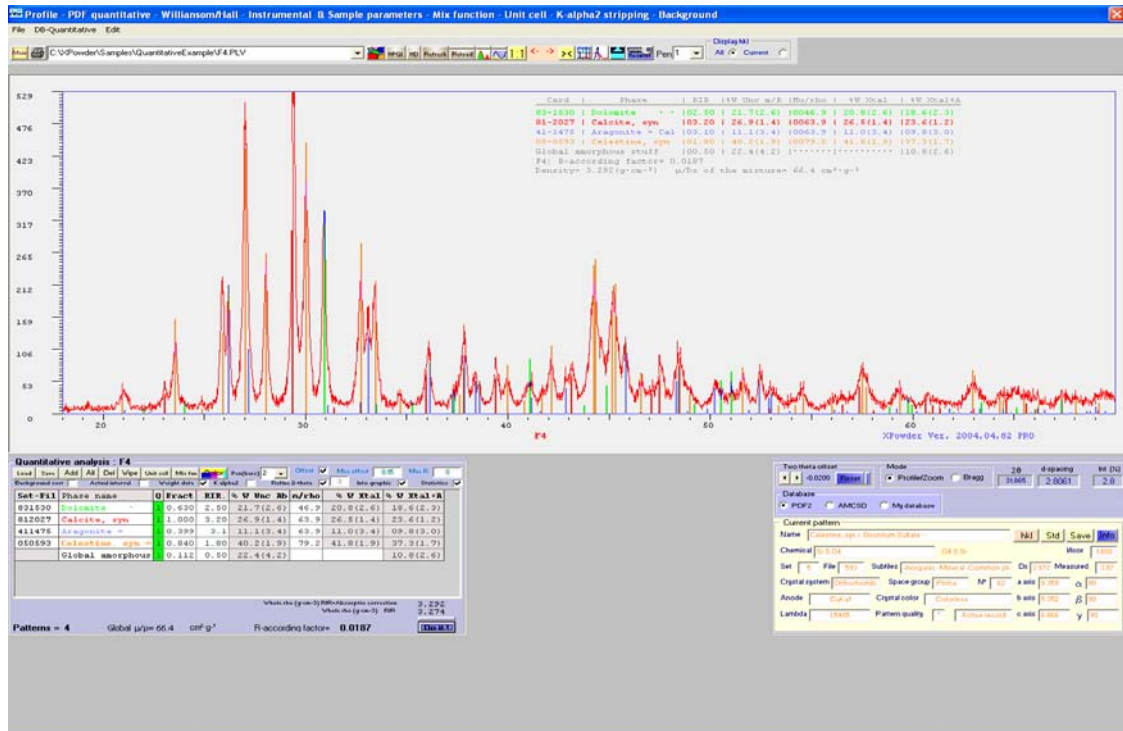


Figure 6.1.

5. The tool of quantitative analysis appears as in Figure 6.2, showing the previous results obtained directly from the parameters that the program has a default. **RIR** and  $\mu/p$  RIR values are calculated and incorporated automatically from the content of the database. If any of these records is not the factor **I/ICor**, the program assigns a provisional 1. Subsequently can be changed by the user to appropriate values, obtained in the laboratory or from literature. The lack of data density and chemical composition is also approach by the program.



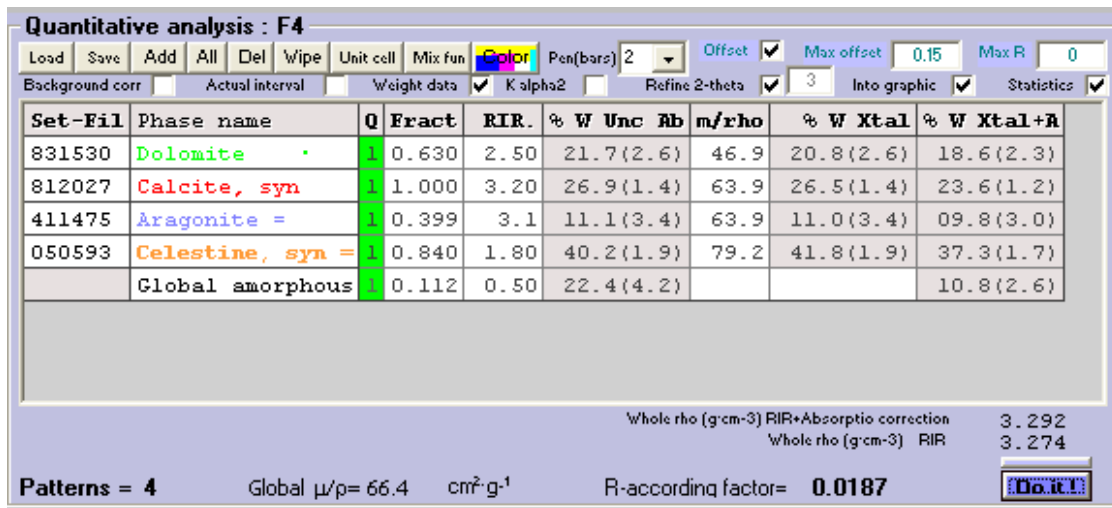


Figure 6.2.

In any case, you can always modify the values of the parameters **RIR** and  $\mu/p$  for each type of composition (including the amorphous pseudo-RIR value) and recalculate the quantitative by pressing **Quantitative**. Right part of this button performs the simultaneous analysis of all the loaded in computer memory diffractograms (50 maximum). All data are collected in the archive (logfile.tmp) that can be saved at any time from the menu "**File-> Save Log File as TXT**".

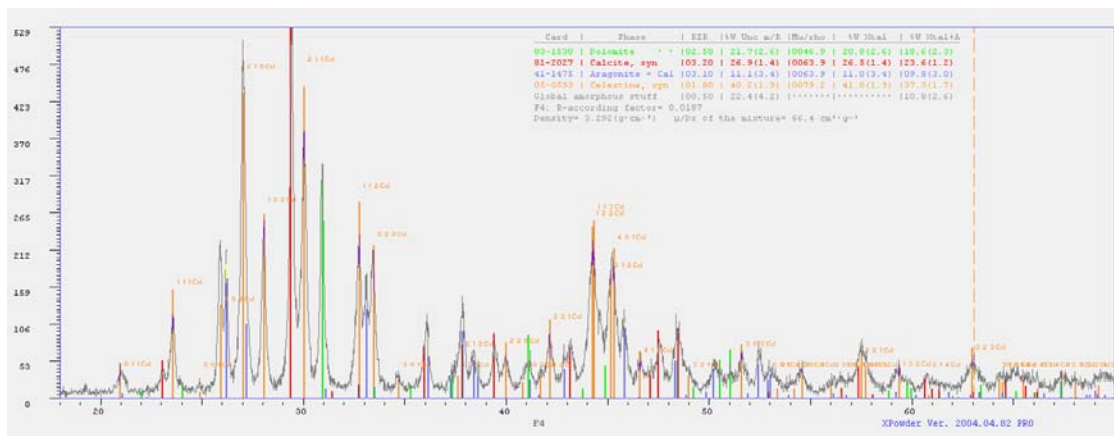


Figure 6.3.

### Description of the **RIR tool** (Figure 6.2.)

Sample file  
 C:\XPowder\SAMPLES\c.plv

This is the file of the active diffractogram. Can be changed by clicking  in the text box.

Background corr     Actual interval     Weight data     K alpha2     Refine 2-theta     3    Into graphic     Statistics

By checking the boxes are made respectively the following:

- It takes in account the background in according factor calculation
- Adjust the analysis to the current range of 2θ.
- The experimental data are weighed according to  $w = 1/\sqrt{\text{Counts}}$
- $K\alpha_2$  2 is included in the calculation of the profile function and the graphics (does not affect the quantitative analysis).
- The D-space values of the database patterns are refined
- Statitics are Included 'Log file' and graphical output.

Offset     Max offset    0.15    Max R    0

If checked, 2 $\theta$  experimental pattern offset is refined. Maximum 2 $\theta$  offset must be = **Max offset** value. According R for convergence is **Max R**.

R-according factor= **0.0187** It is defined as::

$$R = \frac{\sum \{ w(l_o - l_c) \}}{\sum w l_o}$$

To obtain good values of R is necessary to use those cards in the database whose intensities best fit our experimental diffractograms. The best results are obtained with their own records (mydatabase).

Set-File	Phase name	Q	Fract	RIR	% W Unc Ab	m/rho	% W Xtal	% W Xtal+R
831530	Dolomite	1	0.630	2.50	21.7(2.6)	46.9	20.8(2.6)	18.6(2.3)
812027	Calcite. svn	1	1.000	3.20	26.9(1.4)	63.9	26.5(1.4)	23.6(1.2)

Head of quantitative table of active experimental pattern. First column = Set (two digits) and file (four digits). Second column = phase name. Third column = (1) if phase will be quantified, and 0 for no analysis. 'Fract' column shows L.S. fractional composition of reference phase (0 to 1). 'RIR' similar to 'Reference Intensity Ratio' of phase reference, for all experimental pattern. Must be experimentally measured and can be edited and saved. '% W Unc Ab' % weight uncorrected for absorption. 'mu/rho' masic absorption coefficient calculated from chemical and density values of database record. '% W Xtal' column shows % weight (Sum= 100%) of crystalline components. Last column is equal from previous but includes an estimated **global amorphous stuff %**, obtained by:

$$\sum \{ [(l_i) / N]^2 + \sigma \}^2$$

RIR factors must be measured experimentally on the diffractogram of an artificial mixture, whose components are known weights. Among these components must have a stable pattern, common to all samples to be analyzed (quartz, fluorite, NaCl, corundum, CeO, B<sub>6</sub>La, etc). After, a prior quantitative analysis is done with X Powder, using initial **RIR<sub>phase</sub>** values equal to one. The final **RIR<sub>phase</sub>** factors are determined for each component according to:

$$RIR_{\text{phase}} = \left( \frac{\% W \text{ Xtal}_{\text{phase}}}{\% W \text{ Xtal}_{\text{reference pattern}}} \right) \cdot \left( \frac{\text{Weight}_{(\text{mg})}_{\text{reference pattern}}}{\text{Weight}_{(\text{mg})}_{\text{phase}}} \right)$$

The first two factors are obtained in the penultimate column of the output table of prior quantitative analysis and the latter two are the real weights of each component used to prepare the artificial sample. The calculated **RIR<sub>phase</sub>** values can be then used in future analysis in order to obtain absolute percentage results. Note that only need to use an artificial mixture for each paragenesis.

Across the table shows the standard deviation in brackets after each outcome.





**Load** Allows loading specific configuration parameters for each type of samples or associations, that has been previously saved with **Save**. This latest order allows you to create specific configurations of usual samples.


**Add** It allows you to add manually database records to be weighted in the quantitative analysis. It is necessary to know before the reference (*Set and File*) of each record.


**All** Select, or discarded, alternately all database records from the list of quantitative analysis.

 Clears the list.

 Unit-cell refinement using active reference phase pattern.

 The theoretical and difference patterns, based in the database cards, are calculated from the quantitative composition. The program uses the active profile parameters (Caglioti parameters and pseudo-Voigt average profile function). The calculation does not include asymmetric peaks, but the effects of the lack of monochromatism of the radiation.

 Allows you to select the color and size of the pen bar of the active database record (orange horizontal bar in the example in Figure 6.2) who is drawn in the diffractogram pattern graphic (Figure 6.3).

 The program makes quantitative analysis with the current parameters are listed in the table (as in Figure 6.2). Right part of this button performs the simultaneous analysis of all the loaded diffractogram patterns in computer memory (50 maximum). All results are collected in the archive (logfile.tmp) that can be saved at any time from the menu "[File-> Save Log File as TXT](#)". It is assumed that they all have the same qualitative composition, although it admits that some component has zero % in composition), as shown in the 'log file' example:

```
-----
Quantitative section based on PDF2 cards
Sample= C:\XPowder\SAMPLES\A.plv
  Card | Phase | RIR | %Weigth | Mu/rho | %Weight
-----
77-2093 | Fluorite, syn | 03.80 | 01.9(0.6) | 0115.2 | 01.8(0.8) | 01.8(0.8)
77-1904 | Gypsum . -Ca | 01.70 | 02.1(0.6) | 0060.8 | 01.8(0.8) | 01.8(0.8)
77-0529 | Celestine . | 01.90 | 26.5(0.8) | 0082.6 | 24.7(1.0) | 24.6(1.0)
77-1378 | Barite . -Ba | 02.80 | 69.5(9.4) | 0286.4 | 71.7(7.7) | 71.4(7.7)
Global amorphous stuff | 00.55 | ..... | ..... | 00.4.....
A.plv: R-according factor= 0.0274
Density= 4.281(g·cm-3) μ/Dx of the mixture= 224.3 cm2·g-1
Sample= C:\XPowder\SAMPLES\B.PLV
  Card | Phase | RIR | %Weigth | Mu/rho | %Weight
-----
77-2093 | Fluorite, syn | 03.80 | 15.2(1.7) | 0115.2 | 14.9(1.7) | 14.8(1.7)
77-1904 | Gypsum . -Ca | 01.70 | 15.9(0.6) | 0060.8 | 14.3(0.8) | 14.3(0.8)
77-0529 | Celestine . | 01.90 | 32.5(1.4) | 0082.6 | 31.5(1.4) | 31.4(1.4)
77-1378 | Barite . -Ba | 02.80 | 36.5(7.6) | 0286.4 | 39.3(6.3) | 39.2(6.3)
Global amorphous stuff | 00.55 | ..... | ..... | 00.4.....
B.PLV: R-according factor= 0.0303
Density= 3.808(g·cm-3) μ/Dx of the mixture= 158.4 cm2·g-1
Sample= C:\XPowder\SAMPLES\c.plv
  Card | Phase | RIR | %Weigth | Mu/rho | %Weight
-----
77-2093 | Fluorite, syn | 03.80 | 30.8(8.4) | 0115.2 | 31.0(7.0) | 30.8(6.9)
77-1904 | Gypsum . -Ca | 01.70 | 24.7(0.7) | 0060.8 | 22.8(0.9) | 22.7(0.9)
77-0529 | Celestine . | 01.90 | 27.4(1.3) | 0082.6 | 27.3(1.4) | 27.1(1.3)
77-1378 | Barite . -Ba | 02.80 | 17.1(0.9) | 0286.4 | 18.9(1.0) | 18.8(1.0)
Global amorphous stuff | 00.55 | ..... | ..... | 00.5.....
c.plv: R-according factor= 0.0207
Density= 3.439(g·cm-3) μ/Dx of the mixture= 122.0 cm2·g-1
Sample= C:\XPowder\SAMPLES\D.plv
  Card | Phase | RIR | %Weigth | Mu/rho | %Weight
-----
77-2093 | Fluorite, syn | 03.80 | 13.0(1.9) | 0115.2 | 12.7(1.8) | 12.6(1.8)
77-1904 | Gypsum . -Ca | 01.70 | 16.8(0.6) | 0060.8 | 15.1(0.8) | 15.0(0.8)
77-0529 | Celestine . | 01.90 | 33.0(1.5) | 0082.6 | 32.0(1.5) | 31.8(1.4)
77-1378 | Barite . -Ba | 02.80 | 37.3(7.4) | 0286.4 | 40.2(6.2) | 39.9(6.1)
Global amorphous stuff | 00.55 | ..... | ..... | 00.6.....
D.plv: R-according factor= 0.0263
Density= 3.817(g·cm-3) μ/Dx of the mixture= 159.2 cm2·g-1
```

#### Summary of quantitative analysis of crystalline components

Sample	Fluorite,	Gypsum	Celestine	Barite	R-acc	Densit	C.Mas
A.plv	01.8(0.8)	01.8(0.8)	24.7(1.0)	71.7(7.7)	0.0274	4.281	224.3
B.PLV	14.9(1.7)	14.3(0.8)	31.5(1.4)	39.3(6.3)	0.0303	3.808	158.4
c.plv	31.0(7.0)	22.8(0.9)	27.3(1.4)	18.9(1.0)	0.0207	3.439	122.0
D.plv	12.7(1.8)	15.1(0.8)	32.0(1.5)	40.2(6.2)	0.0263	3.817	159.2

Summary of quantitative analysis of crystalline compounds and amorphous stuff

Sample	Fluorite,	Gypsum	Celestine	Barite	Amorp	R-acc	Densit	C.Mas
A.plv	01.8(0.8)	01.8(0.8)	24.6(1.0)	71.4(7.7)	00.4	0.0274	4.281	224.3
B.PLV	14.8(1.7)	14.3(0.8)	31.4(1.4)	39.2(6.3)	00.4	0.0303	3.808	158.4
c.plv	30.8(6.9)	22.7(0.9)	27.1(1.3)	18.8(1.0)	00.5	0.0207	3.439	122.0
D.plv	12.6(1.8)	15.0(0.8)	31.8(1.4)	39.9(6.1)	00.6	0.0263	3.817	159.2

End Quantitative section

In addition to the tool of estimate quantitative, a table is shown with the active database card (Fig. 6.4).

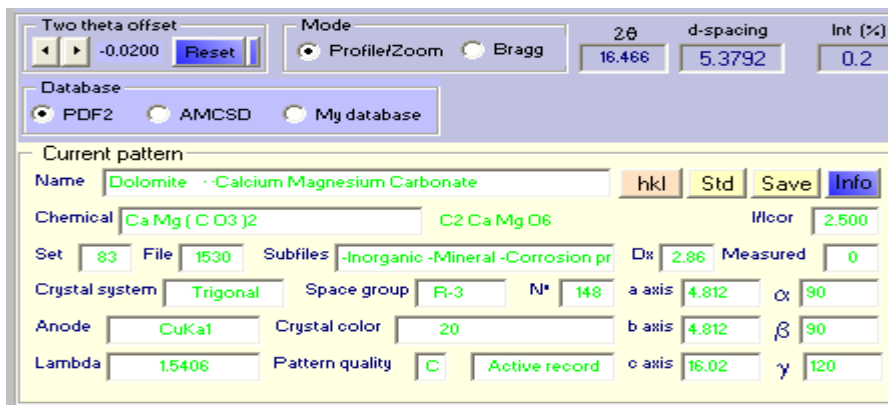


Figure 6.4.

This card is very similar to that described in Chapter 5 (Fig. 5.9). It also added to the pattern graphic **hkl** indices of the identified phases (Fig. 6.3) with the button **hkl**, manually correct the 2θ error and alternately working in mode 'Profile Analysis' (Chapter 8), or edit mode Bragg's reflections ( Profile/Zoom  Bragg)

**Auxiliary buttons**



The first nine buttons have the same significance as in other parts of the program. They are important on this page (Kα<sub>2</sub> stripping) and background subtraction).

Move the diffractogram pattern to the right or the left.

Decreases the zoom level.

Performs analysis profile of reflection marked with the left mouse button.

All  Current card Choose which **hkl** index are shown on screen when it stops the cursor on the graphic pattern.

[Home](#)

## **Chapter 7. Quantitative analysis using experimental standards.**

This is the most accurate way to quantify phases through X-Ray diffraction by the powder method. However requires a careful handling of samples, both of which are used as standard as those that are analyzed.

The method requires the record of diffraction patterns of pure crystalline compounds with the same composition and similar crystallinity to those present in the specimen. When the quantitative analysis is performed, the program makes an adjustment for non-linear least squares to find the mix of diffractogram standard patterns to the experimental pattern.

If the crystallinity among the specimens and standard patterns are very different, it is desirable to make records with different crystallinity patterns. The program will make the weighting of each of them, as if they were separate phases. May also be included diffractograms of amorphous substances for global quantification of them in the analyzed mixtures. The use of internal standards of known weight (eg 10% of corundum  $\text{Al}_2\text{O}_3$ ) allows absolute quantitative analysis.

During the analysis the  $2\theta$  displacement and the mass absorption coefficient are refined. Data must be statistically weighted.

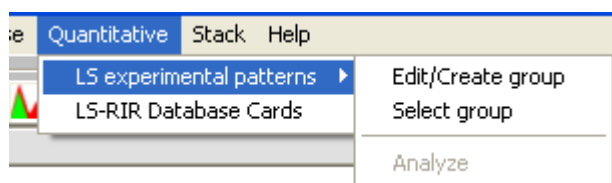
Once obtained the diffractograms standard patterns, it is easy for serialized quantitative analysis with a precision that is generally higher than those obtained by Rietveld methods or RIR-database based correction.

The quantitative analysis are more accurate when made with care the following:

- The volume of standard sample and specimen used in all registrations should be the same. An minimum % of Internal standard compound can be artificially added to the specimen.
- The pressure of compaction of crystalline powder should also be similar.
- It is necessary to use a stable sample pattern to control the derive of the X-Ray meter. The best thing is to use is a pressed tablet having similar absorption coefficient which samples to be analyzed, wherever possible.
- The same radiation, monochromatization system, set of slits, detector and values of discrimination of the detector should be used forever.
- The diffractograms of the tablet pattern and the standard patterns should preferably be in the same session.
- Where then is necessary to create new standard patterns, must be measured also shows stable tablet pattern, in order to correct derive or decay.
- The historic change of intensity is corrected by a factor, which is the ratio between the two measures ( $I_{old}/I_{new}$ ). To this value, you can use a single reflection, or rather the cumulative intensity of several reflections and even entire diffractogram.
- Exceptionally, they can be used calculated diffractograms from the crystal structure, through programs such as Cerius, Mercury, etc., whenever possible to normalize the intensity by a appropriate factor.

Access to such analysis is done from the [main menu](#) with the command:

[Quantitative -> SL Experimental Patterns](#)



There are three subcommands ('[Edit/Create group](#)', '[Select group](#)' and '[Analyze](#)'), which will be as follows:

## Edit/Create group

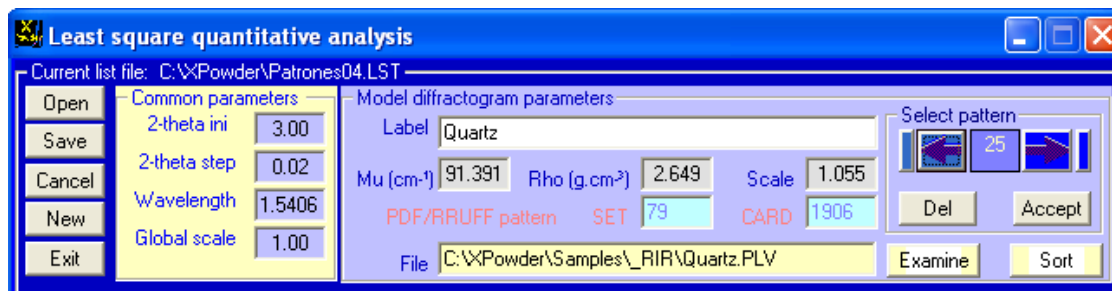


Figure 7.1.

**Open** To open and edit a previously created file that contains group of crystalline and, or, amorphous phases. These files are text format ('ascii') and the extension '.LST'

**Save** It allows to save a group phases for later reuse with **Open**.

**Cancel** Return without any operation.

**New** Lets create a new group.

**Exit** Return to the main screen, after requiring the recording of the group created.

**Del** Erase data from the active compound whose order number appears in the box under the message 'Select compound'.

**Accept** Accepts the selected pattern. Equivalent of pressing the right arrow.


**Examine** Lets explore the computer disk drives to locate the file of the standard substances (Barite.PLV in the example). When you load the file, the boxes **Label**, **File** and **Common parameters** are filled automatically. These should be identical for all phases listed. The figure **Global scale** is 1 normally but can be modified with the same approach that the term **Scale**, as shown in the following paragraph. All the boxes may be edited, but **2-theta ini**, **2-theta step** y and **Wavelength** must coincide with those of the corresponding specimen diffractogram patterns.

The values of *lineal absorption coefficient* **Mu(cm<sup>-1</sup>)**, *density* **Rho(g.cm<sup>-3</sup>)**, **SET** and **CARD** are optional, and should be entered manually. If the first two are not introduced, is not performed the absorption correction. **CARD** and **SET** are used to superimpose the reflection graph bars of the database records. The value of box **Scale** is 1 normally. Must be modified if the search pattern has been made after observing a variation of the intensities of the tablet standard sample with respect to other historical patterns used in the same association.

The left and right arrows (framework **Select compound**) let go through the list of patterns, or introduce a new one.

Figure 7.1 shows, for example, the fourth compounds (number 25 in the **Select compound** frame) for a association which includes all the possible data.

## Select group

Lets explore the disks from the computer to select a file (.LST) created with 'Edit / Creat group'. Once loaded, the same group can be invoked repeatedly by using the **Analyze** menu or the button  on the main screen.

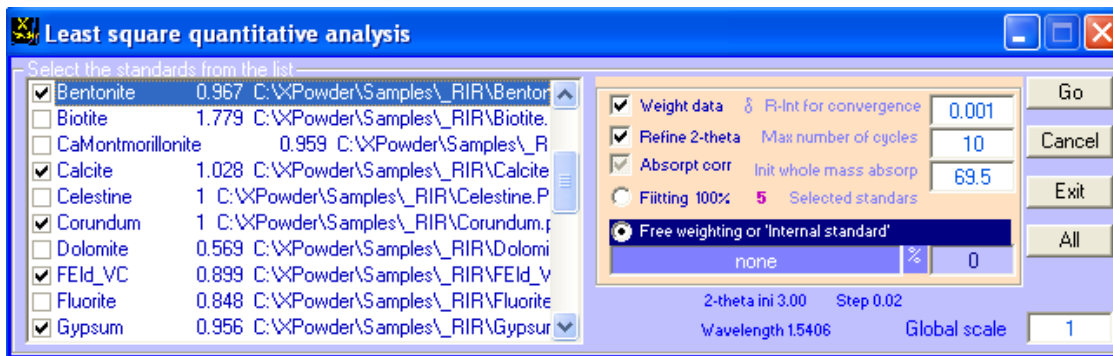


Figure 7.2.

The list on the left shows the components of the association and the files it contains diffractograms standard patterns. You can select (☑) part or all components of the list (Order All). If you have entered the values of the absorption coefficients and densities, you can tick Absorpt corr. You can also refine the mistakes of shifting angles  $2\theta$  (Refine 2-theta). You can also weight the experimental data ( check box Weight data ).

Maximun number of cycles. Limits the number of least squares cycles.

§ R-Int for convergence When it reaches this divergence value , the analysis stops even have not been completed cycles. Smaller values provide more accurate results.

Init whole mass absorp. Initial estimated mass absorption coefficient for the specimen. It can be manually modified.

Exit Lets leave the quantitative analysis.

Cancel. Cancel any operation, and leaves the quantitative analysis.

Go Makes quantitative analysis.

**Analysis options:** There are two different operating modes.

1. Fitting 100% The sum of components are 100 % fitted.

2. Free weighting or Internal standard: In turn provides two options:

2.1. Without internal standard (Free weighting): If not selected any internal standard (none), diagram calculated will be fitted in accordance with the experimental, but the results have a relative nature, generally do not total 100 (Figure 7.3).

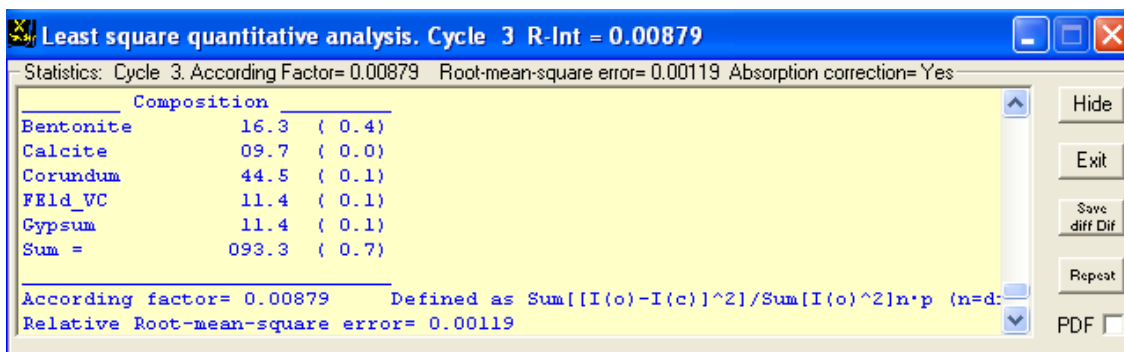


Figure 7.3

2.2. With internal standard. You can select from a list of components whose weight is known as internal standard (48% of corundum in the example of Figure 7.4). You can use a component of the mixture itself or added artificially.

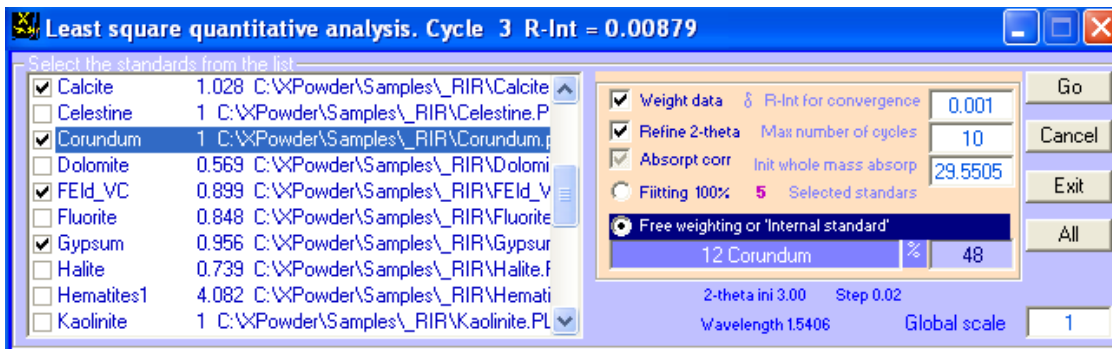


Figure 7.4.

To select the internal standard, you double-click on the appropriate line of the list (Corundum in the example), or on the box . In the latter case the active compound is selected from the list. A new double-click on this box, discarding the internal standard. The quantitative composition (48% in the example) must be entered manually. The result of the analysis will be absolute in this case (Figure 7.5).

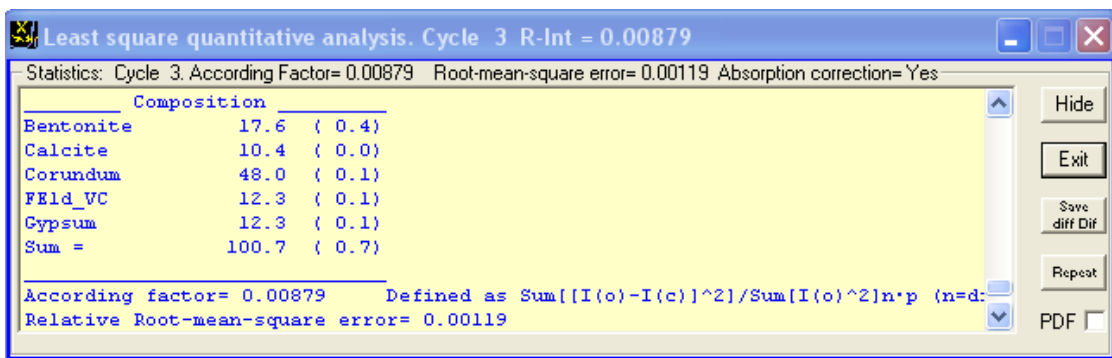


Figure 7.5.

The results (Figure 7.6) are displayed in the main graphic above and to the left. They include statistics and some auxiliary parameters obtained during the process. The calculated pattern (*mix function*) is shown with red dots overlapped by the diffractogram. The difference between standard and experimental diffractograms are shown in green at an height of close to 10% on the main screen and a 80% on the auxiliary lower pattern.


The header of the results screen (Fig. 7.5) shows the number of cycles performed before convergence, the factor of agreement, the mean square error final and informs us of the absorption correction.

The agreement factor (*Accordinging factor*) is defined as:

$$\text{Accordinging Factor} = \left\{ \frac{\sum [w(I_o - I_c)^2]}{\sum w [I_o^2]} \right\} \cdot n \cdot p$$

where  $I_o$  are observed intensities and  $I_c$  calculated intensities.  $n$  = number of experimental points,  $p$  = number of standard patterns.  $n \cdot p$  is constant for a each experience and it is used only for scale purposes.



**Hide** Minimizes the floating screen of figure 7.6. It's like you press the button .

**Exit** Lets leave the analysis.

**Save diff Dif** Lets save the difference pattern in PLV format.

**Repeat** Lets repeat the analysis. The program leads to the figure 7.4.

**PDF** If you have filled the boxes **SET** and **CARD** (Fig. 7.2), and check the box **PDF**, the bar graphs of the database are displayed on the main screen.

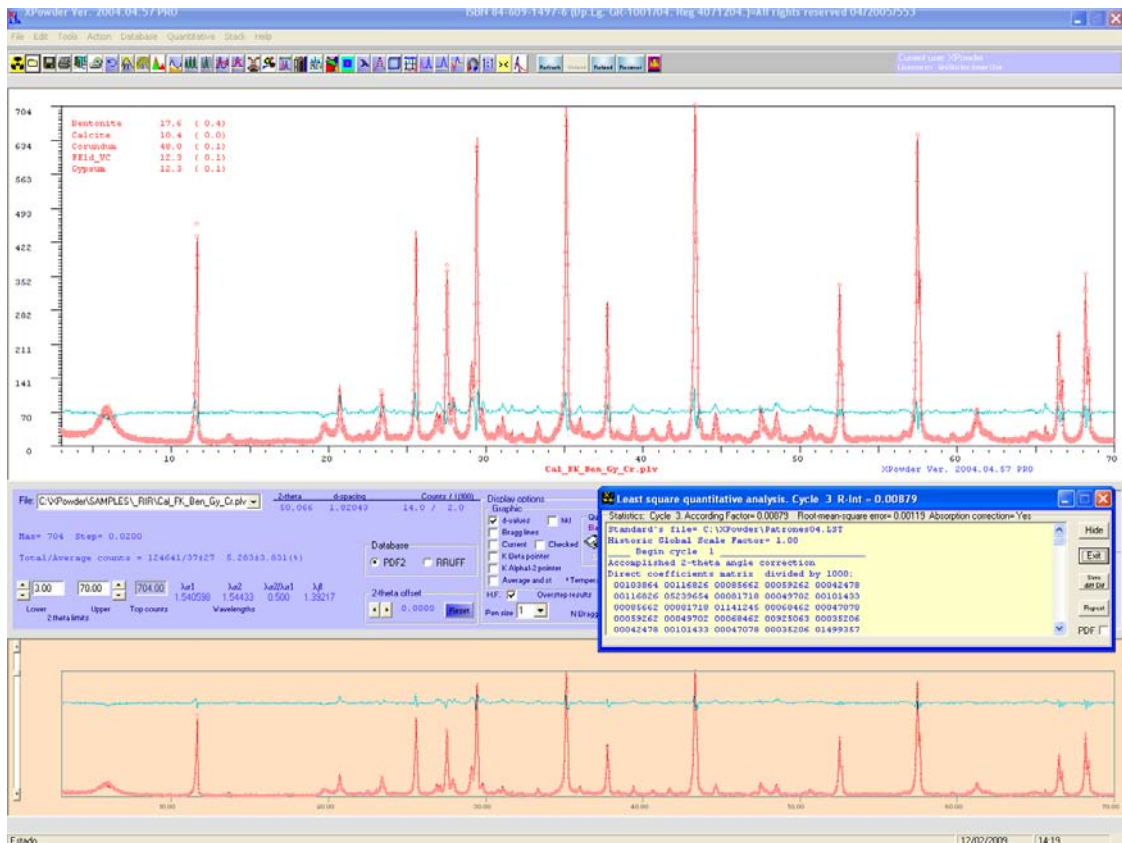


Figure 7.6.

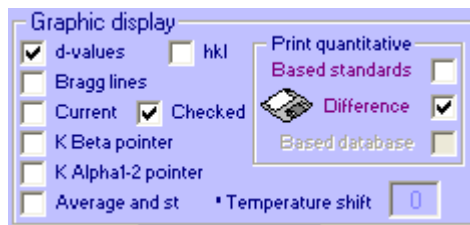


Figure 7.7.

The options on the main screen can be used (Fig. 7.7) to draw the desired details on the diffractogram graph. In the example has been marked **Checked** to display all the patterns selected in the tool **Matching**. It has been unchecked the box **Based standards**, not to be mixed on the screen the results of quantitative analysis with the names of the phases of the database. Many other alternatives are possible.

Note that we can perform a quantitative analysis regardless of one or more phases. In these cases, the difference diffractogram lie only to 'experimental' stage of non-quantifiable phases.

Thus, we can save this difference file and use it later to analyze individual profiles, for example, with results generally more accurate than those obtained by deconvolution techniques. Figure 7.8 shows a quantitative adjustment as shown in Figure 7.6, which has excluded one of components (Bentonite). The diagram of differences, in blue, displays the diffractogram of the pure bentonite, which can then be studied separately (figure 7.9). Some peaks of other phases can not be completely eliminated and appear in the difference diffractogram as residual sharp reflections.

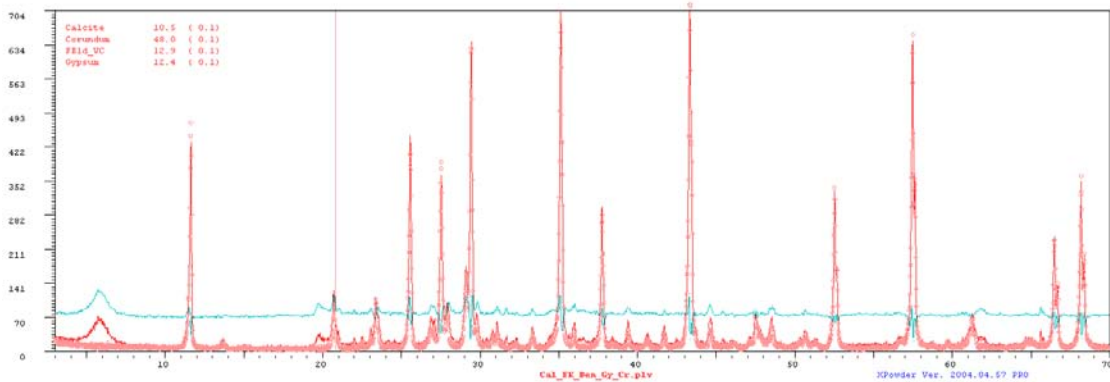


Figure 7.8.

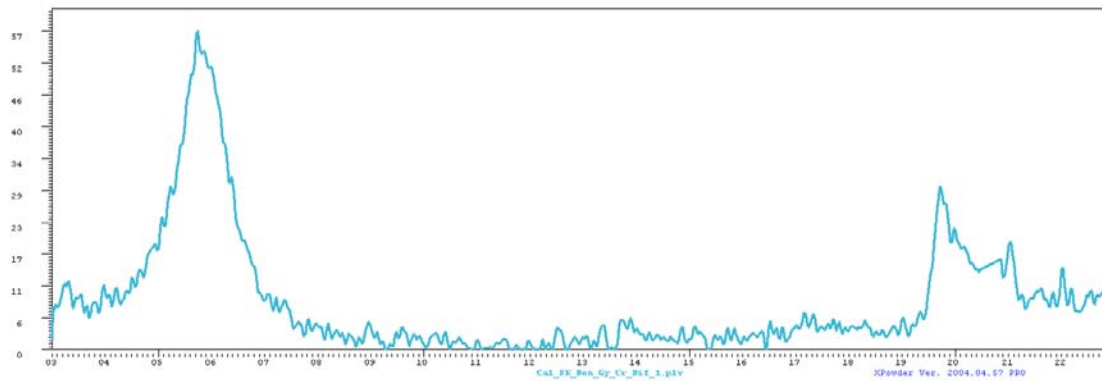


Figure 7.9. Detail of the difference diffractogram corresponding to Figure 7.8 where you can appreciate the isolated pattern of bentonite.

The partial results and other calculation details are displayed on-screen text of a yellow background (Fig. 7.6) and are recorded in the 'log file', as shown in the following list:

```
-----
Least squares quantitative analysis Section. Sample: C:\XPowder\SAMPLES\D.plv
Full profile refinement method
Standard's file= C:\XPowder\Salts.LST
```

```
-----
Historic Global Scale Factor= 1.00
```

```
-----
Begin cycle 1
```

```
Accomplished 2-theta angle correction
```

```
Direct coefficients matrix divided by 1000:
```

```
00340479 00219720 00007577 00017374
00219720 00469209 00029085 00025070
00007577 00029085 01140231 00009856
00017374 00025070 00009856 00303487
```

```
-----
Inverse coefficients matrix (x 1000000):
```

```
0.0042 -0.0020 0.0000 -0.0001
-0.0020 0.0031 -0.0001 -0.0001
0.0000 -0.0001 0.0009 0.0000
-0.0001 -0.0001 0.0000 0.0033
```

```
-----
Correlation coefficients matrix:
```

```
1.0000 -0.5481 0.0119 -0.0212
-0.5481 1.0000 -0.0389 -0.0434
0.0119 -0.0389 1.0000 -0.0144
-0.0212 -0.0434 -0.0144 1.0000
```

```
-----
Acumulated Counts for observed diffractogram = 51166
```

```
Acumulated Counts for calculated diffractogram= 36637
```

```
-----
Composition
```

```
Barite      52.9   ( 0.3)
Celestin    27.5   ( 0.3)
Fluorite    09.1   ( 0.1)
Gypsum      10.6   ( 0.3)
```

```
-----
Sum = 100.0 ( 1.0)
```

```
Density 3.989( 0.040) g·cm-3
```

```
Linear absorption coefficient 58.465 cm-1
```

```
-----
According factor= 0.05130 Defined as Sum[[Int(o)-Int(c)]^2]/Sum[Int(o)^2]
```

```
Relative Root-mean-square error= 0.07933
```

```
The percentages have been calculated weighing the data.
```

```
The selected composition is unsuitable or incomplete
```

```
Absorption correction= Yes
```

```
-----
Begin cycle 2
```

```
Accomplished 2-theta angle correction
```

```
Direct coefficients matrix divided by 1000:
```

```
00340479 00196180 00008363 00015846
00196180 00456333 00030140 00025144
00008363 00030140 01139641 00010019
00015846 00025144 00010019 00325783
```

```
-----
Inverse coefficients matrix (x 1000000):
```

```
0.0039 -0.0017 0.0000 -0.0001
-0.0017 0.0029 -0.0001 -0.0001
0.0000 -0.0001 0.0009 0.0000
-0.0001 -0.0001 0.0000 0.0031
```

```
-----
Correlation coefficients matrix:
```

```
1.0000 -0.4962 0.0088 -0.0176
-0.4962 1.0000 -0.0398 -0.0473
0.0088 -0.0398 1.0000 -0.0139
-0.0176 -0.0473 -0.0139 1.0000
```

```
-----
Acumulated Counts for observed diffractogram = 51166
```

```
Acumulated Counts for calculated diffractogram= 37131
```

```
-----
Composition
```

```
Barite      54.6   ( 0.7)
Celestin    25.8   ( 0.6)
Fluorite    08.7   ( 0.3)
Gypsum      10.9   ( 0.6)
```

```
-----
Sum = 100.0 ( 2.1)
```

```
Density 3.994( 0.084) g·cm-3
```

```
Linear absorption coefficient 59.394 cm-1
```

---

---

Accordinging factor= 0.02407      Defined as  $\text{Sum}[(\text{Int}(o)-\text{Int}(c)]^2)/\text{Sum}[\text{Int}(o)^2]$

Relative Root-mean-square error= 0.07685

The percentages have been calculated weighing the data.

Absorption correction= Yes

\_\_\_\_ Begin cycle 3 \_\_\_\_\_

Accomplished 2-theta angle correction

Direct coefficients matrix divided by 1000:

00322047 00196784 00008635 00013832  
00196784 00469212 00029085 00026019  
00008635 00029085 01140231 00010886  
00013832 00026019 00010886 00325783

Inverse coefficients matrix (x 1000000):

0.0042 -0.0017 0.0000 0.0000  
-0.0017 0.0029 -0.0001 -0.0002  
0.0000 -0.0001 0.0009 0.0000  
0.0000 -0.0002 0.0000 0.0031

Correlation coefficients matrix:

1.0000 -0.5049 0.0070 -0.0106  
-0.5049 1.0000 -0.0369 -0.0515  
0.0070 -0.0369 1.0000 -0.0153  
-0.0106 -0.0515 -0.0153 1.0000

Acumulated Counts for observed diffractogram = 51166

Acumulated Counts for calculated diffractogram= 37711

\_\_\_\_ Composition \_\_\_\_\_

Barite	49.4	( 0.7)
Celestin	30.6	( 0.6)
Fluorite	08.9	( 0.3)
Gypsum	11.2	( 0.6)

Sum = 100.0 ( 2.2)

Density 3.963( 0.086) g·cm<sup>-3</sup>

Linear absorption coefficient 56.124 cm<sup>-1</sup>

---

---

Accordinging factor= 0.01662      Defined as  $\text{Sum}[(\text{Int}(o)-\text{Int}(c)]^2)/\text{Sum}[\text{Int}(o)^2]$

Relative Root-mean-square error= 0.07821

The percentages have been calculated weighing the data.

Absorption correction= Yes


\_\_\_\_ End cycle 3 \_\_\_\_\_

[Home](#)

**Chapter 8. Pattern stacking.** (See also '[Rearranging diffraction patterns](#)' and '[Homogenization of 2θ scan intervals and steps](#)' in [New features of ver 2010.01.10](#) ).

XPowder can work simultaneously with a maximum of 50 diffractogram patterns. In this way, is also highlighting aspects that are not seen when working with isolated diffractograms, such as phase transitions, composition or crystallinity. The program allows the representation in perspective (3D) and by projection with level curves and, or, false color (2D).

### 3D Screen

To enter the 3D display (Figure 8.1) uses the button  or the command 'Stack' from the main menu.

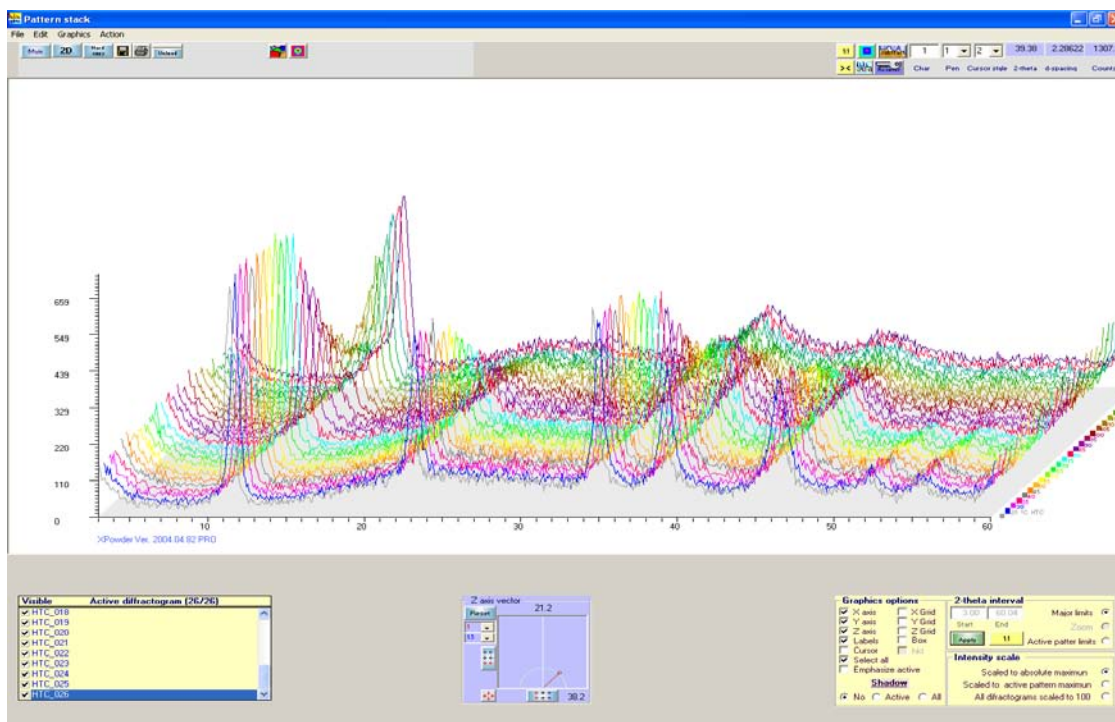






Figure 8.1. 3D Visualization of a sequence with a recorded temperature variation.

The blue bar from the list on the left shows the diagram of the main screen active and can be changed by clicking on the list with the left mouse button. Fields marked (☑) correspond to the patterns that are drawn on the figure. It can be selected manually.

The tool [Z-axis vector](#) can control the direction and depth of the third axis (Z) by dragging the red dot on the small screen of a blue background. The buttons  and  set to zero displacement of the axis vertical, horizontal or both respectively.  modify the sensitivity of the drag of the mouse on this screen.  change the height of the patterns, enabling the stack as the figure of 8.4.

The tool [Graphics options](#) selects the items shown in the graphic (axes, background, labels, etc.) or highlight the active pattern ( [Emphasize active](#) ).

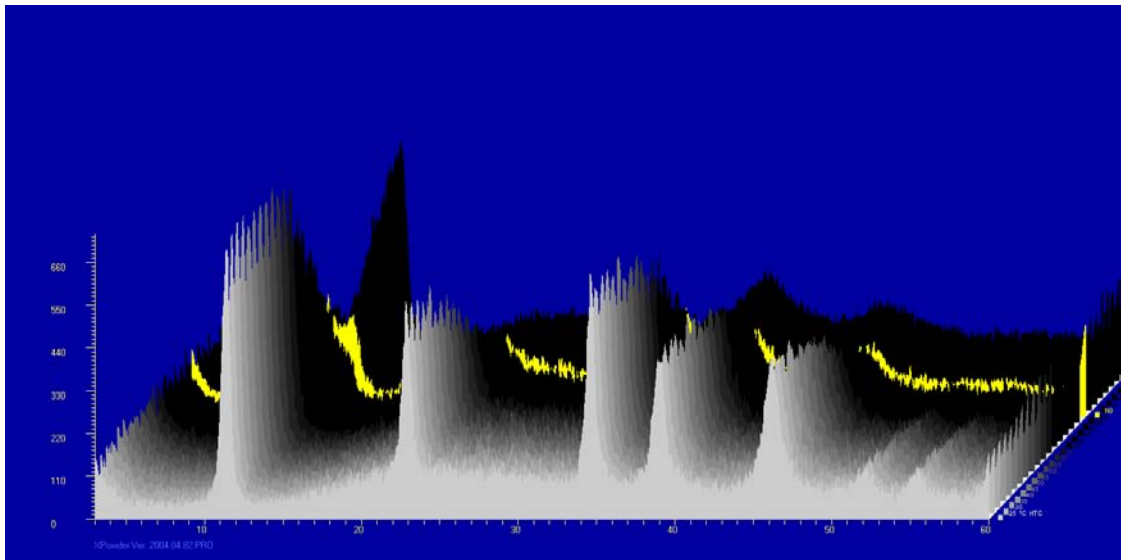


Figure 8.2

In figure 8.2, have used a gray color palette ( ), a blue background ( ) and has set the active chart with a specific color ( ) yellow).

In Figure 8.3 has been removed to fund the entire package ( Bgnd ).

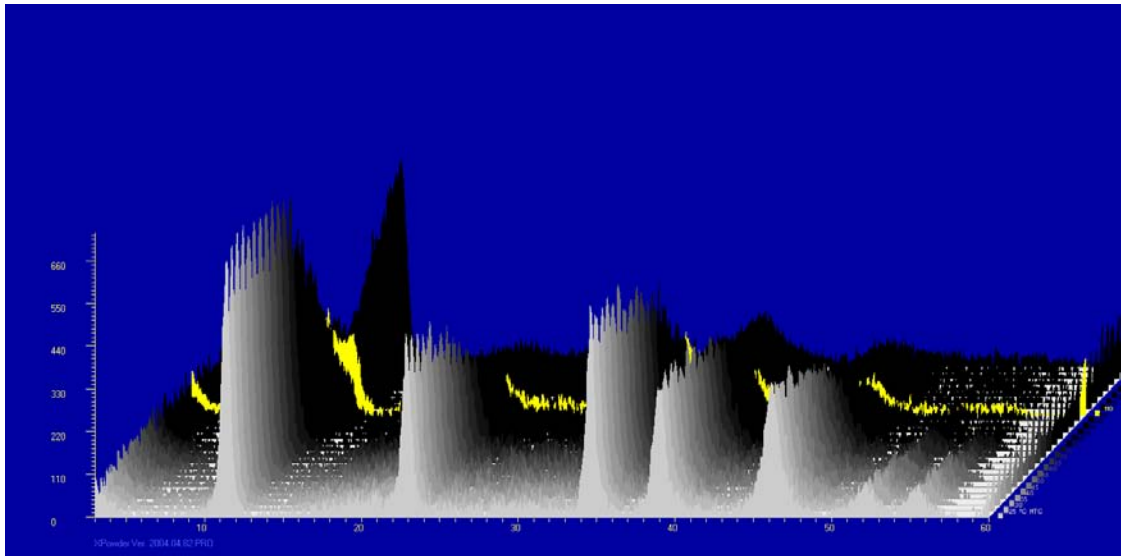



Figure 8.3.

You can use the [matching](#) tool, both in the 3D and in the 2D representations, in order to graphically superimpose database records in experimental patterns. Figure 8.4 shows an example in 3D (tick box [hkl](#)). In presenting 3D is necessary to put the horizontal scroll to zero (it can be used to the button )

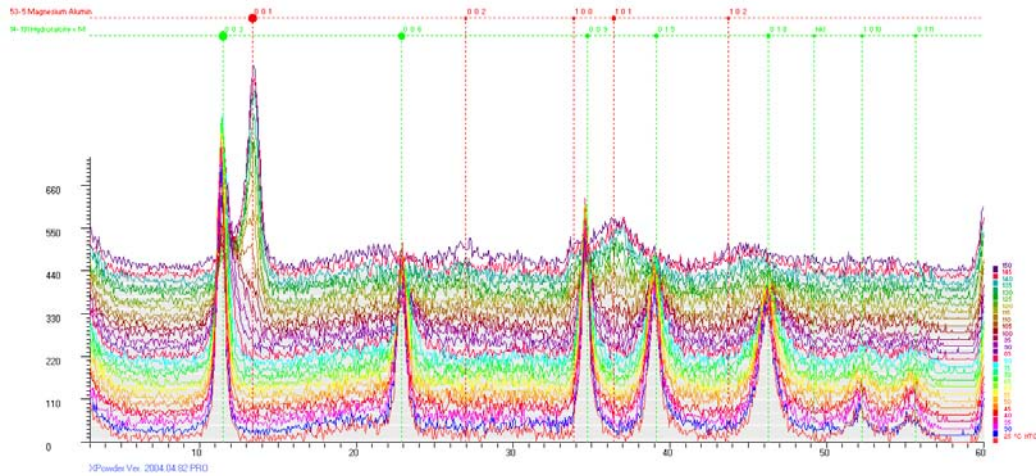


Figure 8.3.

Figure 8.4 also shows the use of the tools Z-axis vector in order to visualize a sequence of the same diffractogram patterns. The area of circles (red and green in the illustration) lets recognize the peaks correspond to the relative intensities of each phase of the database.

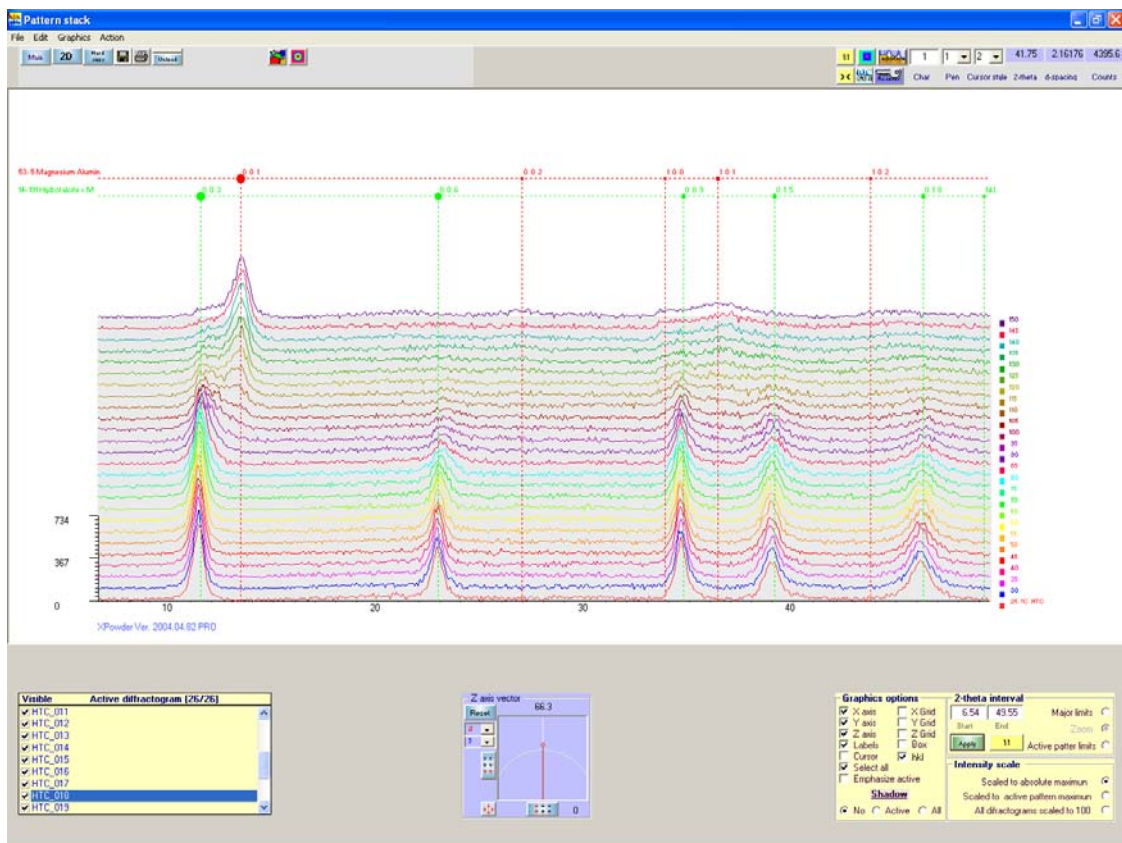
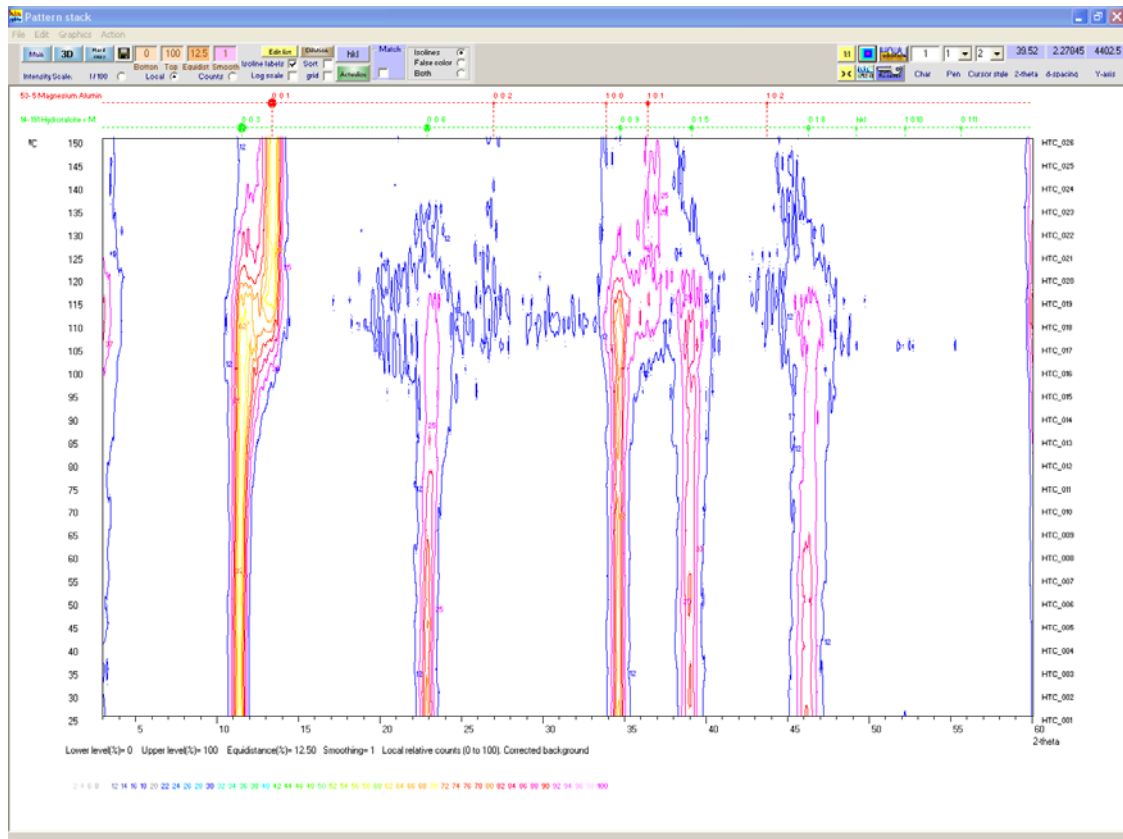


Figure 8.4.

**2D Screen** In this screen you can enter only from the 3D display by pressing the button **2D**. The result is shown in Figure 8.5.



**Figure 8.5**

The colored curves, calculated by quadratic interpolation methods, show different scales of intensity, as the key to the bottom, and can be scaled depending on the choice (**Intensity scale**) to the value 100 of the respective partial patterns (Option **I/I100**), at maximum value of each diffractogram in the range of used  $2\theta$  (**Local** Option, is selected by default) or absolute (**Counts**). You can select a logarithmic representation (Mark **Log scale**). Instead of isolines can be used false color or both representations (**Isolines**, **False color** or **Both** Options). You can also subtract/add background with the button **Bgnd**.

$2\theta$  specific intervals can be selected by clicking and dragging with the left mouse button. **1:1** and **>>** buttons are used to extend the  $2\theta$  interval.

Orders **Edit list** / **Hide list** allowed to edit/hide the list of patterns used for the mapping, whose file names are displayed in the right column of the chart.

The bar pattern of databases can be drawn, in combination with the tool 'Matching'. In this sense, the button **hkl** allows the drawing/delete these same bars directly on the map of intensities. The name of the crystalline phase and the *hkl* reflections index appear, when the cursor stops on and maximum of the intensity map (Fig. 8.6).

**0** **100** **12.5** **1**  
**Bottom Top Equidist Smooth** The values of minimum isoline, equidistance, maximum isoline and surface smoothing (a value 0, produces no smoothing of the data) can be respectively introduced in these boxes.



The button **Actualize** is used to redraw the map when a parameter or the list of diffractograms change.

When a data PLV format type is used, including the parameter 'Temperature', the column on the left shows a temperature values (Figures 8.5 and 8.6). If a recording of patterns has been done while the sample is heated and subsequently cooling has been recorded, it should tick **Sort**, to display the records in a historical arrangement and not temperature arrangement because, in the latter case, the records obtained at the same temperature, during the ascent and descent, they would appear together.

If the process is independent of temperature, the sequence of presentation list is the same used to load the respective data files.

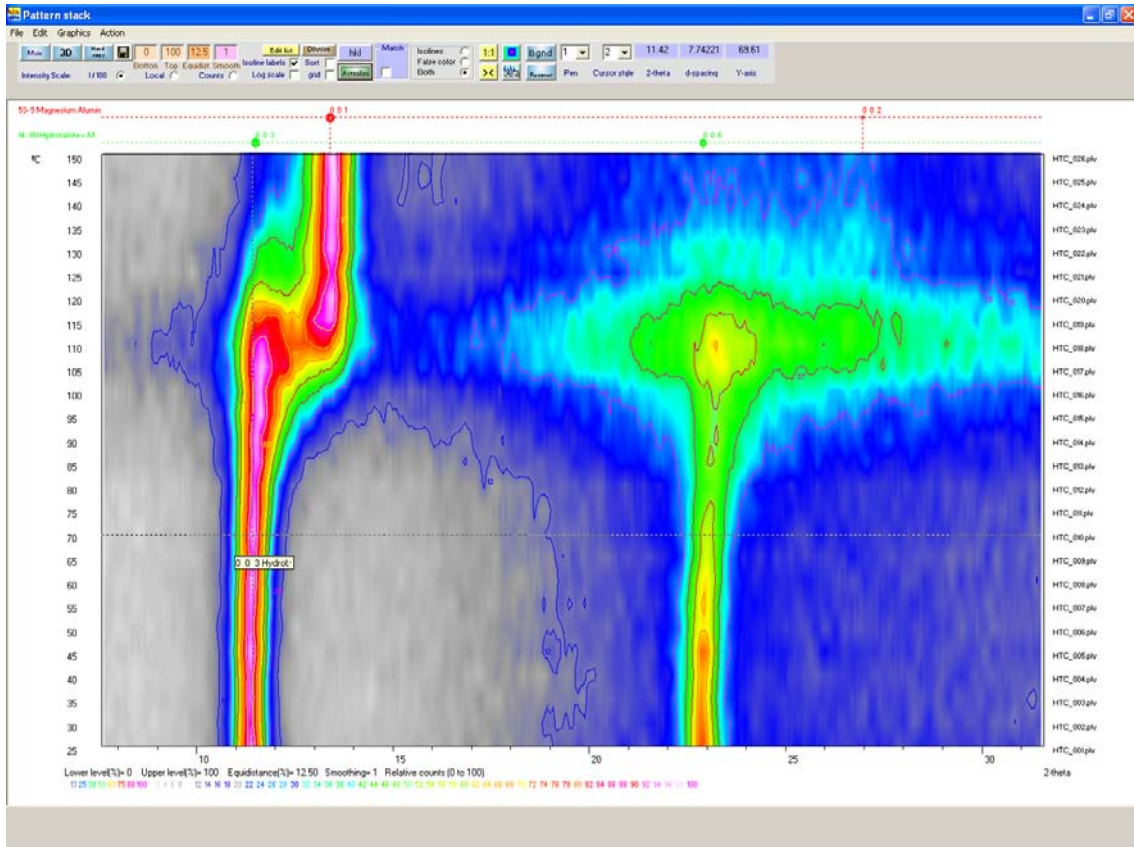


Figure 8.6. Change of phase around the 110 °C. A widespread loss of crystallinity is observed. This is marked by the widening of the maximum that precede the formation of the higher temperature phase.

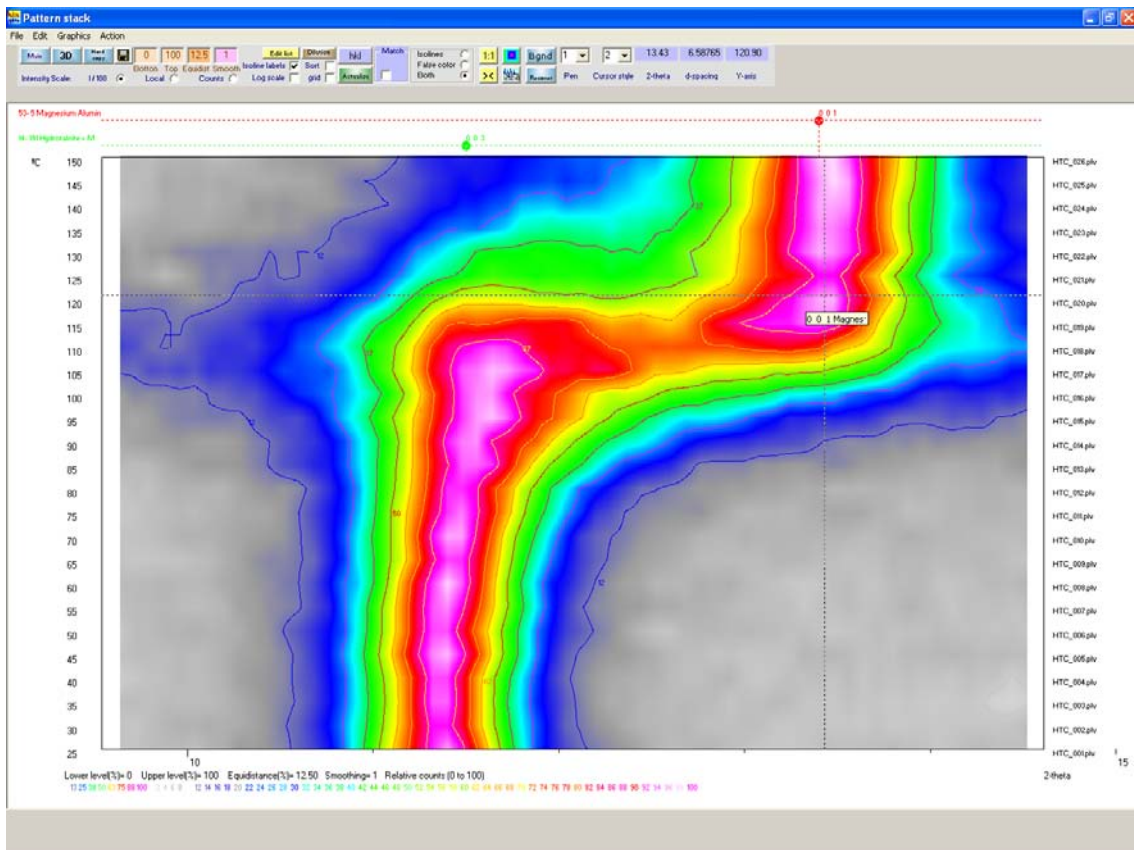
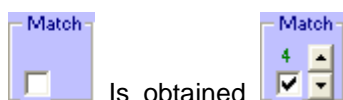




Figure 8.7. Details of the previous figure. The indexes (001) of the phase formed at higher temperatures are shown overprinted. The curve level of 50% (between yellow and green) marks the evolution of FWHM along the sequence.

Can be noted that while the 3D presentation allows patterns with any data format (RAW, UDF, TXT, etc.), with different exploration ranges of ( $2\theta$  angles initial and final) and even different  $2\theta$  steps between successive intensity measures, the **2D option requires all diffractogram patterns have been registered under the same experimental conditions**, because X Powder uses nonlinear interpolation techniques for the drawing of the isolines and the calculation of the false color requiring that restriction.



By clicking on  Is obtained . This eliminates the interpolation of data, which involves creating maps of the previous figures and limited representation to the original patterns (very similar to colored Debye-Scherrer patterns, Figure 8.8). The number (4 in the example of the [Match](#)) is the width of each diffractogram.

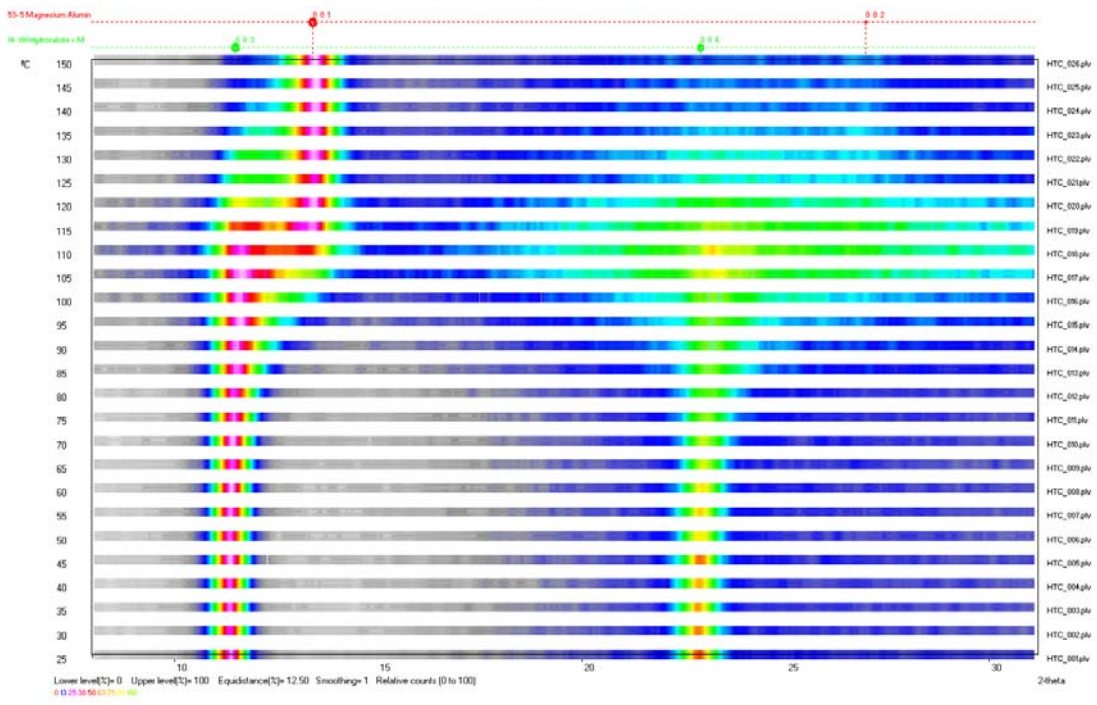


Figure 8.8.

The button **Dilation** allows to do calculations of expansion coefficients. When the tool **Thermal coefficients** is present, simply click (while press down the **Alt** key) points of the map from which you want to measure the thermal dilation coefficient. Note that you can make a measurement for each *HKL* direction, which allows studying the thermal dilation tensor (Fig. 8.9).

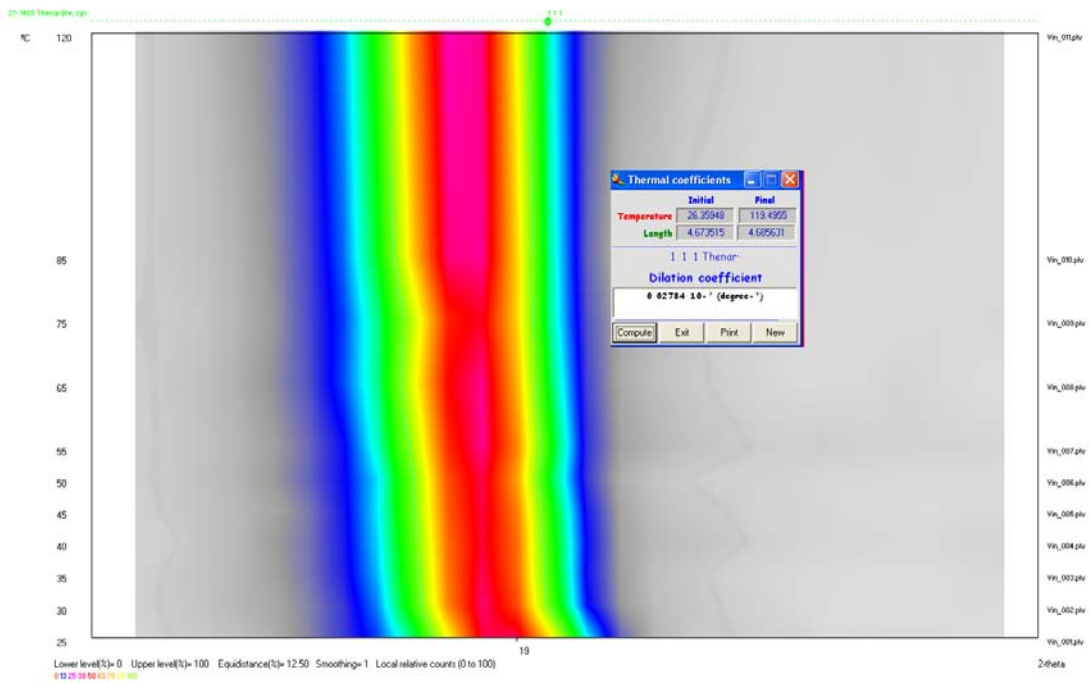


Figure 8.9.

[Home](#)

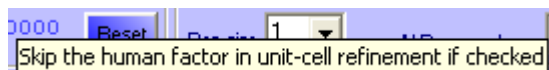


## Chapter 9. Unit-cell refinement.

XPowder has an advanced tool that allows comfortably the refinement of the unit-cell even if the sample has several components. The initial parameters are approximate values  $a, b, c, \alpha, \beta$  and  $\gamma$ . The results include the optimized new lattice parameters with corresponding statistics and the possibility to systematic study of extinctions of space-group and come to the study of the existence of partial or total superstructures.

As is well known, these data from initial cell unit are very difficult to calculate from the powder patterns, so that, wherever possible, it should be results obtained by methods of single crystal, such as those that often of database records. If the substance has been previously identified and the lattice parameters are included among the information in the database, such values can be used as initial values. When the tools' *Matching*' is present, XPowder read them directly. It can also use the data of cell isomorphous substances, even though the chemical composition is very different. In other cases, it is sometimes possible to calculate 'ab initio' of the unit-cell from powder patterns, through the use of specific programs, which often use methods of "trial and error" to propose possible solutions ('TREOR', etc).

If the box **H.F.**  (*Human Factor*) from the initial screen is checked, most of the refining process is done automatically without user intervention, although this need not lead to better solutions.




XPowder uses a non linear least squares routine that allows the simultaneous refinement of the lattice parameters  $a, b, c, \alpha, \beta$  and  $\gamma$ , and the instrumentals (horizontal and vertical) displacement of the sample.

As a general rule, it is always preferable to devote some time to make the necessary alignments in the diffractometer, rather than trusting the quality of results to the purely mathematical refinement of instrumental parameters. This is because the number of parameters to refine (6 from unit-cell and 2 instrumentals) may be too high compared to the available number of reflections. On the other hand, if the patterns are poor quality, it is possible that during the successive refinement cycles, the parameters really interesting, ranging from too bad correct values and there is no convergence in the overall refinement process.

Some parameters to refine, can be linked or fixed, so as to facilitate the calculation by using smaller matrices. For example, if the a tetragonal unit-cell is refined, the parameters  $a$  and  $b$  can be linked ( $a = b$ ) and the values of  $\alpha, \beta$  and  $\gamma$  can be fixed ( $\alpha = \beta = \gamma = 90^\circ$ ). If, moreover, the diffractometer is correctly aligned, you can skip the instrumental correction, so that only the cell parameters  $a$  and  $b$  are refined.

Other times, particularly when there are isomorphism or order-disorder phenomena, it may be interesting to refine a unit-cell of high symmetry in a system of lower symmetry (for example, a crystal with initial orthorhombic cell can be refined in monoclinic system or even in the triclinic system). This strategy is often used in structures type *spinel, perowskita, garnet*, etc.

Before making the refinement of a unit-cell, the displacement of  $2\theta$  angle should correct using a standard pattern (better internal standard), remove the component  $K\alpha_2$  (*'K $\alpha_2$  stripping'*) and 'read' the d-spacings of experimental pattern (better manually through the left mouse button on the main chart which automatically). The elimination of the component  $K\alpha$  is not indispensable, but in many cases can improve the precision of refined parameters up an order of magnitude. It is not desirable to do background subtraction in any case.

The process of refinement can be accessed from various parts of the program. For example, in the initial screen, the button  comes directly to the refinement tool (Figure 9.3). However, it is always desirable that the tool '*Matching*' is present, and that the initial crystalline phase is the current one. Simply press the button **Unit-cell** of this tool to obtain the refined unit-cell or to do further refinement cycles.

In the example in Figure 9.1, the program is available to refine the unit-cell of the mineral 'Celestine', having been identified and incorporated into the tool '*Matching*'. It is observed that the **HF** check-box of the main screen is selected. The phase, which provides the initial lattice

parameters is the third of the tool '*Matching*', which appears in the figure on a blue band (*Celestine*).

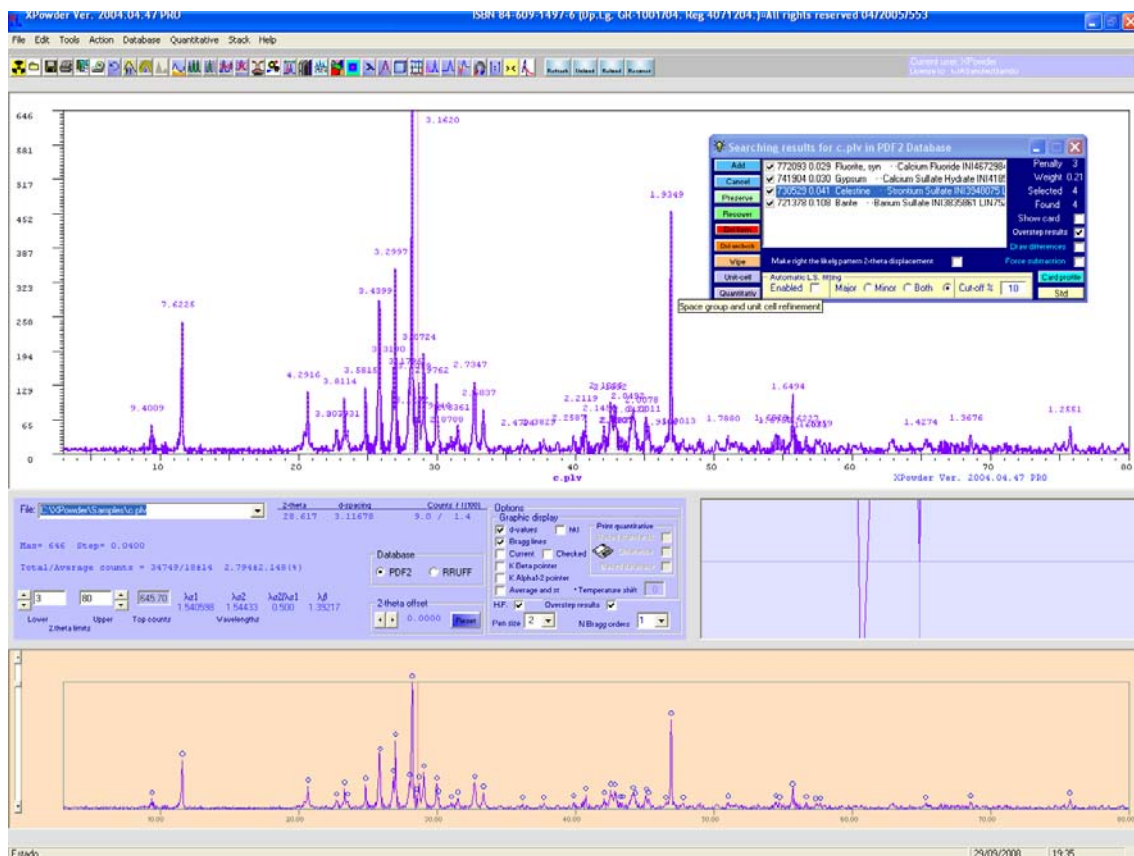


Figure 9.1.

By clicking [Unit-cell](#) comes the unit-cell refinement process. In Figures 92 and 93, shows that the program has performed automatically constraints due to the space group of crystalline phase (orthorhombic P lattice,  $\alpha = \beta = \gamma = 90$ ) and restraints for the instrumental alignment parameters. The values of the initial and refined unit-cell, including statistical and volume are also shown directly.

It can see that in the main graphic (figure 9.2) have been drawn calculated HKL lines for the refined unit-cell, but in a primitive and lacking space symmetry elements (screw axes or glide planes). HKL types are grouped by colors at different heights. The colors correspond to those of the axes of the [Unit cell parameters](#) framework. The reflections  $h00$ ,  $0k0$ ,  $00l$ ,  $0kl$ ,  $h0l$ ,  $hk0$  and  $hkl$  show from top to bottom. This distribution is done to facilitate the fast identification of isolated reflections. These can be studied in detail by 'zoom' on the upper main graphic (**Shift + left mouse button**), or in the lower secondary display.

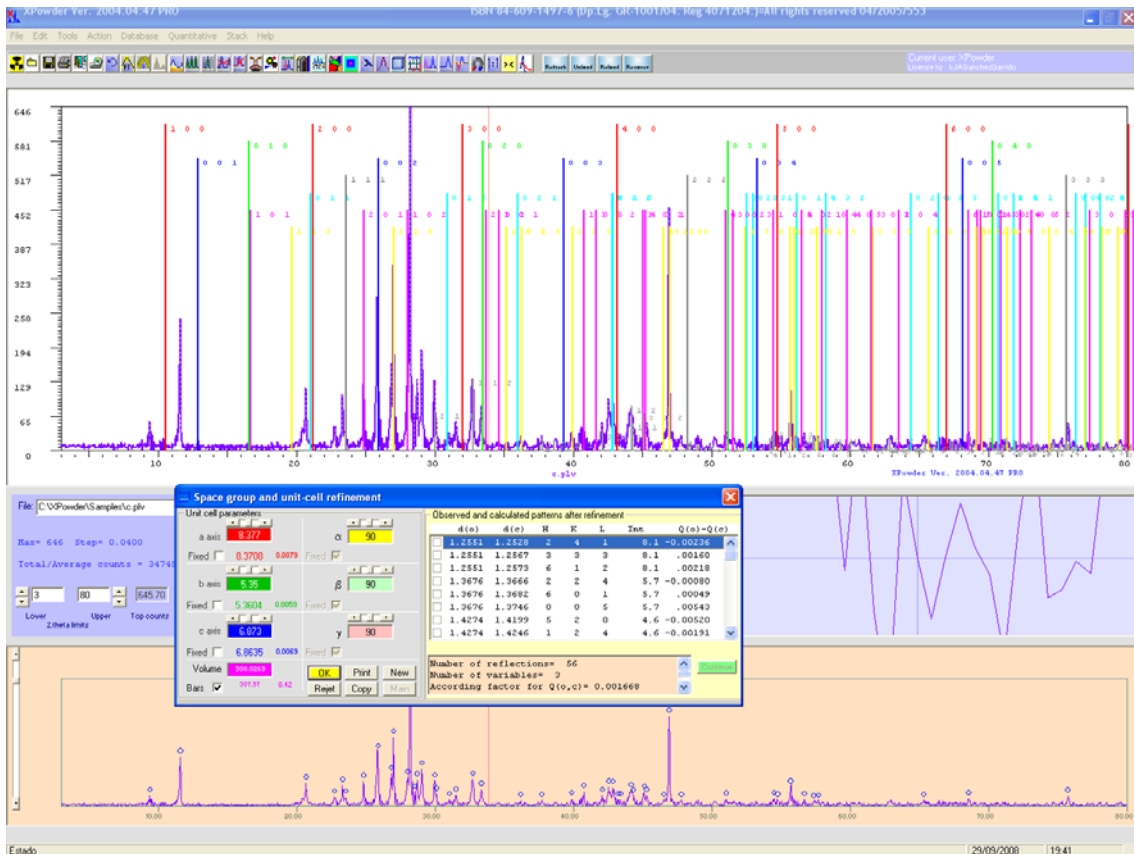


Figure 9.2

By pressing **OK** will get the figure 9.3.

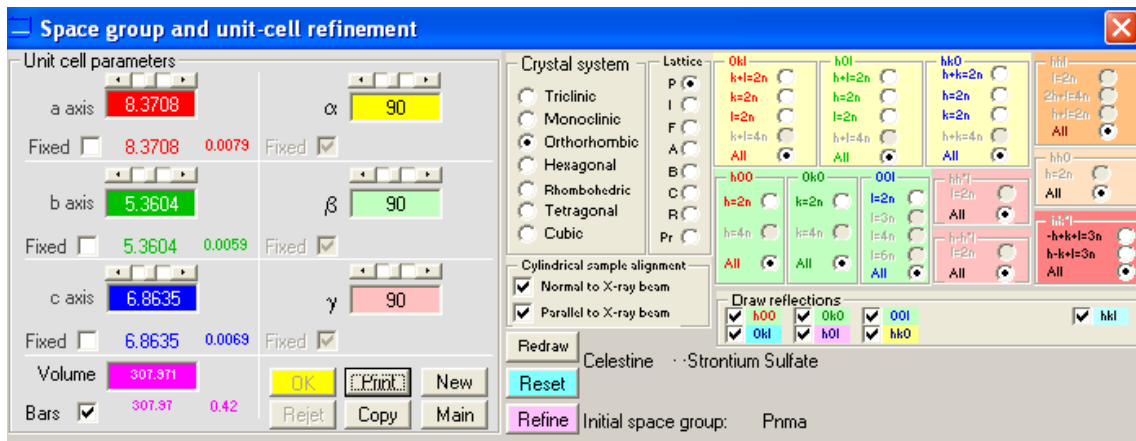


Figure 9.3.

From the screen shown in Figure 9.3 is you can do:

- Show / Hide bar chart of the refined unit-cell. (Box **Bars**).
- Restrict the drawing of hkl reflection groups attached to specific symmetry space elements (Bravais lattices, screw axes or glide planes, 'Ok<sub>l</sub>, h0<sub>l</sub>,..., hh\*<sub>l</sub>') framework). Initially there are no restrictions except those due to the lattice type. It can see that by stopping the cursor on the respective option buttons, a message appears overlapped, which contains information on the space symmetry associated with the systematic extinctions, linked to each HKL group, which facilitates the study of space group.
- Redraw reflections ( **Redraw** ).
- Draw the reflections by groups (Framework **Draw reflections** ).

- Modify 'manually' values calculated using cell cursors for each crystallographic parameter.
- Fix/Refine parameters in the next cycle (  Fixed check-box of each crystalline parameter or instrumental parameters of the framework [Cylindrical sample alignment](#)).
- Changing the crystalline system and Bravais lattice for the next cycle of refinement.
- Ignore the results in order to initiate a new unit-cell refinement with different conditions ().
- Print graphic (  ).
- Copy the graphic to the clipboard (  ).
- Back to the main menu (  ).
- Make the refinement of another crystalline phase of the specimen pattern and listed in the tool '[Matching](#)' (  ).
- Perform a new cycle of refinement using the refined parameters such as new initial parameters (  ).

eliminates the  selection (human factor), so all the following calculations will be controlled by the operator. The tool appears now as in Figure 9.4.

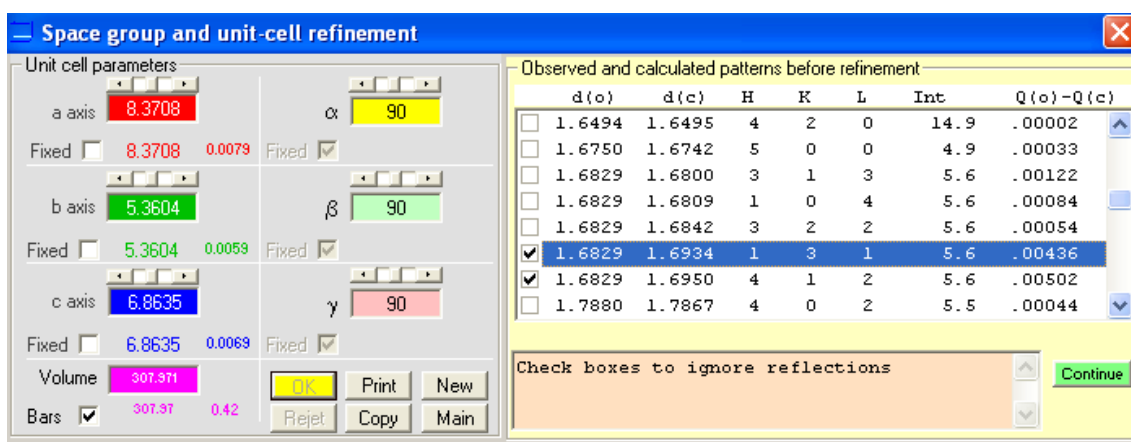


Figure 9.4.

La lista de la derecha muestra los valores de espaciados observados  $d(o)$  y calculados  $d(c)$ , índices  $hkl$  de cada reflexión, *intensidades observadas* referidas a cien y la diferencia entre los cuadrados de los vectores recíprocos observados y calculados  $Q(o)-Q(c)$ . Se puede recorrer la lista y eliminar del cálculo (marcar ) aquellas reflexiones cuyo valor ' $Q(o)-Q(c)$ ' sea excesivo ( $Q_{hkl} = 1/d_{hkl}^2$ ). En el ejemplo de la Figure 9.4 se indica al programa que debe prescindir de las reflexiones 131 y 412, ya que están marcadas. En este punto el programa queda detenido hasta que se pulsa la tecla , lo que proporcionará nuevos resultados (Figure 9.5) muy semejantes a los de la Figure 9.4, ya que apenas se han modificado las condiciones del afinamiento.

The list on the right of Fig 9.4, shows the observed  $d(o)$  and calculated  $d(c)$  d-spacings, HKL reflection index, observed intensities referring to 1000 (Int) and the difference between the observed and calculated squares of reciprocal vectors  $Q(o)-Q(c)$ . The list can be scrolled to eliminate of the refinement (tick ) those reflections whose value ' $Q(o)-Q(c)$ ' is excessive ( $Q_{hkl} = 1/d_{hkl}^2$ ). In the example in Figure 9.4, we have decided that the program rescinds the 131 and 412 reflections (which were already marked for this purpose). At this point, the program is paused until you press the button , which will provide new results (Fig. 9.5) very similar to the figure of 9.4, just because we have slightly modified the terms of refinement.



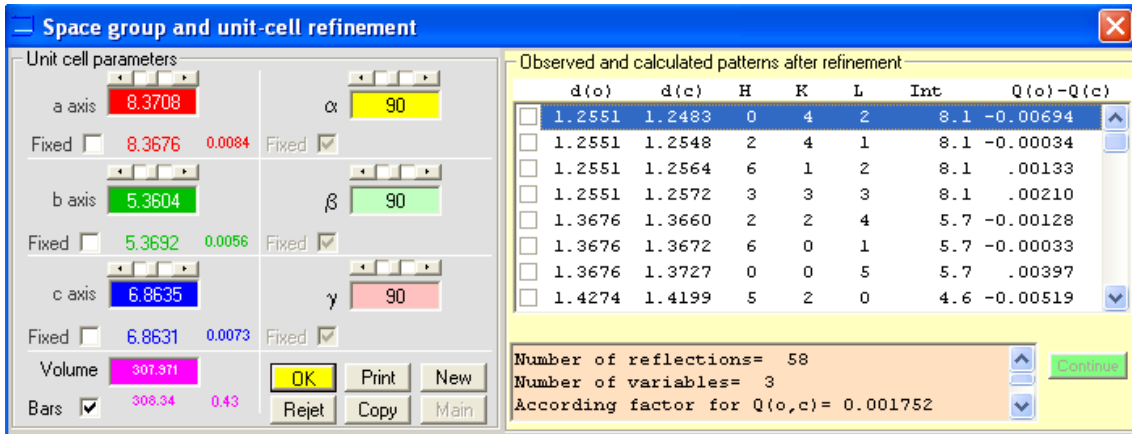


Figure 9.5.

Under the list of figure 9.5 there is a summary which contains the number of data used in the latest refinement (58), the number of refined variables (lattice axes **a**, **b** and **c**), and the overall **According factor for Q (or, c)** that, being very close to zero, indicates that the refinement has been done correctly. In addition to this, the calculated errors for each of the results are obvious signs of quality refinement (0.0084 Angstroms for a-axis, 0.0056 for b-axis, 0.0073 for c-axis and 0.43 cubic Angstroms for unit-cell volume).

With the **New** order (Fig. 9.5), the unit-cell refinement of another component of the sample can be done. In the example, by choosing 'Gypsum' and clicking **Unit cell**, the results for the new phase are obtained directly (Fig. 9.6).

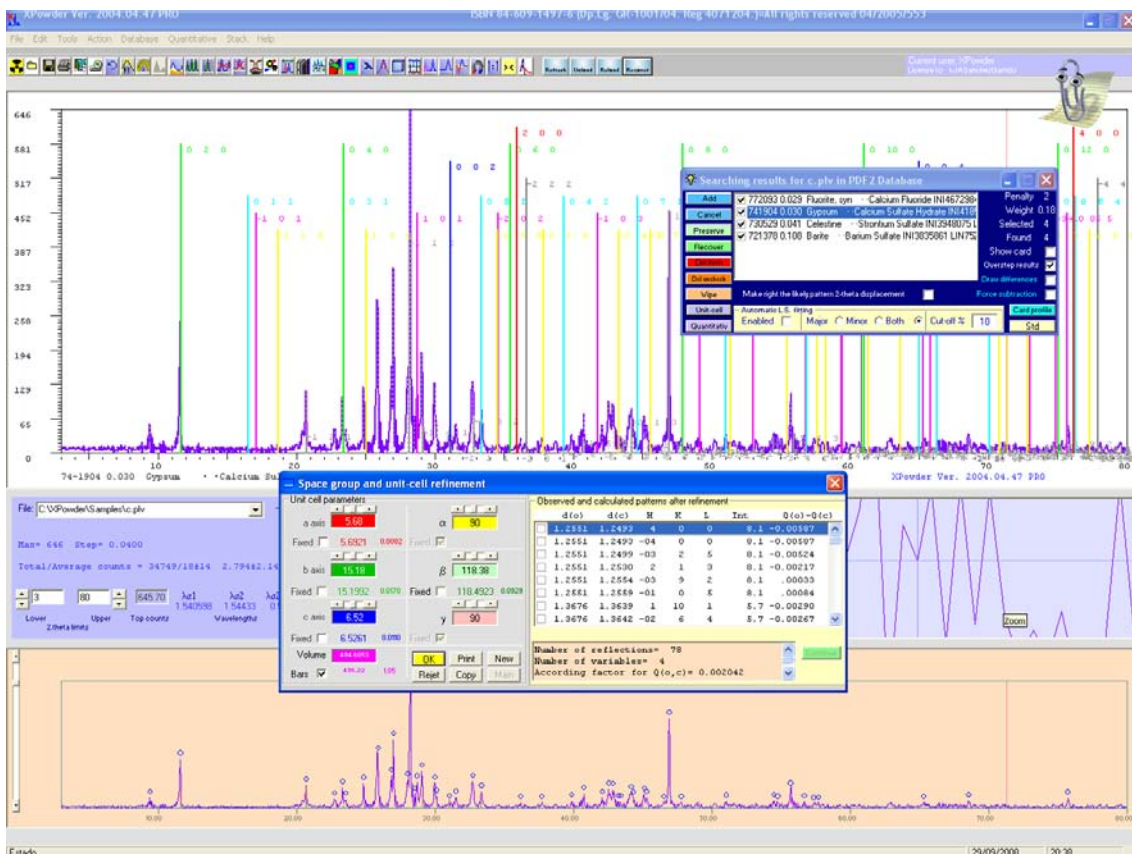




Figure 9.5. To summarize, in order to refine the unit-cell of each phase, the cursor is placed on it in the tool 'Matching' and the button **Unit-cell** is then pressed. The procedure can be repeated for each identified phase. See details in the text.

**Example: The determination of the ratio Ca / Mg in magnesium carbonates by PXRD** is usually performed through unit-cell refinement. The most likely result is obtained then by linear interpolation between the parameters of cell in terms of extremes which have well established unit-cell parameters and chemical composition. This is the general procedure used to obtain the exact term of any mineral having solid solution composition. What makes X Powder interesting for this analysis is that this program calculates unit-cell parameters with a single mouse click.

**Example:** By using the program X Powder, this **real** example has been developed in approximately two minutes. Adjustment charts come from previous experiences.

1. Load a *Calcite* diffraction pattern.

2.  $K_{\alpha 2}$  stripping  (it is an optional but advisable action). On the other hand, the internal standard and the 'spline' interpolation function , can improve the quality of the unit cell refinement.

3. Searching (i.e., 'one click searching'  or 'advanced searching' )

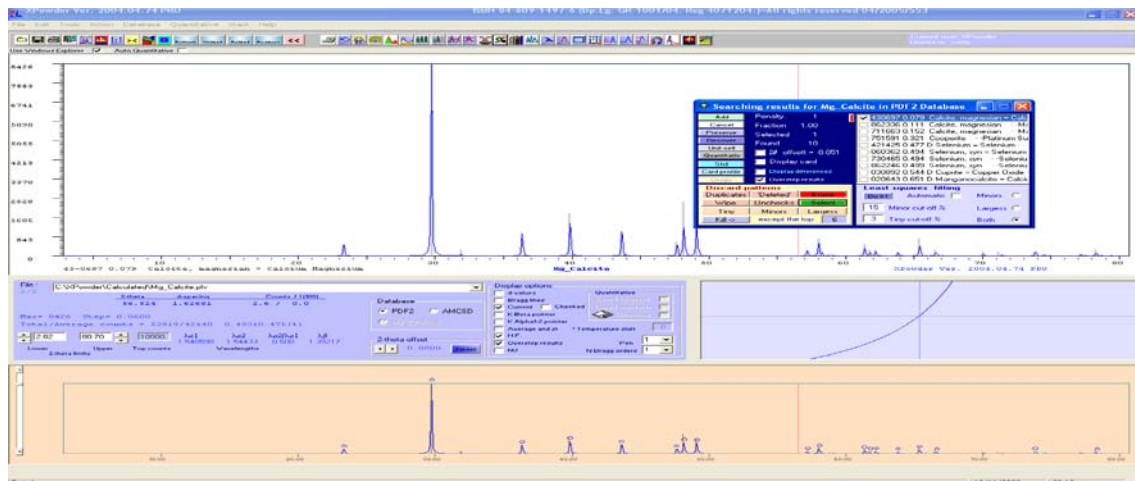


Fig 9.6

4. Click Unit-cell refinement 

5. Click . The unit cell is now refined:

**a-axis = 4.9361 ± 0.0040 Å      c-axis = 16.8475 ± 0.0219 Å**

**Unit cell volume = 355.49 ± 0.59 Å<sup>3</sup>**

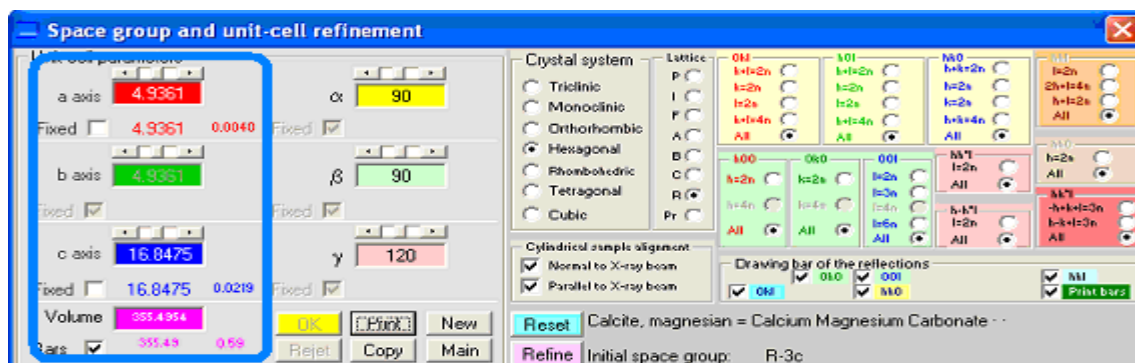
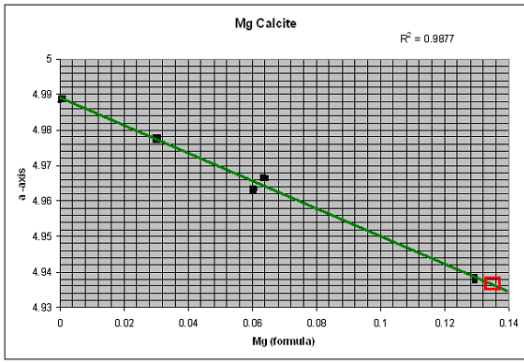


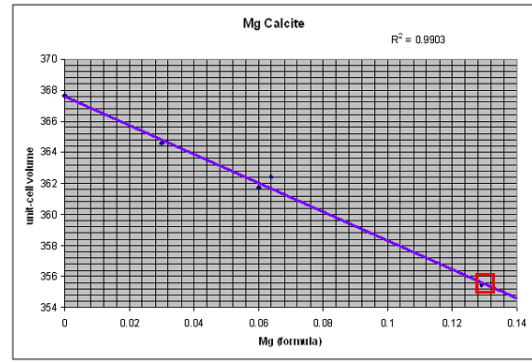
Fig 9.7

6. **Error assessment:**  $\Delta[Mg] = m \cdot \Delta(p)$  ; where  $\Delta(p)$  = error of the crystallographic parameters or unit-cell volume and  $m$  slope of the adjustment line.

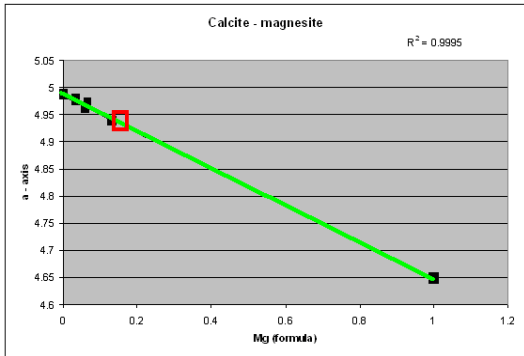
7. **Results:** The magnesium content of the specimen can be calculated using varied linear regression lines (Fig 1 to 6).



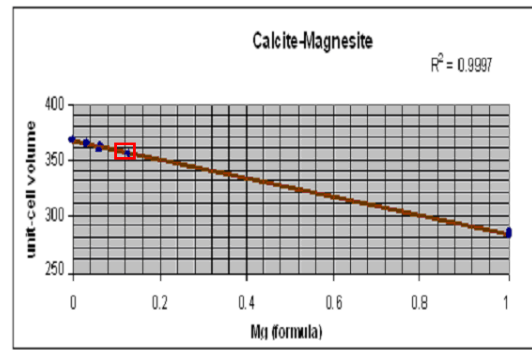
**Fig 9.8**  $Mg_{(formula)} = -2.5548 \cdot a + 12.79533 = 0.13 \pm 0.01$



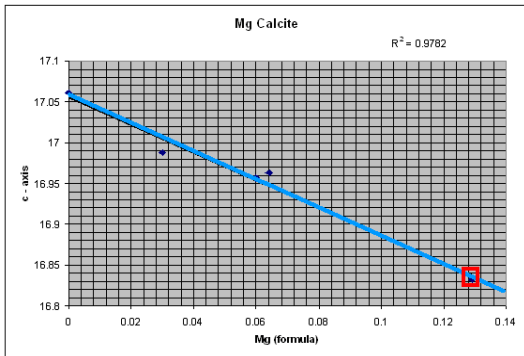
**Fig 9.12**  $Mg_{(formula)} = -0.0119 \cdot Volume + 4.35 = 0.13 \pm 0.04$



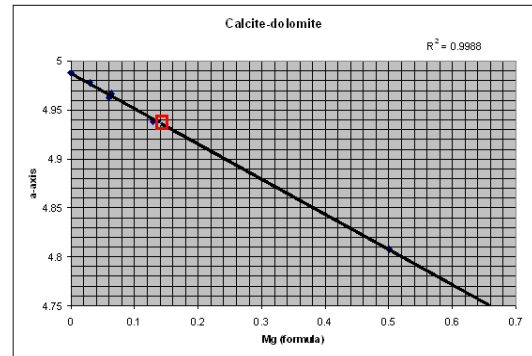
**Fig 9.9.**  $Mg_{(formula)} = -2.935 \cdot a + 14.62516 = 0.13 \pm 0.01$



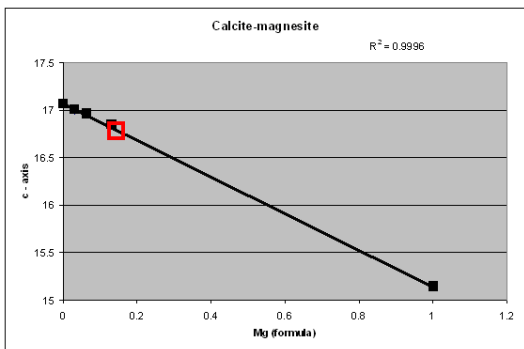
**Fig 9.13**  $Mg_{(formula)} = -0.0107 \cdot Volume + 3.94 = 0.12 \pm 0.04$



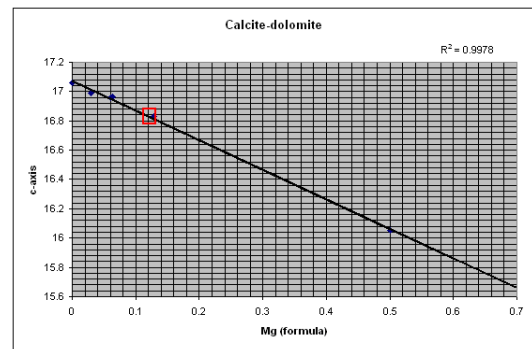
**Fig 9.10**  $Mg_{(formula)} = -0.587 \cdot c + 10.00645 = 0.12 \pm 0.01$



**Fig 9.14.**  $Mg_{(formula)} = -2.77932 \cdot a + 13.86 = 0.14 \pm 0.01$



**Fig 9.11**  $Mg_{(formula)} = -0.5188 \cdot c + 8.855 = 0.12 \pm 0.01$



**Fig 9.15**  $Mg_{(formula)} = -0.494169 \cdot c + 8.437 = 0.11 \pm 0.01$

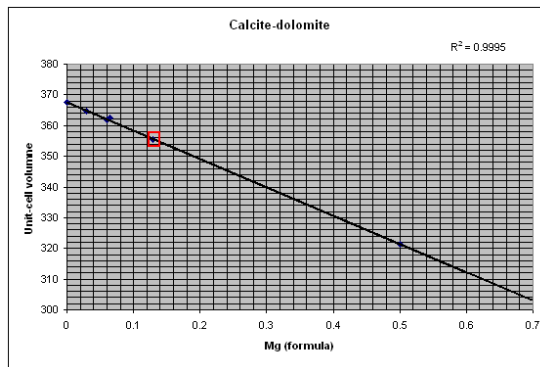


Fig 9.16.  $Mg_{(formula)} = -0.01083 \cdot volume + 3.98 = 0.13 \pm 0.04$

**Black points:** Regression data from experimental chemical and PXRD analysis. Data of the 'Mg content = 0.5' point in the figs. 7, 8 and 9 are of pure dolomite. Data of the 'Mg content=1' point in the figs. 2, 4 and 6 are of pure magnesite. Data of the 'Mg content=0 are of pure calcite. **Unit-cell volume =  $a \cdot a \cdot \sin(120) \cdot c$**  (figs. 5 and 6).

**Red squares:** PXRD data from example

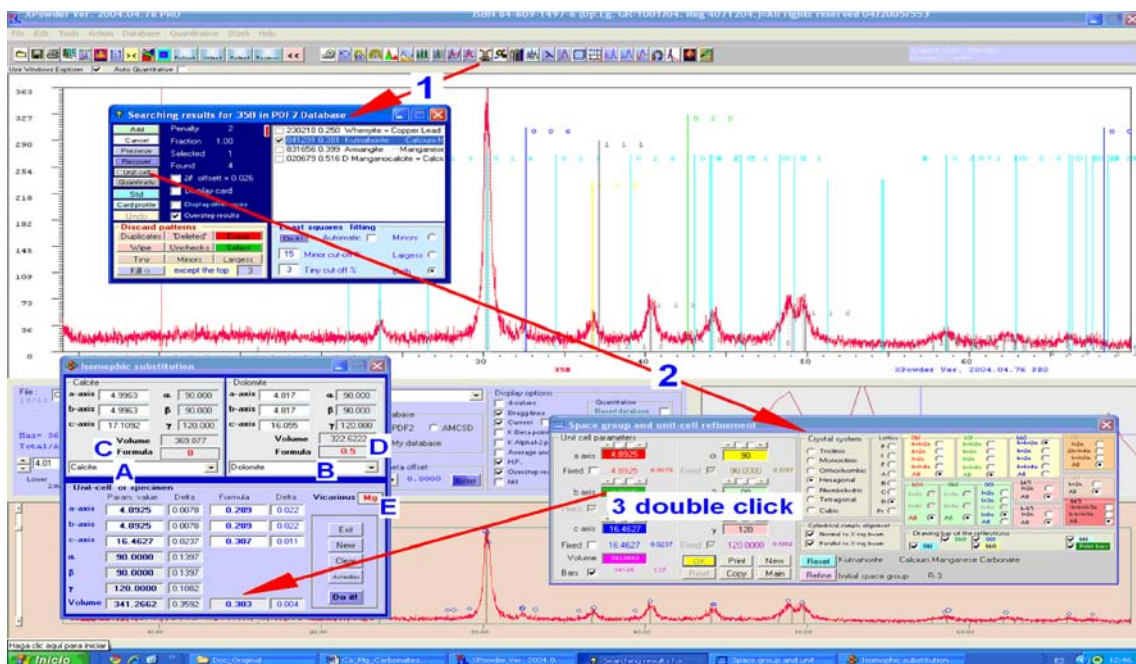


Fig 9.17 XPowder Program can do this automatically using a tool that calculates the terms interpolated from the values of ending cells. This tool is derived from the main menu (**tools ▶ Solid Solution**), or from the **cell refinement** tool, by double clicking on the text box of any lattice parameter. In the example, a carbonate type '*Mg-Ca kutnohorite*' has been identified (1). The unit cell is refined (2). Then, the exact term of the series is obtained by double clicking on the box of the refined parameter **b** (3). The extreme terms and vicariant elements can be changed into A, B, C and D. The editable file '*So/Sol.txt*' in the program directory, is a collection of unit-cell of exact composition phases as in the example:

Calcite	90
4.9963	90
4.9963	120
17.1092	Magnesite
90	4.646
90	4.646
120	15.139
Dolomite	90
4.808	90
4.808	120
16.055	

[Home](#)

## Chapter 10. Profile Analysis.

The reflection profiles provide information on the crystallinity. This concept can not be defined uniquely as it covers many aspects of the real crystal, as are the average crystal size, the size and distribution of crystal mosaic (it is often called in diffraction as 'coherent domain'), its form and habit, uniformity in both, dimensions (including here the inhomogeneous deformation due to active or residual tension) and composition of the lattice, etc.

This leads to significant changes to three elements of the observable profile:

- Absolute and relative values of the integrated intensity of the profile.
- Profile broadening.
- Asymmetry.

**Absolute and relative values of the integrated intensity.** Increases with the square of the average radio of the crystal sections, perpendicular to each reciprocal vector, which produces the HKL reflection. In the same way, the average of absolute intensity of the total diffracted by a powder sample is a good measure of its overall crystallinity. By contrast, the 'relative average' value, the most general expressed as a percentage (and also its standard deviation), is inverse function of the overall crystallinity (the latter two figures are virtually independent of the experimental conditions). All this are applied both to individual reflections and full pattern. Here, the concept of crystallinity refers primarily to the size of grain. These values are displayed directly by the program when the sample is loaded. These figures appear on the screen in numerical or graphic forms when the [Average and st](#) is checked(Figure 10.1).

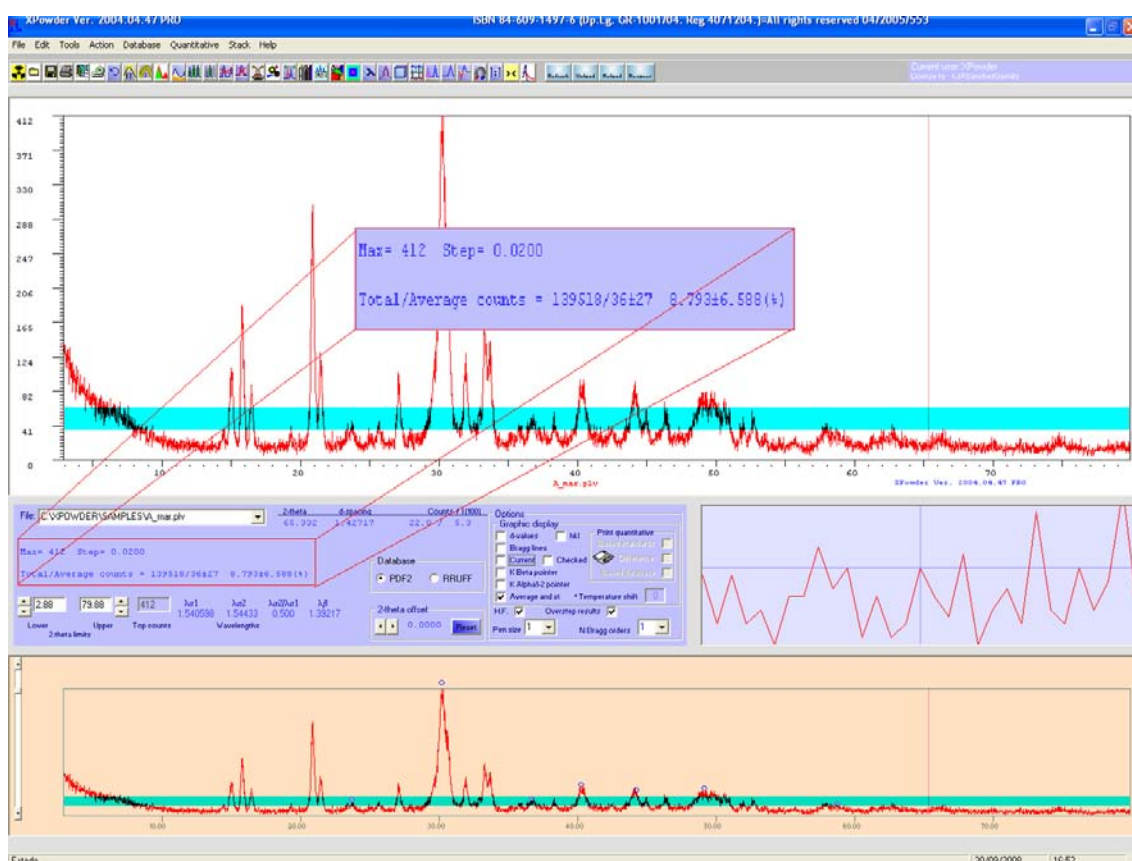


Figure 10.1. The base of the blue-green band is the average for the overall intensity of the pattern. The height of the band is the standard deviation. The crystals are small (Struvite). The average value of intensities is% 8793 ± 6588

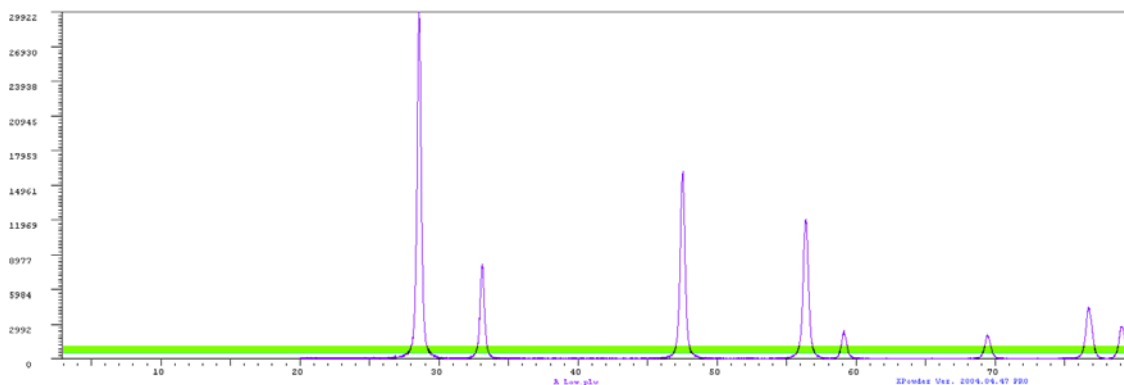


Figure 10.2. The pattern corresponds to a mid-sized crystal specimen (CeO). Average intensities (%) =  $0848 \pm 1703$

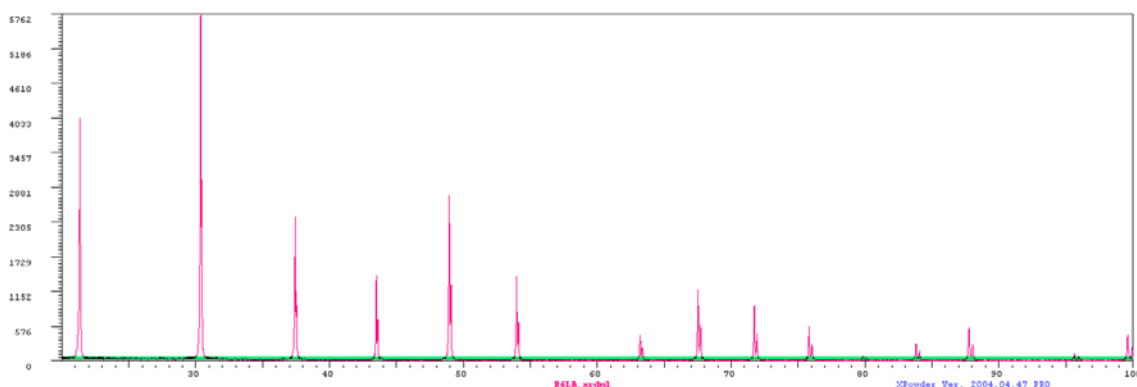


Figure 10.3. Pattern of large crystals specimen ( $B_6La$ ). Average value of intensities (%) =  $0.644 \pm 0.531$

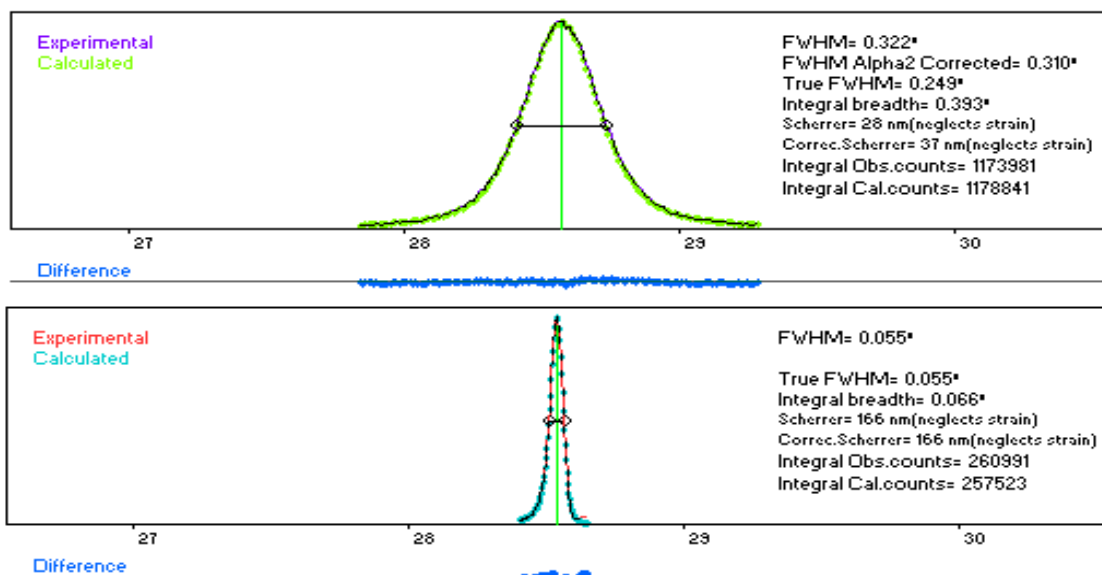


Figure 10.4. Powder individual profiles of CeO<sub>2</sub> 111 reflection of low powder size (above) and large size (below) grains. The intensities of the latter are divided by 106 in order that they can be comfortably handled by the program. As will be seen below, there increase in the size of the mosaic is related to sample larger crystals (as evidenced by the decrease in the width of the profile). The  $K\alpha_2$  component of radiation has been eliminated, to adjust the profile to a *pseudovoigt* function . .

**Line broadening.** The simplest measurement of dispersion (line breadth) is the a full width of the intensity distribution at half of the maximum intensity (*FWHM*). If the distribution is not symmetrical **XPowder** calculates the half of the maximum intensity on the left ( $w_1$ ) and right ( $w_2$ ) hand side of the peak ordinate. The *asymmetry* is defined as  $w_2/w_1$ . **XPowder** also includes the *integral breadth*  $\beta$ , defined as the width of a rectangle having the same area and height as the observed line profile. *Area asymmetry* ( $A_2/A_1$ ) has similar sense with *asymmetry*, by using of the left ( $A_1$ ) and right ( $A_2$ ) hand side areas of the peak ordinate. The shape of the profiles is measured by the *shape factor*  $\phi$ , defined as the ratio of the *FWHM* to the *integral breadth*. Thus, the calculated parameter for a profile are:

*FWHM* = Full width at half maximum.

*Asymmetry* =  $w_2/w_1$

*Integral breadth*  $\beta$

*Area asymmetry* =  $A_2/A_1$


*Shape factor*  $\phi$  =  $FWHM / \beta$

The causes of the widening and shape of the profiles are:

- Instrumentals
  - 1. The radiation is not strictly monochromatic.
  - 2. Geometry and diffractometer optical. Instrumental function.
- Related to the specimen.
  - 3. High percentage of amorphous materials (high background).
  - 4. Mosaic size (*coherent domain size* in diffraction terms).
  - 5. Heterogeneities and distortions of the unit cell
  - 6. *Non Uniform Strain* (or simply '*Strain*')

Non '*Uniform Strain*'(or simply '*Strain*') and '*Uniform Strain*' are two different concepts. The first cause a heterogeneous dispersion of the d-spacing values, resulting in a widening of different profiles in each  $\theta$ . In the second type, the sizes of all the unit cells modifying alike, as for thermal expansion or Pascal pressure, which causes a non-linear displacement of the  $2\theta$  angles of the reflections patterns, but not the widening of the profiles.

Of all these possible causes of widening the profiles, only the latter two are related to the nature of the analyzed crystals and are often referred as '*microtexture*'. It is therefore necessary to find a suitable procedure to subtract the effects of the first three, which are alien to their own crystals, so that the shape of the '*pure profile*', to say the profile due exclusively to that *microtexture*, will be isolate.

1. Monochromatism. Of course, acquire the patterns with monochromatic radiation through the use of serialized monochromators or synchrotron radiation is convenient. But this is not always possible, so in some methods of *microtexture* analysis (Scherrer analysis or Williamson-Hall) is needed, as a preliminary step, the complicated process of elimination of the  $KA_2$  component (stripping). **XPowder** is done with sufficient quality through the push of the button . If the Williamson-Hall methods are used, the elimination of  $KA_2$  also must be performed on the experimental *instrumental function* (see next item).
2. Instrumental function. The calculation of the so-called '*instrumental function*' is more complicated. This function describes the profile shape induced solely by the diffractometer, and that conditions at last, the final resolution of this technique. The *instrumental function* in theory can be calculated as the product of convolution of the curves generated by each of the components of diffractometer (X-ray source, the sample surface, divergence of the rotation axis, transparency of the specimen, set of divergence and reception slits, monochromator, etc). The details of this calculation can be seen in the book of HF Klug and L.E. Alexander, '*X Ray Diffraction Procedures*', whose 2<sup>nd</sup> edition has been printed by Wiley & Sons in 1974. In general this theoretical calculations are very complicated, because it is very difficult the parameterization of the functions of each element of convolution. Instead, experimental patterns of very high crystallinity compounds ( $B_6La$ ,  $CeO$ , etc.)

are often used in order to use as an *instrumental function*. Then, the *instrumental profile broadening* can be modeled by the Caglioti equation:

$$B^2 = U \cdot \tan^2\theta + V \cdot \tan\theta + W$$

Where B is the width of the profile for each pure angle  $\theta$ . U, V and W have to be adjusted from the *very high crystallinity pattern*. Other times and whenever possible, the *instrumental function* can be obtained from a sample that possesses not only a high crystallinity, but a similar composition to the studied specimen. In this case, the Caglioti function is not used. The calculation of the Caglioti function is performed automatically by X Powder, as explained in Chapter 11.

3. **Background.** Some methods of microtexture analysis, using only the reflection widths (Scherrer and Williamson-Hall), needed to remove the background (📊) before making adjustments in the distribution functions of the crystal reflections. However, except in cases where it is really excessive, the background should never be removed. The background should never be eliminated when using the Warren-Averbach methods, of course

The distribution function that X Powder used to model the *pure profiles* (profiles cleaned of instrumental interference) is:

$$P(L) = \Phi_{(0)} \left\{ \gamma \cdot e^{-\pi x^2 [4 \cdot \ln 2 / \pi] / (B)^2} + [(1 - \gamma) \cdot B^2 / 2(B^2 + x^2)]^p \right\}$$

Where:

x = free variable

B = Reflection broadening (refinable parameter or experimental data)

$\gamma$  and p are refinable parameters

If  $\gamma = 1$ ,  $p = 0$  the function is Gaussian

If  $\gamma = 0$ ,  $p = 1$  the function is Lorentzian (or Cauchy)

If  $\gamma = 0$ ,  $p > 1$  Pearson VII

If  $\gamma = 0$ ,  $p < 1$  Super Lorentzian

If  $\gamma = 0$  to 1,  $p = 0$  Pseudo Voigt (Gaussian + Lorentzian)

If  $\gamma = 0$  to 1,  $p \neq 1$  Mixed function

$\Phi_{(0)}$  = Function value for  $x = 0$  (maximum)

**Asymmetry.** X Powder adjusts, independently the right and left sides of the diffraction profiles, so it is possible to quantify the asymmetry of both, areas as B parameters.

With a strictly monochromatic radiation, sometimes, the slope of the profiles is softer towards minor  $2\theta$  angles. This can be attributed to a lack of uniformity in the size of the unit cell, due to partial hydration process that causes increased volume crystalline, by way of example.

If the slope is softer towards larger  $2\theta$ , the cause is more difficult to explain. Sometimes this can occur in the process of crystallization from a solid solution, in which the more modern cells are formed from isomorphic elements of smallest radius. On the contrary, can be caused in the process of dissolution where the more soluble terms are largest radius elements. In any case, systematic measures from the parameters of asymmetry and form factor described above can be established.



## Profile analysis methods based on width and shape of the diffraction profiles.

The use of strictly monochromatic radiation allows very simple treatments of profiles in terms of variance, so that when the profiles are adjusted to Cauchy functions, you can write:

$$B_{\text{total}} = B_{\text{Instr}} + B_{\text{sample}} = B_{\text{Instr}} + B_{\text{size}} + B_{\text{strain}}$$

If the profile function is Gaussian the relationship is as follows:

$$B_{\text{total}}^2 = B_{\text{Instr}}^2 + B_{\text{sample}}^2 = B_{\text{Instr}}^2 + B_{\text{size}}^2 + B_{\text{strain}}^2$$

From the analysis of the *distribution function* used by X Powder, a more general relationship can be inferred for the *pseudo voigt*:

$$B_{\text{total}}^{(1+\gamma)} = B_{\text{Instr}}^{(1+\gamma)} + B_{\text{sample}}^{(1+\gamma)} = B_{\text{Instr}}^{(1+\gamma)} + B_{\text{size}}^{(1+\gamma)} + B_{\text{strain}}^{(1+\gamma)2}$$

This equation allows easily deduce the value of the width of the reflections when this type of profile function is adequate.

### 1. Scherrer Method.

It is used to calculate the coherent domain size (uncorrected strain) from a single reflection profile ( $\lambda$  supposed monochromatic):

$$\text{Size}(\mu\text{m}) = K \cdot \lambda(\text{\AA}) / (10 \cdot B_{\text{sample}} \cdot \cos\theta_0)$$


The coherent domain size '**Size( $\mu\text{m}$ )**' is often expressed in nanometers (hence the 10 that appears in the denominator).  $\lambda$  ( $\text{\AA}$ ) is the wavelength of monochromatic radiation and  $\theta_0$  is the central angle of reflection.

The width of the reflection  $B_{\text{sample}}$  can be *FWHM*, or the *integrated width*, expressed both in radians. When the instrumental role is known,  $B_{\text{sample}}^{(1+\gamma)}$  can be obtained by the relationship  $B_{\text{sample}}^{(1+\gamma)} = B_{\text{total}}^{(1+\gamma)} - B_{\text{Instr}}^{(1+\gamma)}$ . Otherwise it is assumed that  $B_{\text{sample}}^{(1+\gamma)} = B_{\text{total}}^{(1+\gamma)} \cdot \gamma$  is a refinable parameter, automatically calculated by X powder.

**K** ( $0.8 > K > 1.1$ ) is a experimental constant, which is different when *FWHM* or  $\beta$  are used. Optionally X Powder calculates this value but generally uses  $K = 1$

To measure the size of the coherent domain with Scherrer method, X Powder use the button



or the [Strain and X-size](#) command of home menu. Once on the appropriate screen, press the left mouse button on , or click just about any reflection profile, and the automatic adjustment to a 'pseudo Voigt' function is obtained ( $\gamma$  is also fitted), as shown in Figure 8.4. It is desirable to make a proper  $K\alpha_2$  stripping, and even an '*Spline*' interpolation, before starting the calculations. If you wish to obtain results expressed in absolute values, which can be compared with those of other laboratories, the *instrumental function* should also be set in advance. The background subtraction is not desirable to make, unless cases of very poor quality patterns. In any case, the background subtraction should not be too 'aggressive'.

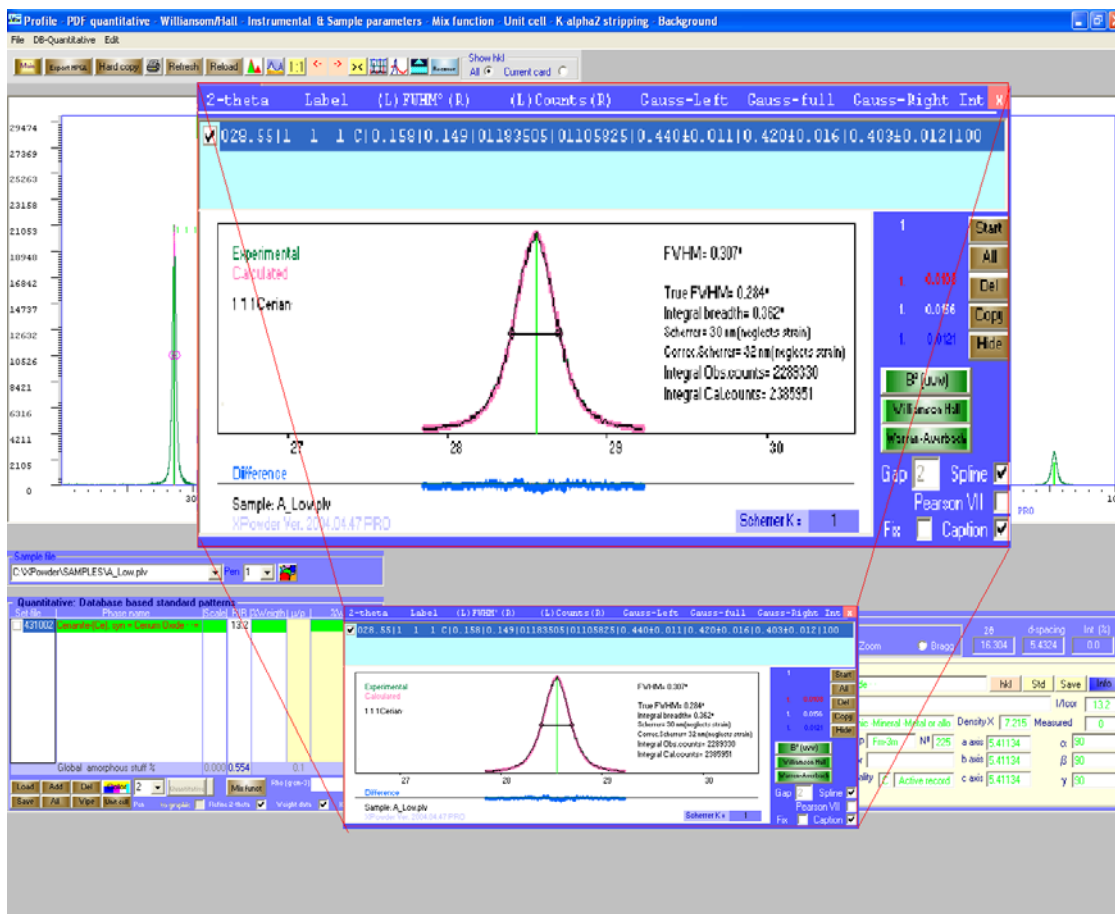


Figure 10.5.

The data shown in the figure 10.5 are as follows:

- $2\theta$  of the maximum ('2-theta' column).
- If the object 'Matching' is present, *hkl* index are shown, on the contrary  $2\theta$  is printed. (Column 'Label').
- Values' FWHM 'expressed in degrees of  $2\theta$ , both to the right side (R) as to the left (L). Columns '(L)', 'FWHM°', '(R)'
- Gaussians components ( $\gamma$ ) of the adjusted functions by the *Right* and *Left*, as well as the error of those values (Columns' Gauss-left ', ' Gauss-full 'and' Gauss-Right '). The statistical values for left, full and right profiles are also shown to the right of the chart with red, white and blue respectively.
- Drawings of the adjusted and difference functions (blue).
- Drawing and value of experimental FWHM.
- Corrected FWHM Value for the instrumental function (**True FWHM**), that should be calculated for each diffractometer. In any case, the program uses latest available function.
- **Integral Breadth** in  $2\theta^\circ$ . Coherent domain size in nm without correction instrumental ('Scherrer').  $K = 1$  is used and the widening of the profile caused by 'Strain' is not taken into account.
- Idem with instrumental correction ('**Corr Scherrer**').  $K = 1$  is used and the widening of the profile caused by 'Strain' is not taken into account.
- Experimental profile integral counts (**Integral Obs. Counts**).
- Calculated profile integral counts (**Integral Cal. Counts**).

If the box **Fix** is marked, the position of the highest profile is set at the exact angle  $2\theta$ , which has made the 'click' with the mouse. In another case, the program finds the position of the maximum.

If the box **Pearson VII** is marked, the exponent  $p$  of the general distribution function is refined.

If the box **Spline is marked**, the experimental data are interpolated virtually, through an a cubic spline, and the position of the maximum with more precision is obtained.

The box **Gap** contains the interval which will be used in adjusting the distribution functions, on both sides of the maximum.


If the box **Caption** is unchecked, any comments appear on the image.

The button **Start** allows you to start a new list of measures. It is used when switching experimental options, or at the beginning of adjustments for special functions such as those of Caglioti (for diffractometer or sample), or Williamson-Hall microtexture analysis.

The button **All** lets you select all the profiles of the header list for subsequent calculations (Caglioti, Williamson-Hall, for example).

The button **Del** lets you remove the current profile of the list (blue stripe).

The button **Copy** moves the graphic to clipboard.


The button **Hide** hides the tool. It is the same as pressing the button  again.

El botón **Rejet profile** elimina de la lista general el último ajuste.

The button **Rejet profile** lets you remove the last fitted profile.

The button **B<sup>2</sup>[uvw]** lets calculate the Caglioti equation. If the sample is a very high crystallinity specimen, enables you to adjust the instrumental function (see Chapter 11).

The button **Williamson-Hall** performs the calculation of the size of mosaic and 'Strain', according to the method of Williamson-Hall.

The button **Warren-Averbach** is equivalent to , and go to a special display, where are the tools necessary to perform calculations of mosaic sizes and 'Strain' by 'Warren-Averbach' methods, as well as 'Log-normal' distributions. This button involves a reload of the original data of the diffractogram pattern, so that all operations carried out before will be cancelled (background subtraction,  $K\alpha_2$  stripping, etc).

All the partial results are listed in detail in the *Log file* for each of the analyzed profiles, as shown in the following example:

```
-----
Profile Information Statistics (Parts of profile L= Left R= Right):
1 1 1 Cerian.
2-theta: 28.553 D-spacing= 3.1236
K-Alpha2 stripping has been performed

-----
Pseudo-Voigt Gaussian Weigh
-----
2theta| Label |(L)FWHM°(R)| (L) Counts (R) | Left part | Full |Right part | Int
028.55|1 1 1 C|0.158|0.149|01183505|01105825|0.440±0.011|0.420±0.016|0.403±0.012|100
-----
Observed FWHM= 0.3070 (2-theta°)
```

```

FWHM (After Instrumental Broadening Corrections)= 0.2838 (2-theta°)
Current Instrumental Cagliotti Coefficients (x 10000): U= 0.032900 V= -0.035600 W= 0.019030
Asymmetry= 0.9438
Areal Asymmetry: 0.9344
Integral breadth: 0.362 (2-theta°)
Shape factor (Observed FWHM/Integral breadth): 0.847
Max. counts: 21053
Uncorrected Size (Scherrer-neglects strain)= 29.7 nm. (Scherrer K=1)
K-Alpha2 and Instrumental Broadening Corrected Size (Scherrer-neglects strain)= 32.1 nm. (Scherrer K=1)
Integral observed counts : 2289330
Integral calculated counts= 2385951
Pearson component has not been fitted for profile

```

## 2. Williamson-Hall Method .

The method of *Scherrer* explained above, uses a single X-Ray reflexion for the calculations of mosaic size, but provides no information on the '*strain*' ( $\epsilon$ ), since this affects the profile differently in each  $2\theta$  value:

$$\epsilon = \tan\theta \cdot (4/ B_{\text{strain}})$$

$$B_{\text{strain}} = \tan\theta \cdot (4/ \epsilon)$$

Where,  $B_{\text{strain}}$  is the variance of the distribution due to 'strain', expressed in radians, and  $\epsilon$  is the 'strain' defined as  $\epsilon = \Delta L/L$

The effect of '*strain*' on the broadening of the profile is generally very small compared to due to the magnitude of the mosaic. To correct the effect of '*strain*', the method of *Williamson-Hall* can be used.

The variance of a pseudo voigt distribution can be expressed:

$$B_{\text{size}}^{(1+\gamma)} + B_{\text{strain}}^{(1+\gamma)2} = B_{\text{sample}}^{(1+\gamma)} = B_{\text{total}}^{(1+\gamma)} - B_{\text{Instr}}^{(1+\gamma)}$$

The method of *Williamson-Hall* calculates separately, the size and the 'strain' by two or more orders of a reflection HKL, but gave no information on the size distribution, provided by the method of *Warren-Averbach*, which will be explained later. Thus,

$$B_{\text{sample}}^{(1+\gamma)} = B_{\text{size}}^{(1+\gamma)} + B_{\text{strain}}^{(1+\gamma)2}$$

$$\text{Size}(\mu\text{m}) = K \cdot \lambda / (10 \cdot B_{\text{size}} \cdot \cos\theta_0) \quad (\lambda \text{ in } \text{\AA}, B \text{ in radians})$$

By removing and replace the values of  $B_{\text{size}}$  and  $B_{\text{strain}}$ , you get:

$$B_{\text{sample}}^{(1+\gamma)} = K \cdot \lambda / (10 \cdot B_{\text{size}} \cdot \cos\theta_0) + \tan\theta \cdot (4/ \epsilon)$$

This is the expression of the equation of a line, whose independent variables are  $B_{\text{sample}}^{(1+\gamma)}$  and the function values are  $\tan\theta$ . In this way, for  $x=0$  we can obtain  $(\text{Size}(\mu\text{m}) \cdot 10 \cdot \cos\theta_0) / (K \cdot \lambda)$  and the slope is  $4/ \epsilon$ .

If the experimental values  $B_{\text{sample}}^{(1+\gamma)}$  are plotted versus  $\tan\theta$ , the absolute values of  $\text{Size}(\mu\text{m})$  and  $\epsilon$  can be obtained from the regression line.

As can be seen easily, the size obtained depends on the *hkl* direction and at least two observations are needed (eg 111 and 222). In isometric crystals can be used occasionally reflections from different directions, although the detailed analysis tends to give a much richer information.

With XPowder, this analysis is done via the button [Williamson-Hall](#) on the screen of the figure 10.5.

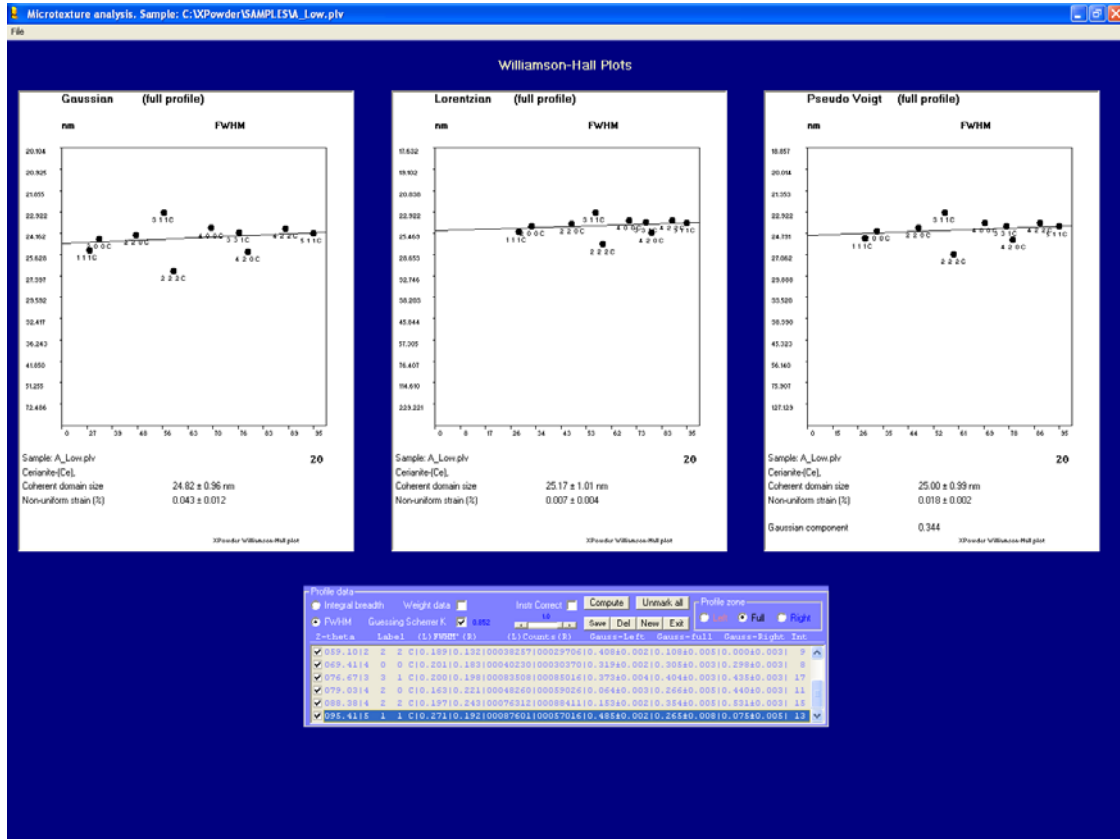


Figure 10.6.

The figure 10.6 shows an analysis of 106 *Williamson-Hall* made automatically on all reflections of a diffractogram of CeO. The three models correspond to Gaussians, Lorentzians and Pseudo Voigt models respectively. As broadening criterion has been used FWHM. The constant K value from *Scherrer* equation is optimized ( $K = 0.852$ ) (box [Guessing Scherrer K](#) marked). The values of 'Strain' are expressed in% and are very low, according to the values of the slope of the straight lines in all cases.

Other options such as ([Integral Bread](#)), ([Weight data](#)), instrumental correction ([Inst.Corr](#)), right side, full side or left side profiles (selecting in the [Profile zone](#) framework, etc can be used.

Figures 10.7 y 10.8 show the *Williamson-Hall* analysis performed on the  $h00$  reciprocal direction, with and without instrumental correction respectively.

Both the method of *Scherrer* as the *Williamson-Hall*, provide size values, as measured on directions HKL, whose calculations involved in the entire volume of crystalline domains. That is the criterion used for statistical weight is the volume. The term 'volume weighted' is used to refer to the sizes obtained, as opposed to the 'area weighted' provided by other methods such as the *Warren-Averbach* which is explained below. In general the weight methods based on 'volume' provide values greater than those achieved with 'areas'.

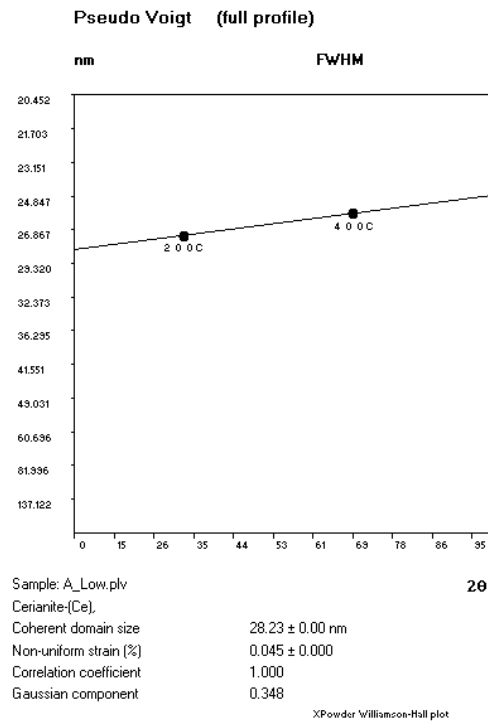


Figure 10.7. Williamson-Hall plot for the h00 direction. The instrumental correction was made.

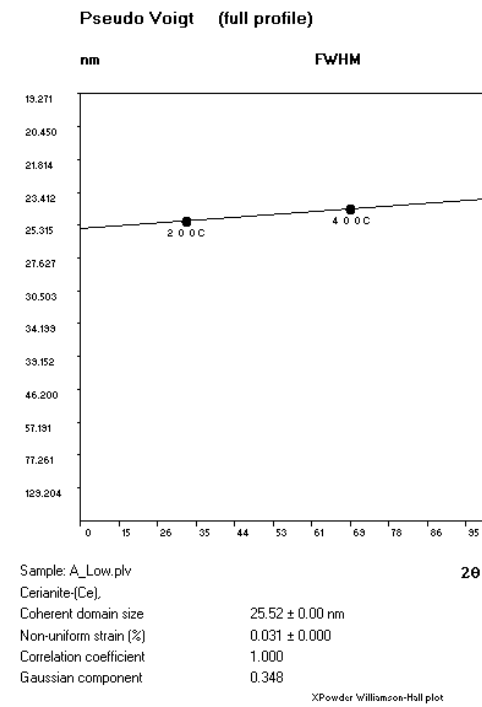


Figure 10.8. Williamson-Hall plot for the h00 direction. The instrumental correction was not done

[Home](#)

### Warren-Averbach method.

A more comprehensive and accurate study of the diffraction profiles based on Fourier analysis, attends the role of total profile ( $R_{total}$ ) as a result of the convolution of the instrumental profile ( $R_{Instr}$ ) with the function generated by the sample ( $R_{sample}$ ), being the latter the product of convolution of the size function ( $R_{size}$ ) and due to strain function ( $R_{strain}$ ).

$$R_{total} = R_{Instr} * R_{sample} = R_{Instr} * R_{size} * R_{strain}$$

The method requires the representation of diffractograms in reciprocal space, instead of doing it in classic  $2\theta$  function. Obtaining histograms diffraction in this space has very experimental difficult, as it requires appropriate programming of diffractometer very different than usual. X Powder uses an alternative path based on the theoretical calculation of histograms (ie diffractograms with  $\Delta 2\theta$  constant) based on typical  $2\theta$ , (which is the usual way of presenting the data) through interpolation methods for cubic spline. It has been proven the effectiveness of this method that allows you to create reciprocal graphs with the same quality and form of profiles than those obtained experimentally. The method is used both for the instrumental function as to the sample function.

The *Warren-Averbach* method is a highly elaborated approach of size and strain analysis by powder X-Ray method which uses the deconvolution of the structural line profile (true profile) and the Fourier transform for evaluation of size of the coherent domain and strain (to say: space dispersion  $\Delta d/d$  %). This methods states that the absolute values of Fourier cosine coefficients are then product of the size and the strain coefficients (Bertaut 1949). The coefficients can be numerically calculated and then related to the distribution of the column length (L), defined as the distance in the crystallite, perpendicular to the diffracting planes  $hkl$  (parallel to diffracting  $q_{hkl}$  vector). The convolution of the size broadened and strain broadened profiles in reciprocal space is the product of their Fourier transforms in real space. The absolute cosine fourier coefficients ( $A_{L,q}$ ) of the true profile are:

$$A_{L,q} = {}^s A_L \cdot {}^\varepsilon A_{L,q} \quad [1]$$

Being

${}^s A_L$  absolute cosine fourier coefficients size dependents,

${}^\varepsilon A_{L,q}$  absolute cosine fourier coefficients strain ( $\varepsilon$ ) L and q dependents and

$$q = 2 \cdot \sin\theta / \lambda$$

If two or more order of the reflection for hkl plane are available in the diffractogram, separate information for size and strain can be extracted assuming small strain values and Gaussian strain distribution for all values of L. Applying logarithms to [1]:

$$\begin{aligned} \ln(A_{L,q}) &= \ln({}^s A_L) + \ln({}^\varepsilon A_{L,q}) \\ &\cong \ln({}^s A_L) - 2\pi^2 L^2 q^2 \langle \varepsilon_L^2 \rangle \end{aligned} \quad [2]$$

where  ${}^\varepsilon A_{L,q} = e^{-2\pi^2 L^2 q^2 \langle \varepsilon_L^2 \rangle}$  (theoretical expression value for  ${}^\varepsilon A_{L,q}$ ) and  $\langle \varepsilon_L^2 \rangle$  is the mean-square strain for the correlation distance L.

In successive plots of ( ${}^\varepsilon A_{L,q}$ ) versus  $q^2$  at fixed L values,  ${}^s A_L$  are obtained from the intercept of the strain lines (at abscissa = 0) and  ${}^\varepsilon A_{L,q}$  from the slope of the strain equations. Note that they are a strains coefficients curve for each q profile.

**General procedure in W-A analysis .**

1. The sample and instrumental profiles are normalized to maximum value=1 (figure 10.9.) and plotted in the reciprocal space with constant step (abscissa =  $2 \cdot \sin\theta/\lambda$ , ordinates = counts, figure 10.10).

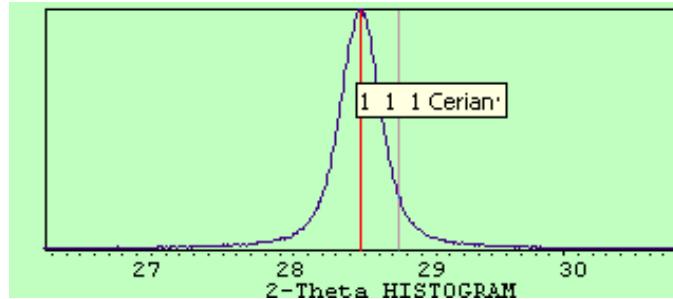


Figure 10.9.  $2\theta$  histogram.

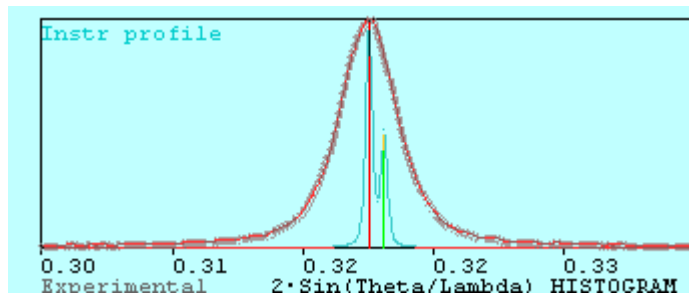


Figure 10.10. Reciprocal histogram

2. Deconvolution is carried out in order to obtain the 'structure profile' ('pure profile', 'physical diffraction line',...) of the sample pattern (figure 10.11).

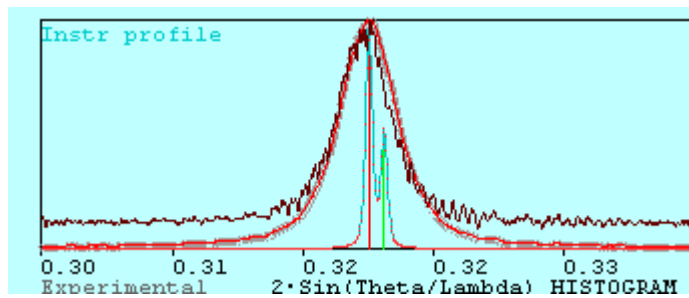


Figure 10.11.



3. Absolute values of cosine fourier coefficients ( $A_L$ ) from the structure profile are calculated and normalized to  $A_0=1$ , and plotted versus column length  $L$ , perpendicular to the reflecting plane  $hkl$  (parallel to reciprocal  $q$  diffraction vector. Figure 10.12).

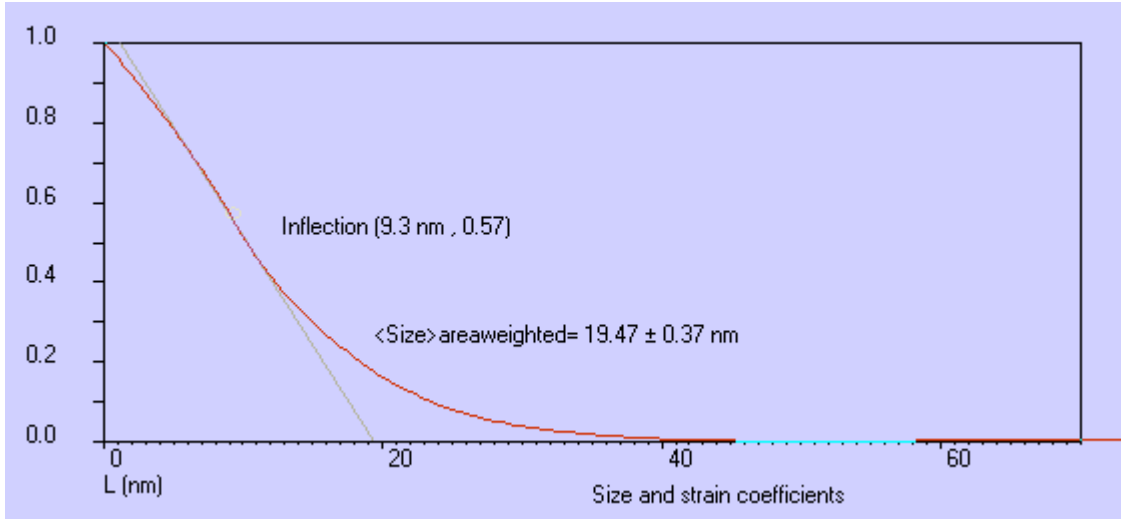


Figure 10.12

The average  $L_{AREA}$  size (uncorrected strain) is calculated from the tangent of the coefficients curve in  $(A_q, 0)$  point for  $A_L=0$  in inflection point ( $2^{nd}$  derivate=0, grey line in figure 10.12).

4. By selecting an upper Bragg's order line of  $hkl$  size and strain coefficients values can be separate, according to [2]

$$\ln(A_{L,q}) = \ln({}^s A_L) - 2\pi L^2 \langle \varepsilon^2 \rangle q^2$$

that is the straight line equation

$$y = b + a \cdot x$$

where

$$b = \ln({}^s A_L)$$

$$a = -2\pi L^2 \langle \varepsilon^2 \rangle q^2$$

$$x = q^2$$

$$y = \ln({}^s A_L)$$

$${}^s A_L = e^b \quad [3]$$

$${}^\varepsilon A_{L,q} = \exp(aq^2) \quad [4]$$

$$\langle \varepsilon^2 \rangle = -a/2\pi L^2 \text{ (average value)} [5]$$

Then, it can be obtain the pure size Fourier-Cosine coefficients plot (column length probability to be greater or equal to L) and the average area weighted size value ( $\langle L_{AREA} \rangle = 20.07$  nm in example) perpendicular to the (111) selected crystalline face (parallel to selected q reciprocal vector figure 10.13),

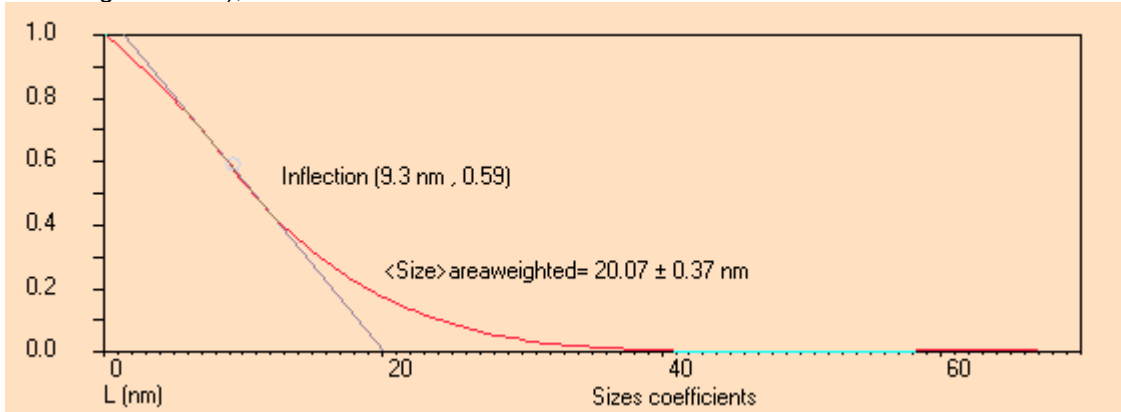


Figure 10.13.

the  $\epsilon_{L,q}$  strain Fourier-Cosine coefficients plots for each analyzed profiles (figure 10.14)

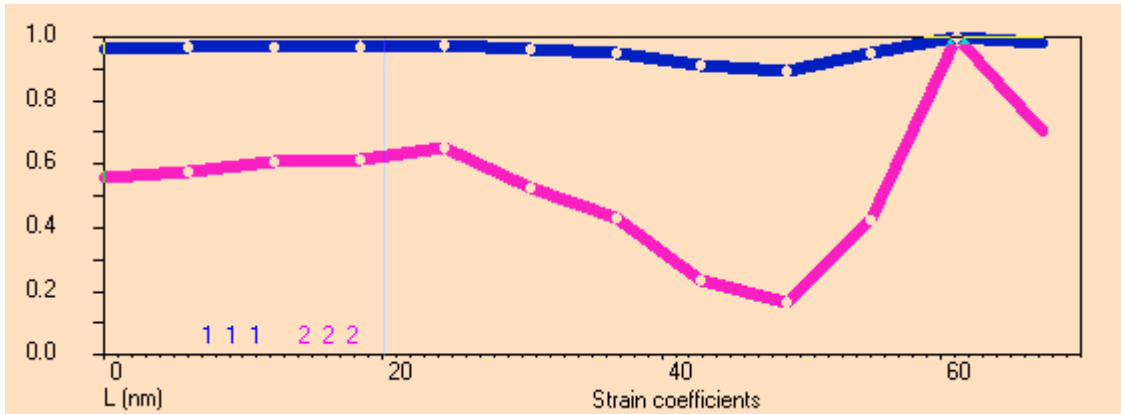


Figure 10.14

and the strain ( $\delta d/d = \langle \epsilon^2 \rangle^{1/2}$ ) versus column lengths plot (figure 10.15).

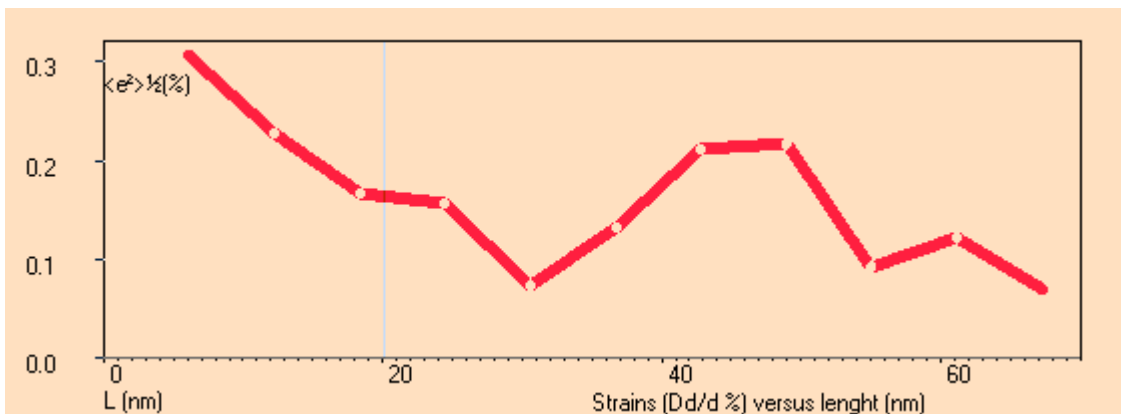


Figure 10.15

**Log-normal distribution.**

Additionally in most cases of small particles or nanocrystalline powder, it can be calculated then column length distribution by fitting to the log-normal distribution function (figure 10.16):

$$f(x) = \frac{1}{\sqrt{2\pi}\sigma} \frac{1}{x} \exp\left\{-\frac{[\ln(x/m)]^2}{2\sigma^2}\right\} \quad [6]$$

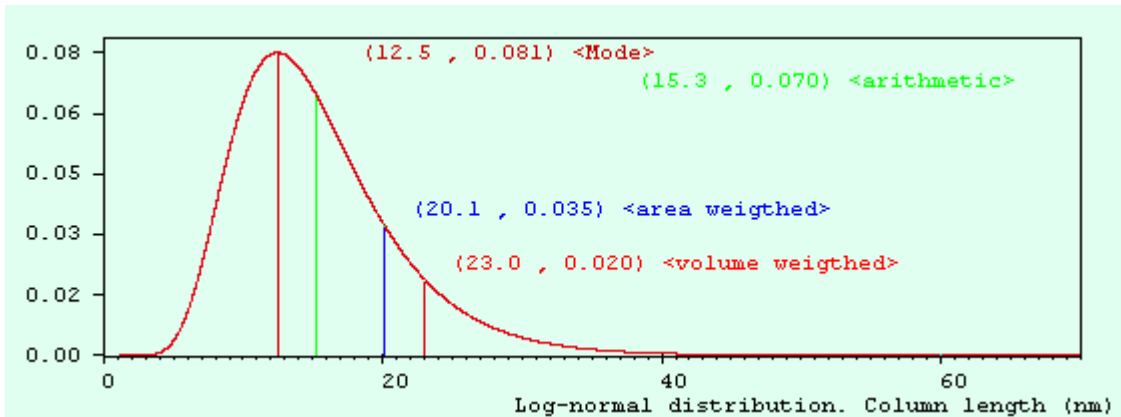


Figure 10.16

**How does XPowder do this?**


When a high quality diffractogram pattern is loaded, you can enter to *Warren-Averbach* module (figure 10.17) by clicking  or **Warren-Averbach** command of figure 10.5..



Figure 10.17.

### Selecting profiles:

Select the profiles by draping around the reflection with the left mouse button in any histogram. The selected profile will be enlarged in the graphic with blue background (reciprocal histogram) and green background (2-theta histogram). Alternatively select 2θ lower and upper limit values and pulse **Actualize** . Optionally, use **Center** in order to improve the symmetry of the profile in the θ interval.

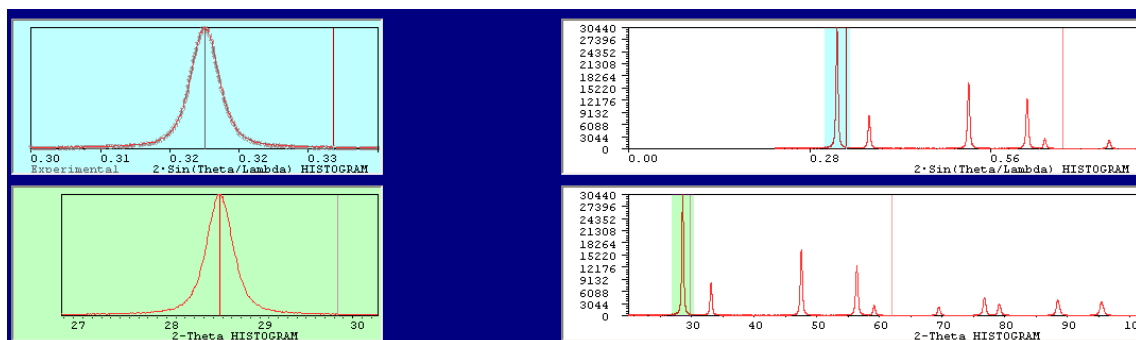


Figure 10.18.

### Definable parameters and computation

**Instrumental Profile**

Calculated  Experimental

Fitting function: Pseudo Voigt  Gaussian component  Pearson VII

Shape factor: 0.2

Include K-alpha2

Compute Instr  Instr correct

Log-Normal size distribution

Restraint sigma  $\sigma$  0.5

Selected profile

2-theta limits: 20 150

Average  Maximum

Automatic  Centre

Equal width  Int counts 0

Scherer Size 0

Scherer K 1 Area weight<Size>nm 20

Standard deviation

PROFILE 1 5 3 3

Inflection point

X value 3

Restraint X value Gap (nm)

N Bragg orders 2

Vol weight Size W-H 20

Scale factor 3.5

2-theta step 0.01 2-sin(T)/L step 0.00003

70 Max L

Figure 10.19.

### Instrumental Profile section

**Calculated**: Allow calculate the instrumental profile by using the Caglioti approximation and selected distribution function (**Pseudo Voigt** or **Pearson VII**) by using an instrumental-standard sample (The National Institute for Standard and Technology- NIST, LaB<sub>6</sub> by example).

**Experimental**: Enable the use of a sample of equal composition and 'infinite' crystallinity for instrumental broadening effects correction.

**Compute Instr**: Shows the selected instrumental profile.

**Include K-alpha2**: The effects of the doublet  $K\alpha_{1,2}$  will be corrected if checked.

**Instr correct**: The instrumental correction will be applied if checked. Default is 'Checked'.

### **Log normal size distribution** section

**Restraint sigma**: Bind  $\sigma$  to actual value

$\sigma$ : Dispersion for log normal distribution. If **Restraint sigma** is checked the  $\sigma$  value is not calculated.

**Compute** (or **Hide**) **Log-Normal size distribution**: Compute/Hide log-normal size analysis [7] and draw graphic of probabilistic distribution of L values (figure 8). The parameter used are  $L_{area}$  and  $\sigma$ .

### **Selected Profile** section

**2-theta limits**: Lower and upper 2-theta of the selected reflection. The values can be input directly, by using of the displacement bar or by draping in the histograms.

**Centre**: The reflection is placed in the centre of the selected interval according to the **average** or the **maximum** of the profile. It will be automatically executed when **Compute\_Coeff** are clicked and the **automatic** box is checked.

**Maximum** or **Average**: Criteria for automatic centering of the profile

**N-polynom**: Select de order of the polynomium for fitting the column length  $L_{AREA}$ . Default value is 3.

**Points**: Number of cosine coefficients to be included in polynomial regression ( $A_0$  to  $A_{points}$ ). Default value is 10.

**Equal width**: Restraint to be equal the width of all the profiles. This box is checked automatically when the first profile has been analyzed by **Compute Coeff**.

**Area weigt<Size> nm**: Value of the area-weighted column length ( $L_{AREA}$  nm) for current analysis (both corrected or uncorrected strain)

**Scherrer Size**: Value of Scherrer size in nm for the current profile.

**PROFILE n**: Ordinal number of the actual profile

**h k l**: Editable label for actual profile.

**Compute Coeff**: Compute **Centre** (if the centre box is checked), **Actualize** and the average area weighted  $L_{AREA}$  size (uncorrected strain) is calculated from the tangent of the coefficients curve in  $(A_0,0)$  point for  $A_L=0$  (figure 4). Uses [7], **N-polynom** and **Points** parameters.

### **Inflection point** section

**X value**: Centre for  $\langle Size \rangle_{AREA}$  calculation

**Gap (nm)**: Interval of X value for lineal regression in orden to obtain then  $\langle Size \rangle_{AREA}$  WEIGHTED value

**Restraint X value**: Bind **X value** to actual value.

### **Others parameters and commands**

**Max L**: Upper limits in nm for column length in graphics. Default value is 45 nm.

**Size W-H** Estimated volume weighted size (nm). This value can be improved from X Powder [Williamson-Hall](#) plot module and can be changed manually by the user. It is used in the calculus of  $\sigma$ .

**Recover** Allow to recoup prior searching PDF2 cards. It is used for get hkl index of the histograms reflections by stopping the mouse cursor on the graphics. By stopping in the reciprocal histogram profile, 'hkl' index of the reflection is writing automatically in the 'h k l' editable label box.

**N Bragg order** Allow to show the first N reflection orders from the actual position of cursor.

**2-sin(T)/L step** Editable value of the step in reciprocal histogram. The change must be actualized with the button **Actualize**.

**Wipe** Reset profile counter and analytical results.

**Actualize** Compute and redraw graphics according to actual parameters. It will be automatically executed when **Compute Coeff** is clicked.

**Exit** Leave Warren-Averbach tools and go to X Powder home screen.

**Compute W-A**: Execute [1] to [5] Warren-Averbach analysis and draw figures 4 to 7. Uses the profiles selected by checking in the list box of figure 12.

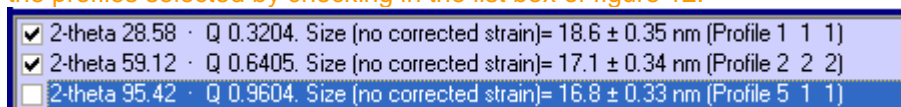


Figure 12.

Note: Use right mouse button for others pop-up contextual menus. **Help** button shows a quickly W-A user guide.

### Warren-Averbach Quick Start User Guide

1. Select first order profile by draping with left mouse button in any histogram (example: 1 1 1 reflection).
2. Centre profile and zoom (click **Centre**). Optional).
3. Change instrumental profile options (optional).
4. Compute Fourier coefficients (Click **Compute Coeff**).
5. Repeat 1 to 5 for another order profiles (example: Select 2 2 2, 3 3 3, etc. reflections)
6. Compute Warren-Averbach (Click **Compute W-A**)
7. Compute Size Distribution for log-normal model (Click **Size distrib**). Optional)

### Lectures.

Balzar, D., Audebrand, N., Daymond, M.R., Fith, A., Hewat, A. Langford, J.I., Le Bail, A., Louër, D., Masson, O., McCowan, C.N., Popa, N.C., Stephens, P.W. and Toby, B.H. (2004) *J. Appl. Cryst.* **37**, 911-924

Bertaut, E.F. (1949). *C. R. Acad. Sci. Paris*, **228**, 187-189, 492-494.

Warren, B.E. *X-ray Diffraction*. (1969). Reading, Mass. Addison-Wesley. 1990 Edit. 381 p.

Lucks, I., P. Lamparter, E.J. Mittemeijer, *An evaluation of Methods of Diffraction-Line Broadening Analysis. Applied to Ball-Milled Molybdenum*, *J. Appl. Cryst.* **37**(2004) 300.

[Home](#)

## Chapter 11. Caglioti equation calculation.

The Caglioti equation calculates the width of the diffraction peaks (B), through the adjustment of the three parameters (U,W,W) of the formula:

$$B^2 = U \cdot \tan^2\theta + V \cdot \tan\theta + W$$

In principle, this function was used to synchrotron diffraction, but also can be used with any other of X-ray monochromatic radiation. There must have a efficient monochromator or eliminate analytically  $K\alpha_2$  component, so that the function of Caglioti can be used correctly.  $K\alpha_2$  stripping can be done by X Powder with enough precision, where values of wavelengths and reason  $IK\alpha_2/IK\alpha_1$  are sufficiently accurate. (See Chapter 3.4).

To adjust these parameters (U,V,W), we have to calculate individual profiles, as explained in Figure 10.4 and then, press the button **B<sup>2</sup> (uvw)**. The image of the Figure 11.1 will be obtained.

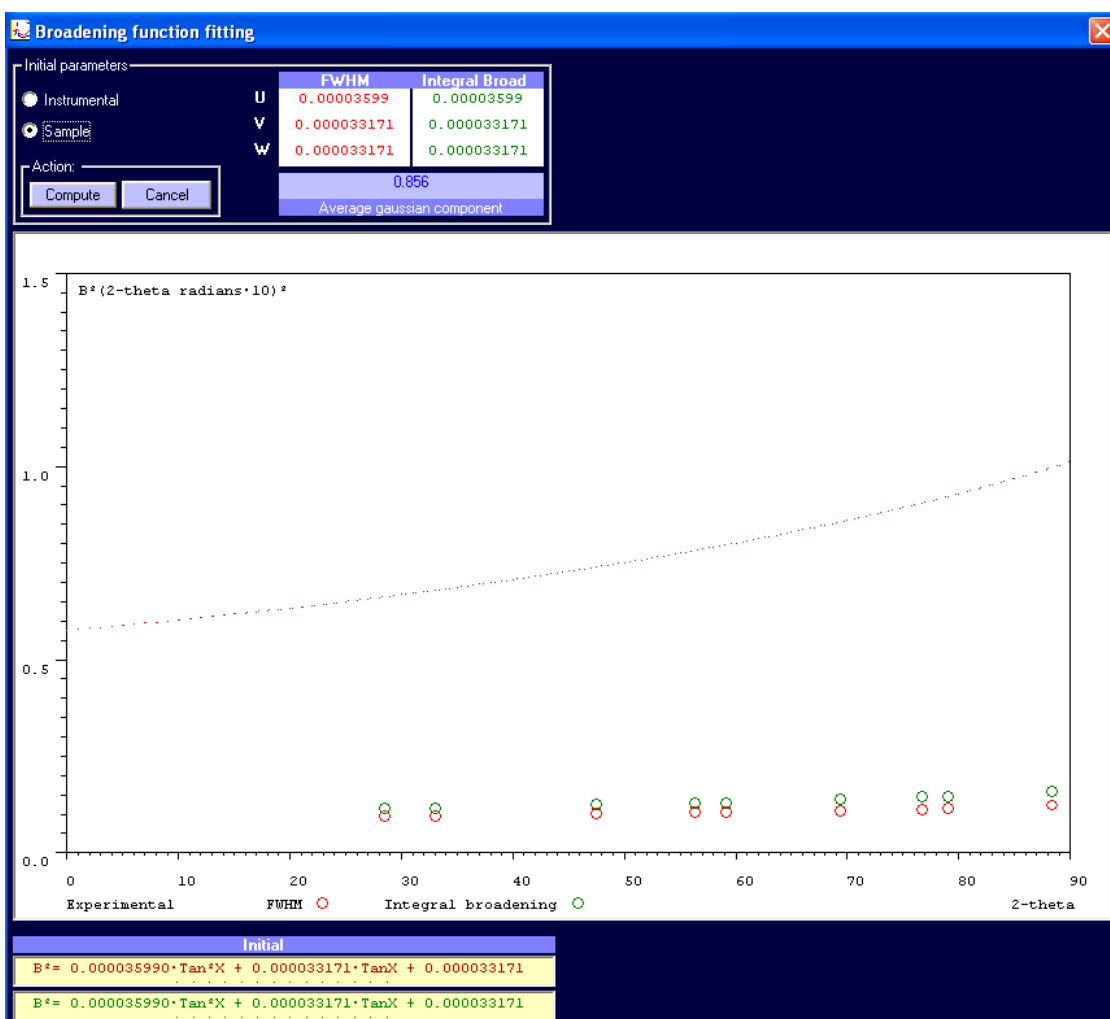


Figure 11.1.

In the graph of figure 11.1, the values of experimental widths and initial Caglioti functions are shown (Red circles= FWHM, Green circles= Integral broadening), both in algebraic and graphic form (the last one previously saved on the hard drive of your computer). You can adjust both the 'instrumental function' (when using a standard sample of a very high crystallinity), as the 'sample function' which can be used later in theoretical profile calculations, or initial profile data in Rietveld analysis programs. Before making the Caglioti

adjustments, X Powder automatically calculated the 'pseudo-voigt' average profile of the sample, whose Gaussian component appears in the top frame.

In this example, the **Instrumental** option must be chosen, because we want to adjust the *instrumental function* of the diffractometer. Pressing **Compute** functions are calculated and adjusted for **FWHM** (red) and '**Integrated broadening**' (green, Figure 11.2).

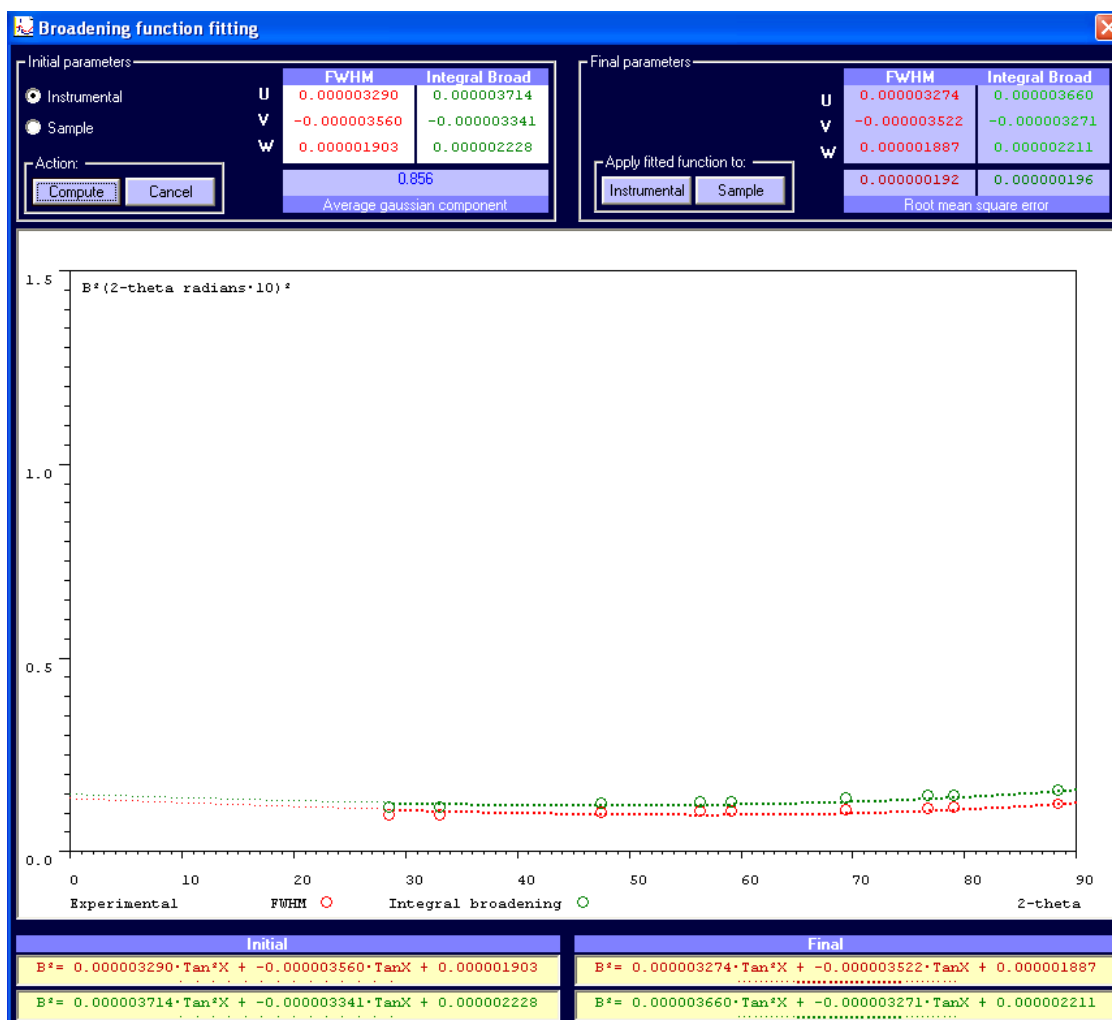


Figure 11.2.

The least-square adjusted functions are drawn with thick points in the analyzed  $2\theta$  interval and with thin points in the extrapolated zones. The numerical values are printed on the bottom right. If it is then pressed **Cancel**, the calculations will be discarded. If **Instrumental** is pressed, the calculated values will be applied to all instrumental corrections which are required in the future. Touching **Sample**, the UVW calculated values will be applied to new theoretical profile calculations (for example when , by using 'Matching', you want to subtract from the experimental pattern, a identified partial profile in order to explore comfortably the rest of compounds. .

[Home](#)



## Chapter 12. Additional files.


### XPowder.ini

It is a text file, which contains basic information about the initial configuration of the program. Can be modified through a text editor. Some data is updated from the XPowder program itself. The following example in green, it commented line by line (right in red).

```
[Xpowder]
SampleDir= .\samples
LoadFilterIndex= 2
5=Udf, etc.)
SaveFilterIndex = 1
DiagramPoreColor= &HFF00FF&
currentLd= Cu , 1.540598 , 1.54433 , 1.39217 , 0.5
lambda= Cr , 2.28970 , 2.29351 , 2.08480
lambda= Fe , 1.93604 , 1.93991 , 1.75653
lambda= Co , 1.78897 , 1.79278 , 1.62075
lambda= Ni , 1.65784 , 1.66169 , 1.50010
lambda= Cu , 1.5405981 , 1.54433 , 1.39217
lambda= Mo , 0.70930 , 0.713543 , 0.63225
lambda= Ag , 0.559363, 0.563775 , 0.49701
lambda= W , 0.208992, 0.213813 , 0.184363
lambda= Cu2 , 1.5405981 , 1.54433 , 1.39217
lambda= Dummy, 1.5405981 , 1.54433 , 1.39217
lambda= Synchrotron, 1.5406, 1.5406, 1.5406
kalphaFT= 1
hRoller= 1
vRoller= 5
interpolate= 2
2-theta_Tuner= 0.1
QUAntitative= True
Amorphous_Whole_RIR= 0.5541791
Monochromator_Constant= 1
rZoom= 50
iZoom= 50
peakSearchMinInt= 4
peakSearchSmoo = 0.2
SkipDuplicatePDF= False
[Initial PdfSubfiles]
Deleted pattern= True
Inorganic= False
Organics= False
Mineral= True
Metal= False
CP= False
NBS= False
FORensic= False
EDUCational= False
ZEOLite= False
EXPlosive= False
SCMaterial= False
CEment= False
CORrosive= False
POLYmer= False
DETergent= False
PIGment= False
PHArmaceutical= False
ICSD= False
Ceramics= False
[www]
XPowderSite= http://www.XPowder.com e_mail:support@xpowder.com
InstrumentalU-Width= 0.00003290
InstrumentalV-Width= -0.00003560
InstrumentalW-Width= 0.000001903
InstrumentalU_WidthIB= 0.000003714
InstrumentalV_WidthIB= -0.000003341
InstrumentalW_WidthIB= 0.000002228
Rem OldUValue= 0.000044

Head
Sample subdirectory in the directory program.
Specifies the initial sample file format (1=All, 2=PLV, 3=Raw, 3=RD, 4=X'Pert,
Output data format files. All values are not valid.
Background color of main diffractogram in hexadecimal.
Default anode: Element of anode,  $\lambda K\alpha 1$ ,  $\lambda K\alpha 2$ ,  $\lambda K\beta$ ,  $I K\alpha 2$  /  $I k\alpha 1$ 
Normalized  $\lambda$  values: Anode,  $\lambda K\alpha 1$ ,  $\lambda K\alpha 2$ ,  $\lambda K\beta$ 
Idem
Idem
Idem
Idem
Idem You can modify or add radiation
Idem
Idem
Idem
Idem
Idem for Synchrotron radiation (The three values must be equal).
Parameter used in the Fourier filtering. There should be no change
Horizontal initial value of 'roller' in  $2\theta^\circ$ , for background subtraction.
Idem vertical in % counts.
Initial number of points to be interpolated by spline.
maximum  $A2\theta^\circ$  for L.S. fitting in searching ( $0 < A2\theta^\circ < 0.4$ )
Establishing the capacity to make quantitative analysis based on RIR
Pseudo RIR global amorphous. Updates itself, according to the types of samples.
Monochromator constant
Number of horizontal points of the window Zoom
Idem vertical
Minimum initial intensities (%) in 'Searching'
Initial smoothing of maximum in 'Searching'
If True: 'Searching' shows the better solutions from equal phases
Next instructions are for PDF subfiles
If True, Deleted PDF patterns are included in 'Searching'
If True, 'Inorganic' PDF patterns are included in searching..
Idem 'Organic'
Idem 'Minerals'
Etc. Can be modified from running XPowder
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
Idem
URL and e_mail of Xpowder:
Current value (U) of the Caglioti for function instrumental FWHM
Current value (V) of the Caglioti for function instrumental FWHM
Current value (W) of the Caglioti for function instrumental FWHM
Current value (U) of the Caglioti for function instrumental Integral broadening
Current value (V) of the Caglioti for function instrumental Integral broadening
Current value (W) of the Caglioti for function instrumental Integral broadening
The lines that begin with REM are not read by the program.
```

## Std.txt

This file contains standard patterns and is used when you run the ' [Edit-> Set 2-theta offset](#)' or push  from the home screen in order to correcting instrumental 2θ misalignment. Each standard begins with the key '*Begin standard*', after the [chemical symbol for the element of used anode](#), the [name of the compound](#) and a list of 2θ and intensities in scale thousand (separated by commas). The end of each pattern is a row with the key [000.0000,000](#). The first of the patterns whose name is '*None*', lack of data and its presence is necessary, as in the following example:

---

Begin standard	058.0049, 0020	086.1906, 0100	138.3980, 0020	086.4996, 0040	075.5847, 0020
Lambda= Cu	060.6048, 0050	104.2542, 0030	000.0000, 0000	088.9972, 0080	077.5737, 0010
None	060.9139, 0040	118.8626, 0100		090.7050, 0021	079.7871, 0020
000.0000, 0000	061.2713, 0030	124.2775, 0100	Begin standard	091.1794, 0100	079.9552, 0010
	062.9841, 0020	150.8580, 0070	Lambda= Cu	094.8164, 0010	081.0554, 0030
Begin standard	064.6004, 0050	000.0000, 0000	Aluminum (Syn)	095.2357, 0190	081.3796, 0030
Lambda= Cu	065.5200, 0030		038.4720, 1000	098.3804, 0020	083.7256, 0010
Sodium Chloride (Halite syn)	069.1476, 0010	Begin standard	044.7380, 0471	101.0638, 0140	084.8748, 0010
	070.1536, 0020	Lambda= Cu	065.1333, 0219	102.8171, 0010	087.3647, 0010
027.3024, 0130	072.7817, 0020	Silicon(2)	078.2271, 0239	103.3008, 0031	090.7551, 0020
031.6547, 1000	073.6395, 0010		082.4352, 0071	104.6351, 0010	092.7170, 0010
045.3954, 0550	076.2077, 0010		028.4106, 1000	099.0783, 0021	109.5222, 0010
053.7887, 0020	077.0839, 0020		047.2499, 0550	112.0410, 0082	109.8503, 0010
056.4108, 0150	080.8346, 0010		056.0584, 0300	116.5600, 0080	110.8154, 0010
066.1488, 0060	081.4486, 0030		069.0537, 0060	137.4500, 0081	110.9755, 0040
072.9777, 0010	082.0136, 0010		076.2928, 0110	000.0000, 0000	114.0680, 0030
075.2129, 0110	083.6656, 0030		087.9290, 0120		116.0804, 0130
083.8708, 0070	084.6848, 0010		094.8431, 0060	Begin standard	116.6098, 0100
090.2991, 0010	086.3782, 0010		106.5978, 0030	Lambda= Cu	117.8378, 0080
101.0693, 0020	092.9588, 0010		113.9622, 0070	Corundum	000.0000, 0000
107.6764, 0010	094.5853, 0030		127.4020, 0080		000.0000, 0000
109.9103, 0030	094.8949, 0040		136.7419, 0030	035.1498, 0980	Begin standard
119.3563, 0040	096.0477, 0020		000.0000, 0000	037.7672, 0440	Lambda= Cu
127.0104, 0010	097.5282, 0010			041.6834, 0010	Quartz low (1)
129.7306, 0030	099.0396, 0020	Begin standard		043.3402, 1000	Begin standard
142.0569, 0020	102.1170, 0010	Lambda= Cu		046.1754, 0020	Lambda= Co
000.0000, 0000	102.8261, 0010	Calcium Fluoride (Fluorite Syn)		052.5480, 0480	Quartz - - (79-1906)
	103.7715, 0010			057.4981, 0960	036.5006, 0080
Begin standard	103.9963, 0030			059.7375, 0030	039.4111, 0080
Lambda= Cu	105.7159, 0020			061.1238, 0040	040.2379, 0040
Calcium carbonate (Calcite Syn)	106.0151, 0040			061.3031, 0090	042.4168, 0060
	107.2017, 0010			066.5144, 0380	045.7572, 0040
022.9948, 0120	109.4260, 0020			068.2018, 0570	050.0838, 0140
029.3704, 1000	110.3477, 0020			070.4114, 0011	050.5537, 0010
031.3808, 0030	000.0000, 0000			074.3001, 0010	054.8066, 0040
035.9231, 0140				075.7643, 0090	055.2655, 0020
039.3546, 0180	Begin standard			078.0951, 0010	057.1730, 0010
043.0940, 0180	Lambda= Cu			076.8727, 0017	Begin standard
047.0672, 0050	Silicon(1)			077.2342, 0010	Lambda= Co
047.4328, 0170				087.2734, 0170	
048.4552, 0170				094.1097, 0070	080.4151, 0012
056.4865, 0040				105.6840, 0040	063.9282, 0010
057.3326, 0080				112.9358, 0060	065.6859, 0010
				115.4390, 0010	083.2078, 0010
				126.0590, 0080	067.6728, 0060
				085.1346, 0010	068.0531, 0070
				086.3465, 0040	068.2451, 0080
					073.3786, 0020

---

Note: The last two standard patterns have been created in the example from the Xpowder program itself from PDF2 records, for tubes with anode of cobalt. This involves first obtaining the different 2θ angles of the respective reflections, using the formula with the value of Bragg wavelength described in the database information. Subsequently, these values are normalized to the exact wavelength, for the same anode defined in the XPowder.ini file (eg [currentLd = Cu, 1.540598, 1.54433, 1.39217, 0.5](#)).

There are commercial programs that do not perform this normalization of λ and can cause during the operation of correcting, 2θ zero shift higher than the value that is tried to correct. In any case, what is more correct to directly enter the values of 2θ angles and intensities, observed directly on experimental patterns obtained in well aligned diffractometers.

### Favorites.txt

This file is used rarely, but it remains by compatibility with very primitive versions of the program. They have fixed text format and aims to quickly find specific records of databases through names, nickname or improperly written words. Each line contains the file (2 digits), a space, the number of the card (file, 4 digits), a space and all the familiar names or aliases in any language.

```
12 1234 set=two digits    file=four digits
## #### key words
33 1161 Cuarzo Quartz
  5  586 Calcita Calcite Calcium carbonate
36  426 Dolomita Dolomite
41 1475 Aragonito aragonite
33  268 Vaterita Vaterite Baterita
  5  593 Celestina Celestine
29  696 Siderita siderite
35  496 Fluorapatito Fapatito
  9  432 Hidroxiapatito Hapatito
  5  628 Halita sal gema sal comun halite
  6  263 Moscovita Muscovite
33  664 Hematites ocre
17  541 Weddellyte Weddelita Wedelita Wedellita
33  311 Yeso Gypsum
```

### SoISol.txt

It is a text file containing the final stages of isomorphic series that can be used to interpolate chemical compositions. Data from each phase are written on successive lines:

**Phase name, eje a, eje b eje c,  $\alpha$ ,  $\beta$ ,  $\gamma$**

```
Calcite          15.139
4.9963           90
4.9963           90
17.1092         120
90              Forsterite
90              4.752
120             10.192
Dolomite        5.978
4.808           90
4.808           90
16.055         90
90              Fayalite
90              4.815
120             10.4597
Magnesite       6.0818
4.646           90
4.646           90
```

## Default.cnf

It contains the initial communication parameters and configuration of Philips PW1710/00/12 devices. It is only necessary in the PLUS version.

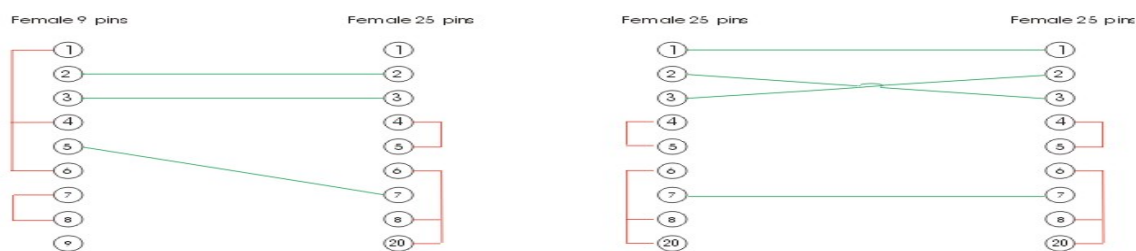
```
[PW1712]
[Diffraction communication port]
CommPort = 1
BaudRate = 9600
DataBits = 8
StopBits = 1
Parity = N
[Scan parameters]
ScanMode = CONTINUOUS
StartAngle = 3
EndAngle = 80
StepScan(2 - theta°) = .040
IntegrationTime(sec) = 0.4
ScanRate(2 - theta° / sec) = 0.1
Batch_mode= 0
[Pulse height analyzer]
LowerLevel = 35
UpperLevel = 70
[Diffraction setting]
Monochromator= Graphite 2°
Filter= None
Slit_1 = AUTOMATIC
ReceivingSlit = 1/0.1/1
AutomaticSamplerChanger = PW 1775
Rem PW 1775,No, ...
Spinner= PW 1774
Rem PW 1774, No
ThermoController = Comm3:9600,N,8,1
Rem False / Comm3:9600,N,8,1
MaxTemperatureCentigrade= 250
GraphicRecorder = PW 8203A
Rem PW 8203A, PW 8203, NO
SingleGobelMirror = NO
GeneratorVoltage(Kv) = 40.00
TubeCurrent(mA) = 40.00
Stand_by_2theta = 5.00
DiffractionSite= <<To be personalized>>
[Profiles]
01 Profile 026.00 003.00
02 Profile 035.00 003.00
03 Profile 044.00 003.00
04 Profile 000.00 000.00
05 Profile 000.00 000.00
06 Profile 000.00 000.00
07 Profile 000.00 000.00
08 Profile 000.00 000.00
09 Profile 000.00 000.00
10 Profile 000.00 000.00
11 Profile 000.00 000.00
12 Profile 000.00 000.00
```

Other specific '\*.cnf' files can be created for particular applications, through editing 'default.cnf', or using the 'File-> Save Setup file', in the acquisition diffractograms module. Also it can be used 'Load Setup file' in same module.

[Home](#)

## Chapter 13. Data collection from the diffractometer.

This option is available in the version **XPowder PLUS** for the PW 1700/10 diffractometers through a PW1712 serial dual interface.



13.1

Figura

The figure 13.1 shows two examples of null-modem cables to link directly the PC (9 or 25 female pins connector) to the diffractometer (25 female pins connector). This cables are rather different to the original, and the diffractometer connector should be in the 25 pins male position 1 of the PW1712 connector (This position is the I/O channel. Position 2 is output only). Remove also the null-modem box which is delivered with the PW1712 (a 12x4x2 cm approximately black box).

To acquire a diffractogram click **File> Acquire** or the  button. The order **File> New** is executed at the same time. The following 13.2 screen appears:

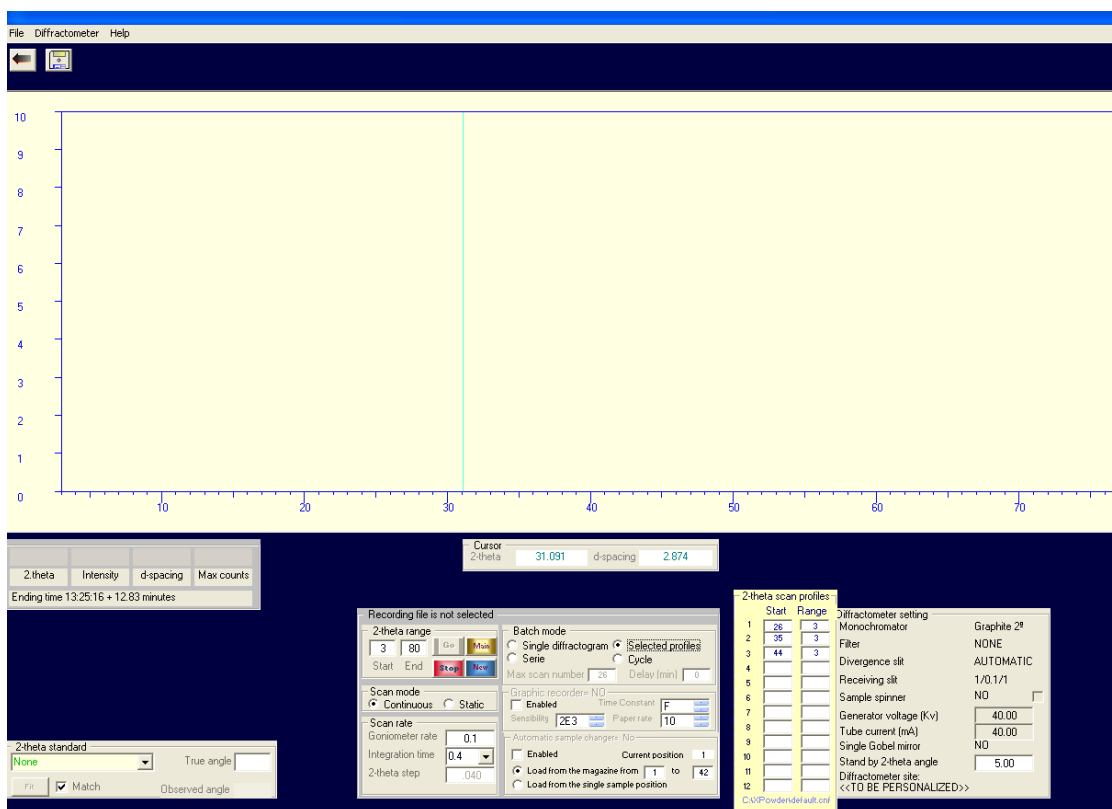
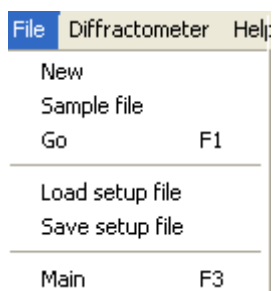



Figura 13.2.

## The File menu




**New.** It allows to begin a new data collection from the diffractometer. It is equal to the **New** button.

**Sample file.** It allows to select a file where the diffractogram will be saved. The format of the data is the same as the one that is shown in the example. It is equivalent to press the  button.

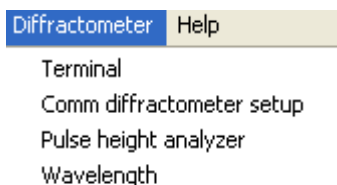
**Go.** The data collection begins under the conditions that have been set up in the rest of the screen (Start angle, final angle, etc). It is equivalent to the **Go** button.

**Load setup file.** It loads a configuration file with the **CNF** extension. When accessed to this screen the configuration file loaded by default is **DEFAULT.CNF**. This order is reserved to configure the data collection in agreement with a model (start angle, exploration type, goniometer speed, final angle, etc.) which is used for a certain purpose (identification of mixtures, unit-cell refinement, OA, etc.). These configurations are defined by the user.

**Save setup file.** A configuration defined by the user is saved with the **CNF** extension (it carries out the inverse operation to the previous point).

**Main.** **XPowder** returns to the main screen. It is equivalent to the  or **Main** button.

## The Diffractometer Menu



**Terminal.** It shows a small screen to can dialogue with the diffractometer. It is equivalent to the keyboard and screen at the diffractometer control panel, but as remote terminal. The commands are sent by **Command** window and the answers of the diffractometer appear in **Response** window. The **History** window contains the whole conversation. **Tuning** button can be used to obtain a graphic of static measures of intensity at the current  $2\theta$  angle in instrumental setting processes.



The keyboard **return** moves the position. **Response** shows the example **C =**).

$2\theta$  angle of the diffractometer to the beginning symbol of the diffractometer system (for

The **Quit** button closes the remote terminal.

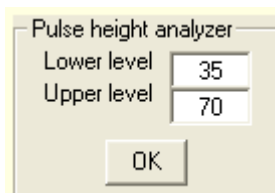
**Comm diffractometer setup.** It establishes the communication parameters between **XPowder** and the diffractometer. These parameters have to be established in the communication plate of the diffractometer by leaving the microswitches in the appropriate position (see the technical manual of the communication plate) and they should be the same in both the diffractometer and the computer. In case of problems try to modify the parameters of **XPowder** until they match those of the diffractometer. Frequent combinations are:

9600, N, 8,1  
4800, N, 8,1  
9600, N,7, 2  
etc.,

The port of the computer is usually *Com1* or *Com2*.

Once the communication is established (it can be proved with **Terminal**) save this configuration (**Save setup file**). It can be edited latter with a text editor (*Note Pad* for example) with the name **DEFAULT.CNF**.

**Pulse height analyzer.** It establishes the minimum and maximum levels of the pulse height of the discriminator diffractometer counter. These parameters should be adjusted previously in the diffractometer (consult the technical manual).



**Wavelength.** It allows to select the wavelength or the X-ray tube installed in the diffractometer.

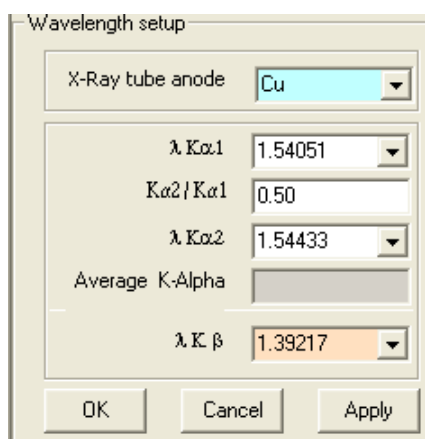


Figura 13.3

## Setting the experimental conditions

### Recording mode

There are two modes of data collection. The first one moves the  $2\theta$  angle of the diffractometer at **continuous** speed and the counts are accumulated by the counter at certain intervals (**integration mode**).

Scan mode  
 Continuous  Static

Scan rate  
Goniometer rate: 0.1  
Integration time: 0.4  
2-theta step: 0.04

Scan mode  
 Continuous  Static

Scan rate  
Goniometer rate: 0.1  
Integration time: 0.4  
2-theta step: .040

The second mode consists of measuring statically during a certain time in a fixed  $2\theta$  angle while the counts are accumulated. This operation is repeated at the next  $2\theta$  angle and so on until arriving to the final  $2\theta$  angle (**static mode**). Naturally both recorded modes are carried out in automatic mode.

The first one produces softened profiles, but also a small deformation and stretching in the peaks. The second one is more accurate and it doesn't deform the profiles, but it produces more random noise.

The first mode can be improved by diminishing the exploration speed. The second mode can be improved by increasing the integration time.

To select the **integration mode**, press the **Continuous** option button. To select the **static mode** press the **Static** button. **Goniometer rate** box marks the angular speed of the goniometer. **Integration time** box marks the time during which the counter accumulates counts and **2-theta step** box marks the increment of  $2\theta$  angle between two successive measurements. Only the boxes that can be modified are actives.

**Exploration interval.** The initial  $2\theta$  angle is entered in the **Start** box and the final  $2\theta$  angle in the **End** box. The starting time and the recording time appear in the text box:

Ending time 19:14:05 + 12.83 minutes

2-theta range  
3 80 Go Main  
Start End Stop New

**Diffractogram capture.** Press the **Go** button when the experimental conditions have been set up. The diffractogram capture can be stopped at any moment (**Stop** button). A continuous re-scale of the intensities axis as a function of the maximum of counts is done during the data collection.

**Data format.** The diffractogram data are codified in ASCII text. The experimental conditions are set up in the first fifty lines. The first line is a heading with free format, consist of a key word(s) (*Step size* = for example) and an argument (0.040 in this same example). Empty lines can be numbered to identify their position (line 41 for example) and the line 50 is "*Data*" to indicate that next lines corresponds to experimental measurements. Data are written in two columns separated by one or more spaces. This format guarantees that the data can be interpreted by any user and read or imported by any program in any operating system. Lines begin with *Line* keyword are ignored.



Example:

XPowder diffraction software. PLV file format Ver. 3.0

Sample= AFRICA.PLV

Site= Universidad de Granada (Spain)

User= Crista-Mine-Gr

Date= 28/10/2003

Time= 13:06:15

Start 2-theta scan= 10.000

End 2-theta scan= 80.000

Step size= 0.040

Scan mode= Continuos

Integration time(sec)= 0.4

Anode= Cu

Filter= NO

Monochromator= Graphite 2 $\theta$

K-Alpha 1= 1.54051

K-Alpha 2= 1.54433

Ka2/Kal Ratio= 0.5

K-Beta= 1.39217

Automatic sampler changer= NO

Single Gobel mirror= NO

Divergence slit= AUTOMATIC

Receiving slit= 1/0.1/1

Generator voltage(Kv)= 40.00

Tube current(mA)= 40.00

Maximum counts= 10

Line 26

Line 27

Line 28

Line 29

Line 30

Line 31

Line 32

Line 33

Line 34

Line 35

Line 36

Line 37

Line 38

Line 39

Line 40

Line 41

Line 42

Line 43

Line 44

Line 45

Line 46

Line 47

Line 48

Line 49

Data

10.000 4

10.040 5

10.080 10

10.120 8

10.160 7

10.200 5

10.240 10

10.280 9

10.320 10

10.360 11

10.400 6

10.440 11

10.480 7

10.520 6

10.560 9

...

...

...

**Setting the 2θ angle zero mark.** It can be carried out automatically by recording the diffractogram of a well-known standard (for example, silicon) or with an internal standard. **XPowder** allows to use the list of the *std.txt* file for this purpose. The following procedure should be performed:.

1. Select the standard from the list as shown in the image.
2. Record the diffractogram.
3. With the **left** button click on the symmetry line (or on the maximum) of a well-known pick from the diffractogram.
4. With the **Alt + left** mouse button click near the position of the standard line to which the maximum must be adjusted. The true 2θ angle can be input manually in the **True angle** box. If this is the case step 1 it is not necessary.
5. Press the **Fit** button and then the diffractometer corrects the zero offset automatically.

To observe the quality of the adjustment, mark the **Match** check box before pressing **Fit**. Then, the diffractometer measures automatically the standard again.

**Recording strategy.** When selecting the **Single diffractogram** option button, the files of each recording should be named one by one. With this option, a file name should be selected before recording each run in order to save the recorded data Figure 13.4.

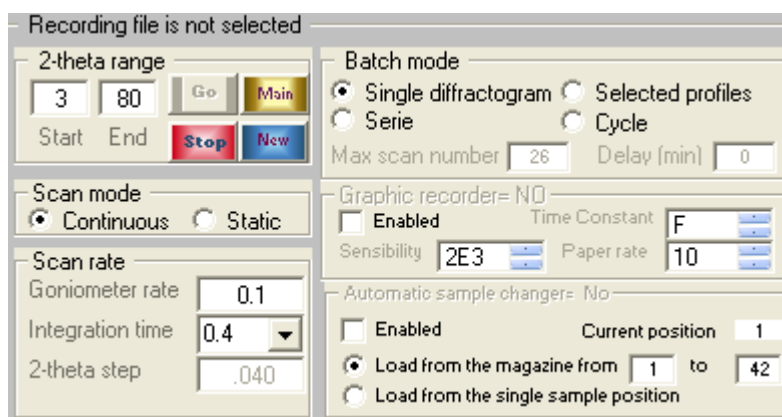


Figura 13.4

If the option **Serie** is selected, the samples are named by adding an order number to the original file name. For example, if the name is *example* the program will output the files *example\_001.plv*, *example\_002.plv*, etc. It is necessary to press **Go** between successive diffractograms.

If the **Cycle** option is selected, the number of recordings selected in the box **Max scan number** will be carried out automatically (10 in the example) with the *time delay* input in the **Delay (minutes)** box (30 minutes in the example). The name of each file follows the same rules as in **Serie**. This mode is used to study changes of phases, hydration grade, crystallinity, etc. It is also used coupled to changes in temperature. The maximum number of diffractograms is 999 and the delay time between diagrams can be set to zero (without wait) or as long as desired (always in minutes).

If **Selected profiles** is checked, we can select individual reflections in order to be sequentially scanned (figure 13.2, **2-theta scan profiles**).

It can be selected also:

- **Automatic sample changer:** Include in 'Default.cnf' the line

```
AutomaticSamplerChanger = PW 1775  
or  
AutomaticSamplerChanger = PW 1775
```

- Spinner: Include in 'Default.cnf' the line

```
Spinner= PW 1774  
or  
Spinner PW 1774
```

- Graphic recorder: Include in 'Default.cnf' the line:

```
GraphicRecorder = PW 8203A  
or  
GraphicRecorder = PW 82030
```

[Home](#)



## Updates

Version 2004.04.49. (11-05<sup>th</sup>-2008)

1. Starting with this release of the program, the searching do not necessarily uses the full diffractogram, as explained in Chapter 2, but is restricted to the selected  $2\theta$  interval. This allows you to search unique reflections on isolated so comfortable.

For example, a residual reflection, which on a previous search has not been assigned to any component, can be selected to complete the list of identified phased. The modification of the program is useful in samples with minority components or or poor crystallization.

2. It has removed the check box **Force subtraction** in the tool 'Matching', Chapter 5, which now stays as in Figure A.1.

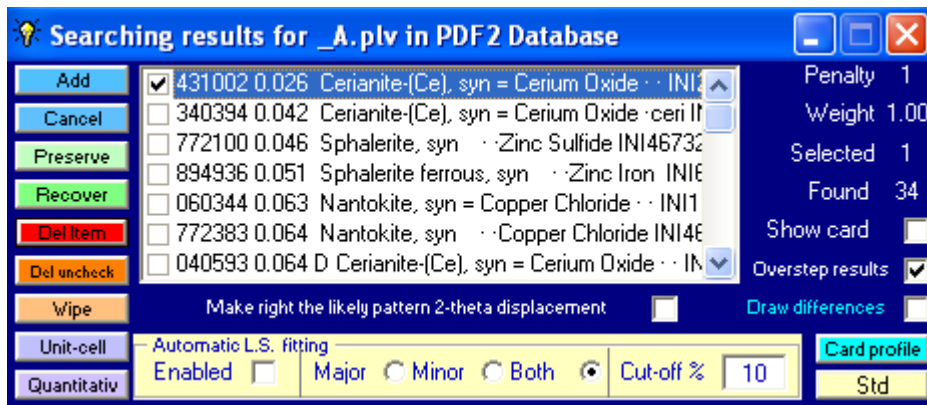


Figure A.1.

Now, the subtraction component option appears as in Figure A.2, after it has calculated the pattern record with the order **Card profile**.

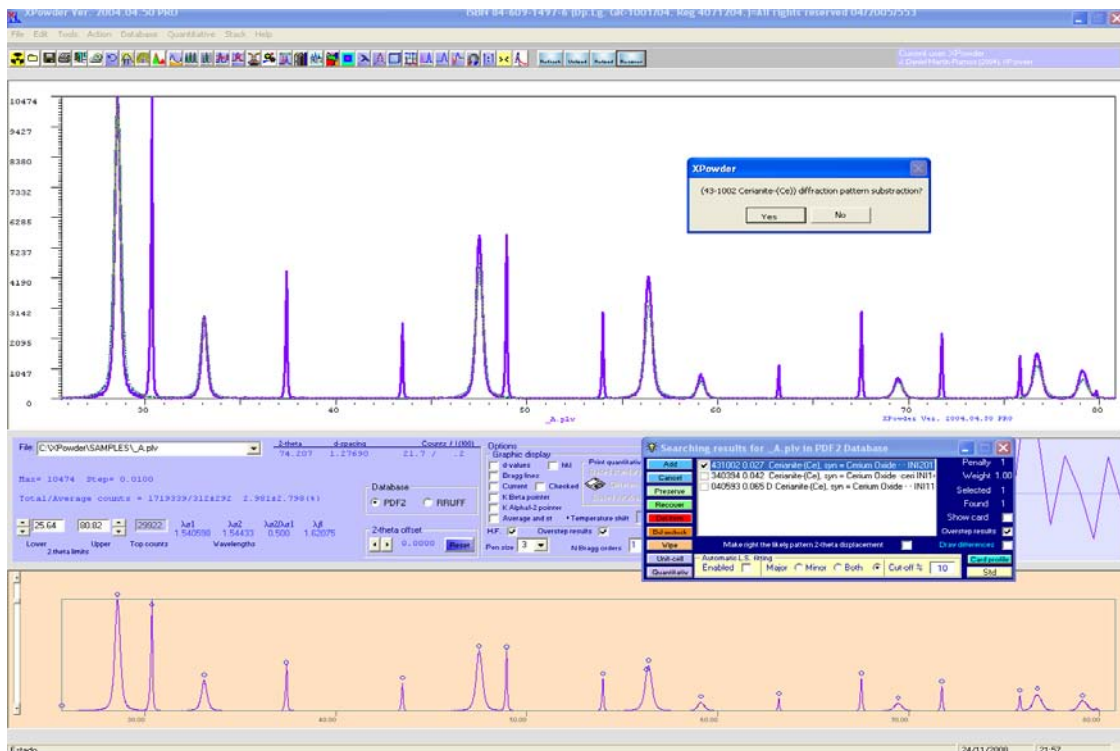


Figure A.2

Version 2004.04.50. (11-10<sup>th</sup>-2008).

File extensions '.asc' and '.xy', in addition to the classic ".txt" for text file formats (XY), which already existed in the early versions of XPowder, have been included again.

Versions 2004.04.53. (01-08<sup>th</sup>-2009) and 2004.04.54 (01-14<sup>th</sup>-2009)

Many researchers record their diffractograms in limited angular intervals (eg explore  $2\theta$  between  $5^\circ$  and  $45^\circ$ ). It is common for example in studies of the clay minerals or when used portable diffractometers without mobile components. However databases (PDF and AMSCD) contain information on crystalline phases patterns registered outside the limits explored in laboratories. Thus, some records contain only d-spacing greatest 3.00 Angstroms while others (especially the most modern) contain information that goes lesser to 0.7 Angstroms.

In order to optimize the search conditions of crystalline phases, users can now instruct the program so that unused  $2\theta$  zones are excluded from the databases. This can be done at the time of the option to install [Database Install](#) or [Update XPowder](#) in XPowder homepage. The searchings are made with much greater speed and safety because only the ranges of records that best matching in the respective laboratories are used for adjustments.

The values for angle interval of database can be entered in boxes [Higher d-spacing](#) and [Lower d-spacing](#) in Figure A-3.

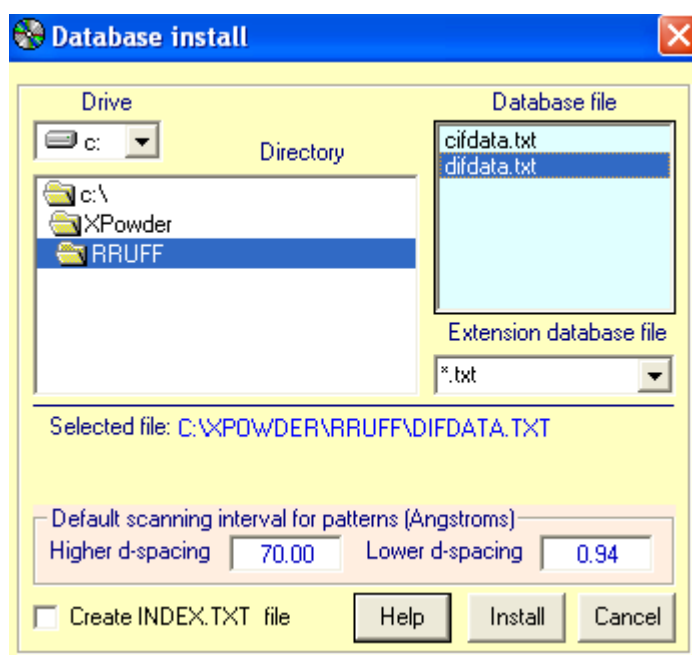


Figure A-3. The program will exclude d-spacing lesser than 0.94 Angstroms and greater than 70 Angstroms during the installation of the database AMSCD.

Angular areas excluded from the database appear in the framework [Database](#) and are drawn with a gray background in [Advance searching](#) tool (Figure A-4).

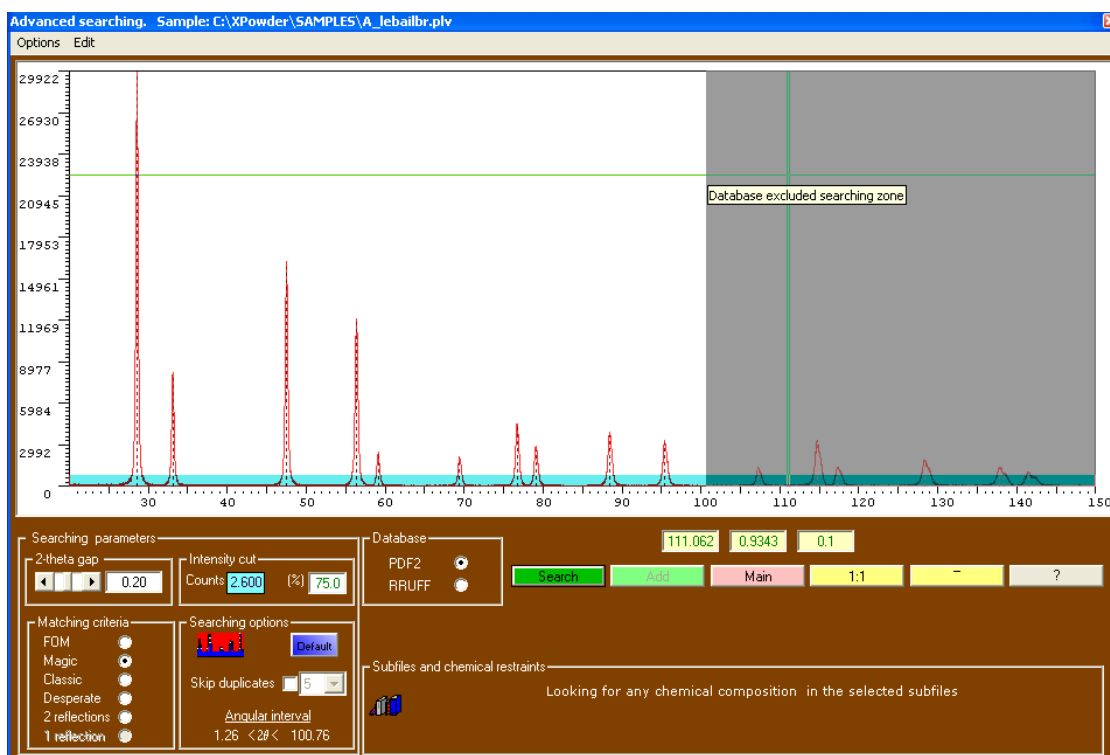
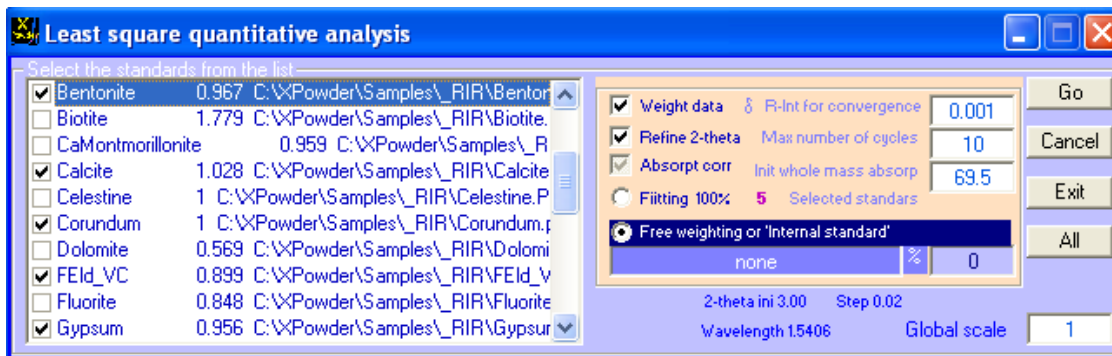


Figure A-4. During the searching, the program does not take into account the d-spacing of the database for higher values of  $2\theta = 110.06^\circ$  (grey zone). In general, this area is not used for identification of crystalline phases. To use it, would have to reinstall the database with value 'Lower d-spacing' of 0797 Angstroms, which corresponds to approximately  $150^\circ$  for radiation  $\text{CuK}_{\alpha 1}$ .

Since version 2004.04.54 has been including in [Matching criteria](#) frame, a new approach [2 reflections](#) that uses only two of the diffractogram reflections to matching with the high intensity reflections of database records. When this option is used, the number of possible solutions is high in general, due to the lack of information used in the calculations. It is therefore appropriate to provide supplementary information to the program (about chemical composition, for example ). This approach should be used in diffractograms having small scanning intervals (eg  $2 < 2\theta < 50$ ), or to identify minority phases. Also, from version 2004.04.54, the second searching options of 'Desperate' has been renamed to '1 reflection', because it uses in searching only one reflection.

To find the database records that match a single reflection of experimental pattern, this reflection should be exclusively selected by the zoom and then click [Search](#) or [Add](#). The searching option '1 reflection' will be changed by the program itself and then it carries out the automatic searching.

1. The new tool **Matching** is more powerful ([Chapter 5](#)).



**Figure A.5.** This tool replaces the one described in [A.1](#)

2. More choices and better options for quantitative analysis with experimental standards ([Chapter 7](#) and PTT)

**Quantitative batch mode analysis**

Sample	*	Aragonite	Calcite	Celestine	Dolomite	Rho (g.cm-3)	Mu	Rint	Cycles	Sigma
F5. PLV	*	22.0(0.2)	30.9(0.2)	06.0(0.2)	41.1(0.2)	2.904(0.021)	61.636	0.00439	02	0.00064
F4. PLV	*	27.6(0.3)	21.5(0.4)	41.0(0.3)	10.0(0.5)	3.308(0.047)	71.981	0.00604	03	0.00068
F3. PLV	*	14.3(0.2)	53.8(0.2)	13.2(0.2)	18.6(0.2)	2.942(0.021)	67.675	0.00369	03	0.00061
F2. PLV	*	15.6(0.2)	33.6(0.2)	32.8(0.2)	18.0(0.3)	3.191(0.028)	69.385	0.00467	03	0.00060
F1. PLV	*	19.5(0.2)	40.0(0.2)	19.8(0.2)	20.7(0.2)	3.040(0.025)	67.682	0.00499	03	0.00064

Sum fitted 100%. The percentages have been calculated weighing data. 2-theta angles have been refined. END

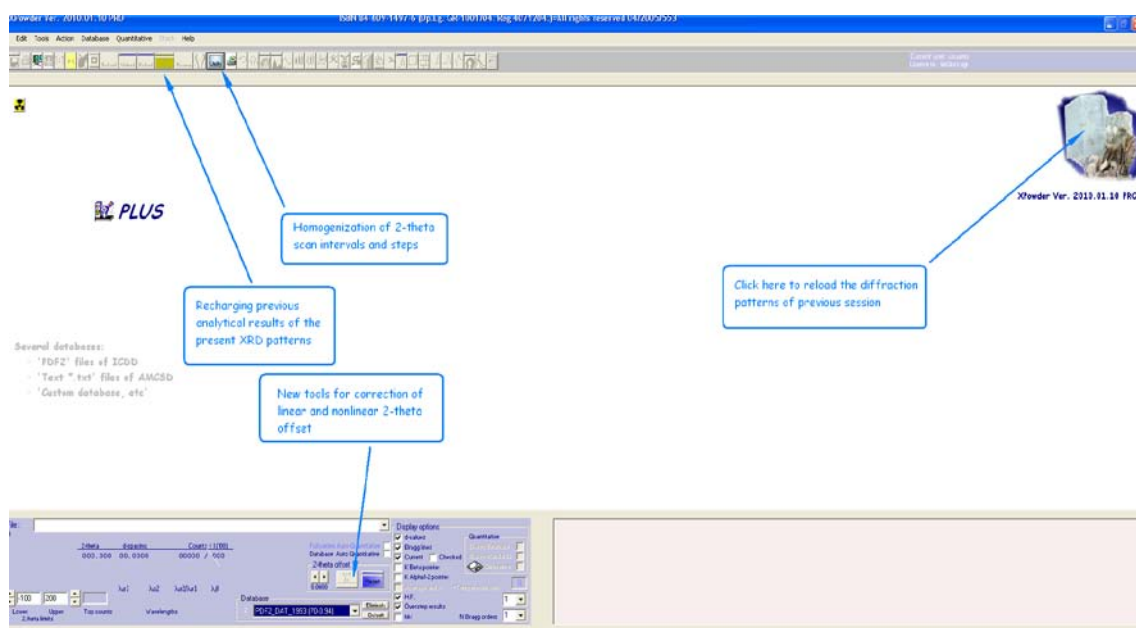
3. Three new data formats are recognized directly by X Powder:

- The ascii dataformat **'\*.X\_Y'** of the diffractogram file output of PowderCell programs of [W. Kraus & G. Nolze \(2000\)](#). *Federal Institute for Materials Research and Testing. Rudower Chaussee 5, 12489 Berlin, German*).
- Sietronic **'\*.cpi'** format.
- **'\*.nja'** de Seifer.

[Index](#)



## XPowder 2010.01.10. New features. (May, 2<sup>th</sup> 2011)

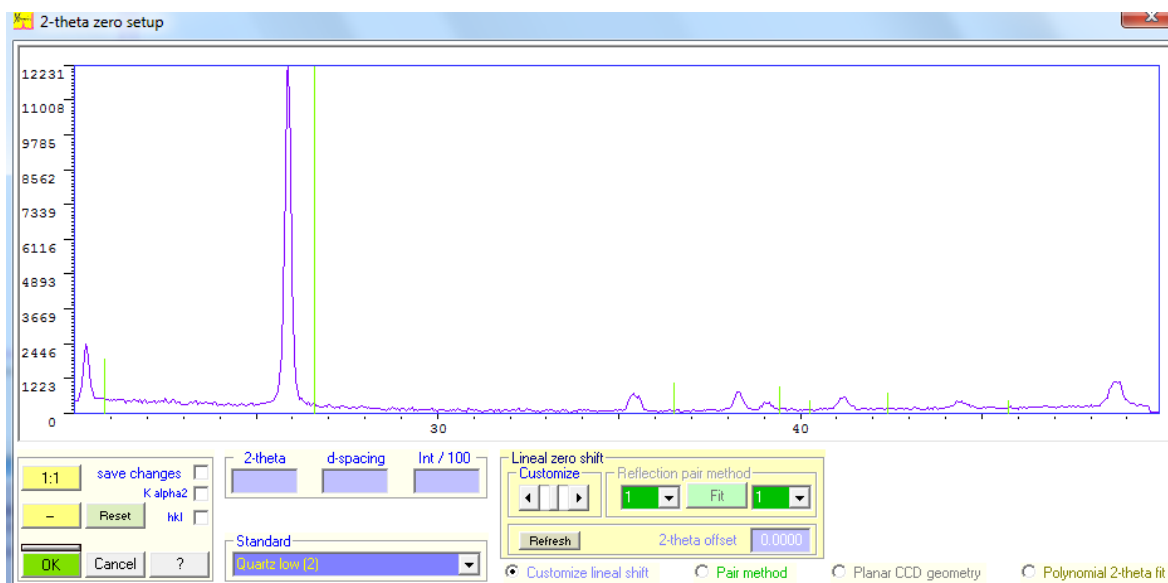


1. Reloading of previous session patterns. Clicking on the picture of the mineral (beryl) of the home screen, reloads all diffractograms of the last working session, but calculations are excluded (searching-match, quantitative, etc. ).

2. Reloading of previous analytical results... Retrieves the previous analysis (historic) carried out on those XRD patterns that are currently in XPowder memory (searching-match, quantitative, etc. ). Like other parts of this program, the large button retrieves data from the active sample, while the top bar performs the same action on all loaded XRD patterns.

3. Homogenization of 2 $\theta$  scan intervals and steps. Standardizes 2 $\theta$  angles (initial, final and steps) for all those XRD patterns loaded. This action is performed even if the initial data formats are quite different. The order is also available in **2D** and **3D** stacking windows. The range is homogenized using the higher initial 2 $\theta$  values, the smaller final 2 $\theta$  values and the minor 2 $\theta$  interval. When some diffractogramme has the scan step variable, data are converted into constant step (histograms). Occasionally, when the initial data are too heterogeneous, this command may need to be run twice.

4. [Linear and nonlinear 2θ zero shift](#). By clicking button , four options are availables:



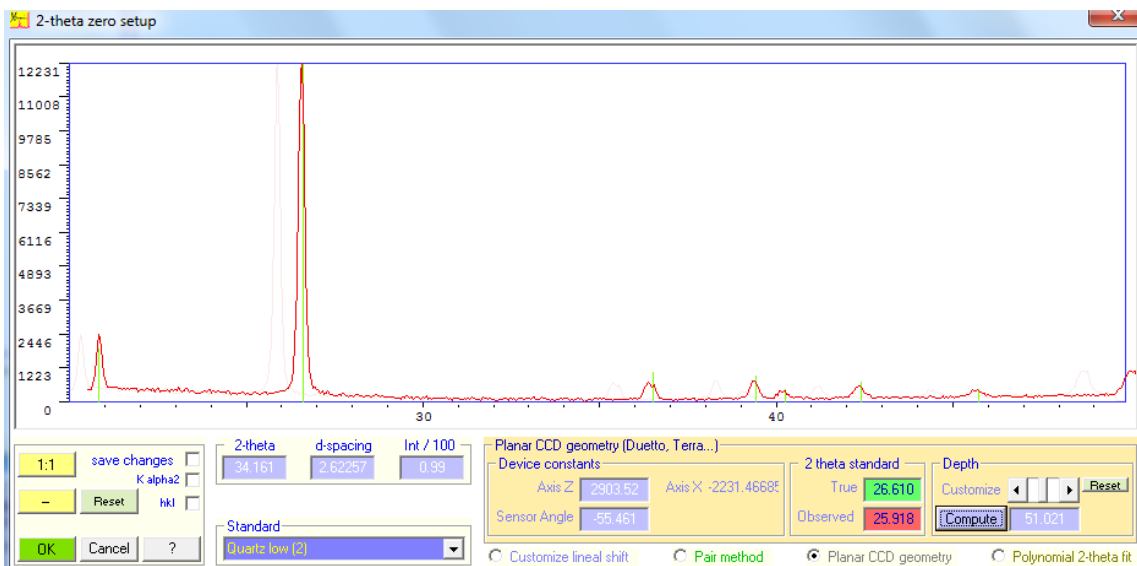
- [4.1. Customize lineal shift \(See Chapter 3\)](#)
- [4.2. Pair method \(See Chapter 3\)](#)
- [4.3. Planar CCD geometry](#)
- [4.4. Polynomial 2θ fit](#)

- 4.3. [Planar CCD geometry](#): This nonlinear correction is used with flat detector diffractometers where the sample position can not be fitted accurately. Requires knowing the approximate distance between the sensor and the sample, and the angle between sensor and X-ray beam. Can be used either one reflection standard ([True](#) and [Observed](#) boxes and [Compute](#)) or the [Customize](#) cursor to move the diffractogram to the correct position

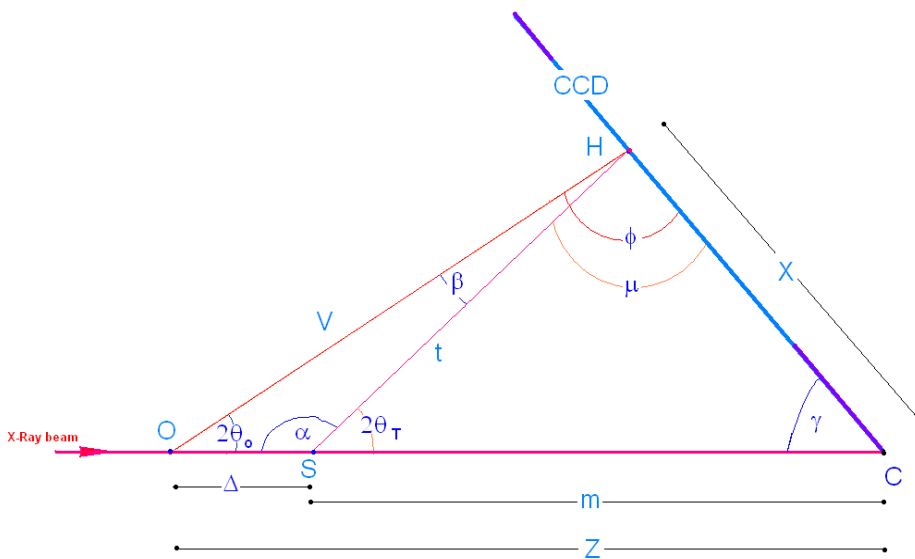
Prior to correction:



After correction:



Planar CCD geometry correction details:



- O = Diffractometer centre (ideal sample position)
- S= real sample position
- $\gamma = 90^\circ$  - Sensorangle
- Z= Axis Z length. Distance between O and CCD along primary X-Ray beam
- X = Coordinate along Axis X
- $\Delta$  = Displacement of diffractometer center ("Depth")
- $2\theta_0$  = Observed (measured)  $2\theta$
- $2\theta_T$  = True  $2\theta$ .

**$2\theta$  correction in function of 'depth' X-Ray penetration (= sample offset along primary X-Ray direction)**

$\Delta$  is a know or estimated data

In OHC triangle, by using sine theorem:

$$\sin 2\theta_0 / X = \sin \gamma / V = \sin \phi / Z \quad \gamma = 90^\circ \text{ - Sensorangle}$$

$$V = X \cdot \sin \gamma / \sin 2\theta_0 \quad [1]$$

$$X = Z \cdot \sin 2\theta_0 / \sin \phi \quad \phi = \pi - \gamma - 2\theta_0$$

$$X = Z \cdot \sin 2\theta_0 / \sin (\pi - \gamma - 2\theta_0) \quad [2]$$

In OHS triangle, by cosine theorem:

$$t^2 = \Delta^2 + V^2 - 2 \Delta V \cdot \cos 2\theta_0 \quad [3]$$

And by sine theorem :

$$\sin \alpha / V = \sin 2\theta_0 / t \quad \sin \alpha = \sin(\pi - 2\theta_T) = \sin 2\theta_T$$

$$\sin 2\theta_T = V/t \cdot \sin 2\theta_0 \quad [4]$$

By replacing V [1] and t [3] in [4]

$$\sin 2\theta_T = (X \cdot \sin \gamma) / (\Delta^2 + V^2 - 2 \Delta V \cdot \cos 2\theta_0)^{1/2}$$

Where V and X are calculated by [1] and [2]

$\Delta$  is the sample offset along primary X-Ray beam direction in equal units of axis Z.

This formula let to correct the deformation of  $2\theta$  scale of any diffractogram obtained from CCD.  $\Delta$  can be estimated from a reflection standard (see next page) or by a cursor changing  $\Delta$  value while the new diffraction pattern is matched.

Calculation of 'depth' X-Ray penetration (= sample offset along primary X-Ray direction) from a standard reflection

$2\theta_T - 2\theta_o$  are know data

In OHS triangle, by sine theorem:

$$\begin{aligned} \sin \alpha / V &= \sin 2\theta_o / t = \sin \beta / \Delta & [6] \\ \beta &= \pi - \alpha - 2\theta_o = \pi - (\pi - 2\theta_T) - 2\theta_o = 2\theta_T - 2\theta_o \end{aligned}$$

On the other hand:

$$\sin \alpha = \sin 2\theta_T$$

[6 ] can be rewritten:

$$\sin 2\theta_T / V = \sin 2\theta_o / t = \sin (2\theta_T - 2\theta_o) / \Delta$$

Turn out  $\Delta$ :

$$\Delta = [V \cdot \sin (2\theta_T - 2\theta_o)] / \sin 2\theta_T \quad [7]$$

Where:

$$V = X \cdot \sin \gamma / \sin 2\theta_o \quad [1]$$

$$X = Z \cdot \sin 2\theta_o / \sin(\pi - \gamma - 2\theta_o) \quad [2]$$

$$\gamma = (90^\circ - \text{SensorAngle}^\circ)$$

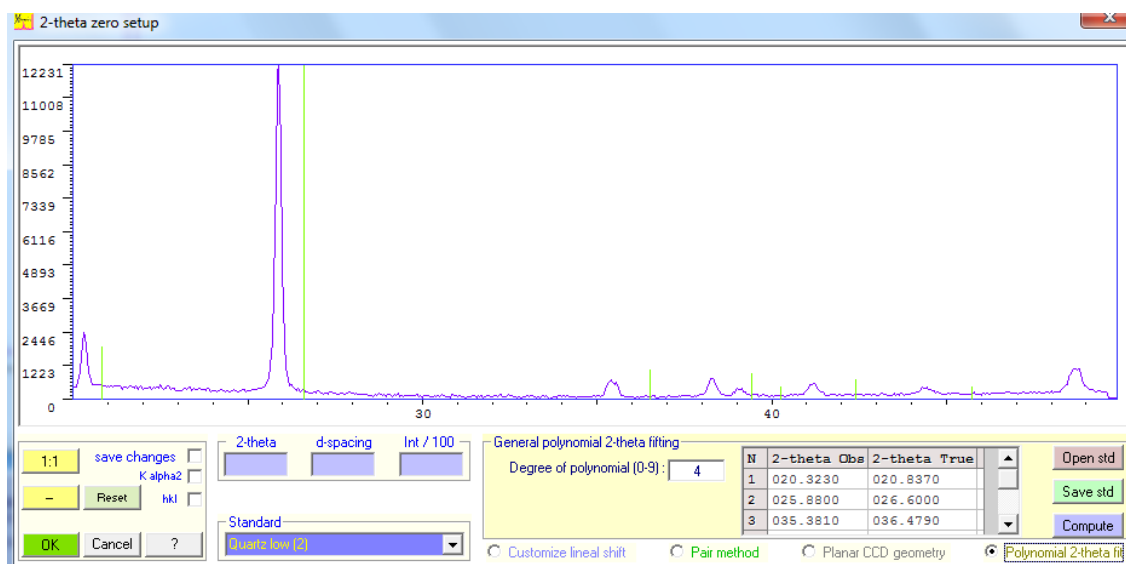
Z = axisZ (distance from ideal simple position to CCD along X-Ray beam direction)

Then:

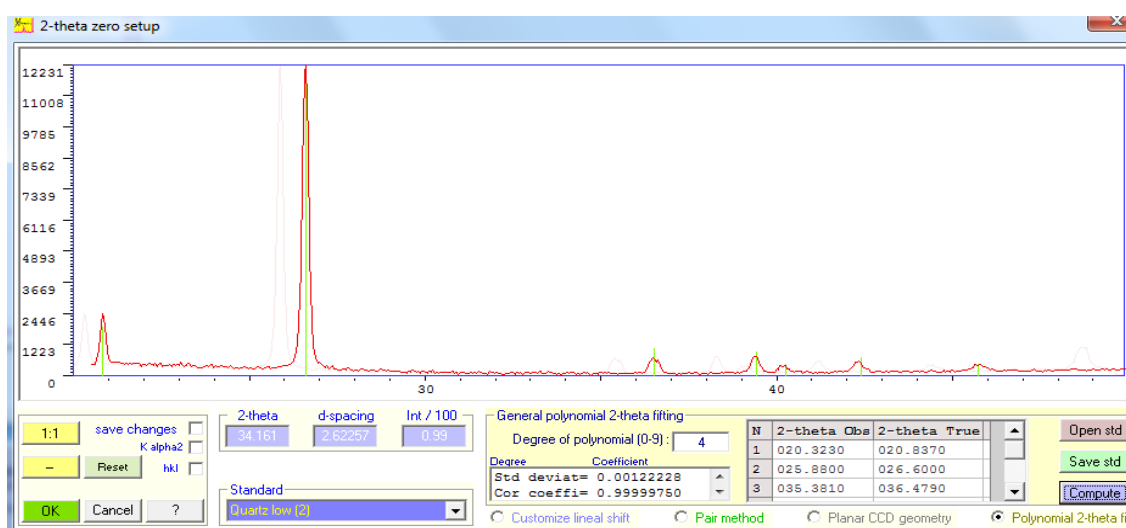
$$\Delta = [Z \cdot \sin \gamma \cdot \sin (2\theta_T - 2\theta_o)] / [\sin (\pi - 2\theta_o - \gamma) \cdot \sin 2\theta_T ]$$

- 4.4. **Polynomial 2θ fit.** This algorithm has general character and allows any non-linear adjustment of the angle by using a standard sample and a polynomial of degree up to 9 maximum. This method can be used instead of 4.3, but requires an examination of reflections of the entire 2θ angular scanned range.

Prior to correction:



After correction:



The observed and expected data they can direct entry into the table, or can be placed in an archive with '.T\_O' extension, created with a text editor (use **Open std** and **Save std**):


Example of '.T\_O' archive:



```
Head (any)
20.323 20.800
25.880 26.600
35.415 36.510
38.331 39.390
39.120 39.420
41.178 42.410
44.334 45.700
```

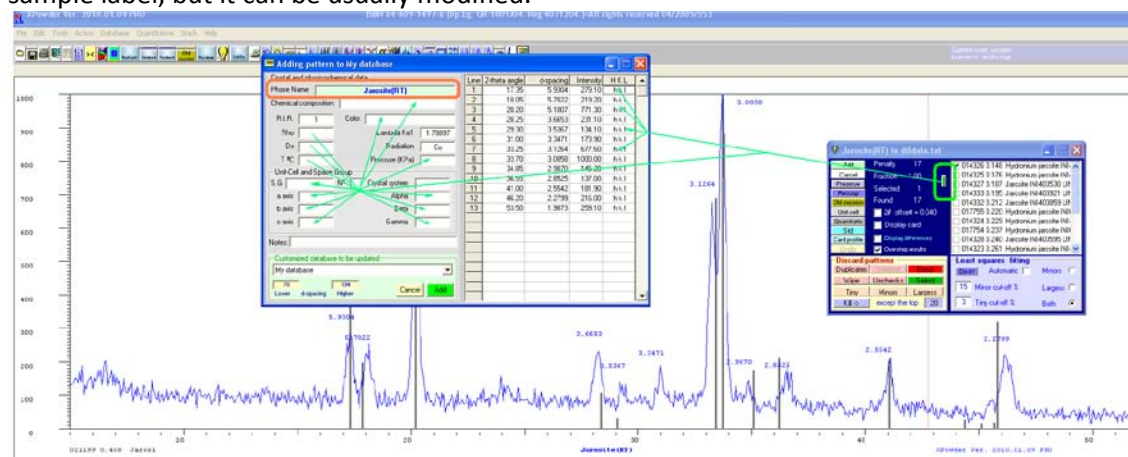
**5. Customized databases.** An unrestricted number of custom databases can be used. The generated files have the extension MYD and they can be installed at any time on various computers, just like any other database. The procedure to build and to maintain a custom database is:



5.1. Load an experimental pattern and optionally make the identification of the crystalline phases.

5.2. Click button  of the tool 'Results' in order to add the current card from an existing database to a custom database.

5.3. Alternately, select the reflections of crystalline phase of experimental diffractogram by clicking on pattern reflections. Then, push on button  of main menu to add the experimental current Bragg's reflections as further card into an existing database. Optionally, you can export crystallographic data (unit cell, hkl, etc) from previous database  or write directly into text boxes. The default phase name is the sample label, but it can be usually modified.



5.4. Select the destination customized database (a preexisting or a starting custom database).

**Adding pattern to Portland (70 to 1.94)**

Crystal and physicochemical data

Phase Name: **Jarosite\_RioTinto**

Chemical composition: **K Fe3 S2 O14 H6**

R.I.R.: **1.000** Color: **white yellow**

Rho:  Lambda Ka1: **1.78897**

Dx: **1** Radiation: **Co**

T °C: **25.0** Pressure (KPa): **100**

Unit-Cell and Space Group

S.G.: **R-3m** N<sup>#</sup>: **0** Crystal system: **Hexagonal**

a axis: **7.304** Alpha: **90**

b axis: **7.304** Beta: **90**

c axis: **17.268** Gamma: **120**

Notes:

Customized database to be updated

Portland (70 to 1.94)

My database

Pharmacy (70.0 to 1.94)

Zeolites (70 to 1.94)

Ferrites (70 to 1.94)

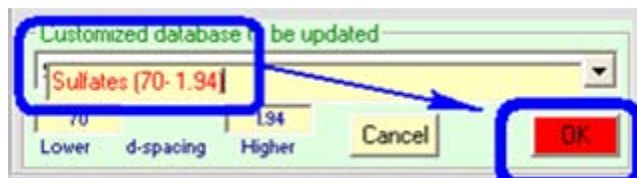
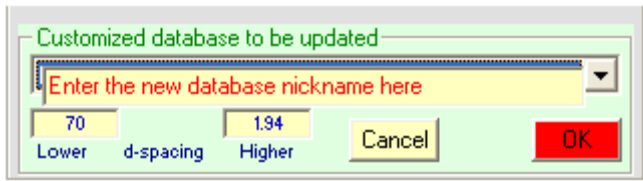
Portland (70 to 1.94)

New database (to be renamed)

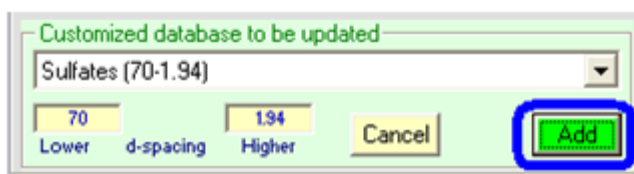
Line	2-theta angle	d-spacing	Intensity	H K L
1	17.35	5.9304	279.10	1 0 1
2	18.05	5.7022	219.20	0 0 3
3	20.20	5.1007	771.30	0 1 2
4	28.25	3.6653	231.10	1 1 0
5	29.30	3.5367	134.10	1 0 4
6	31.00	3.3471	173.90	h k l
7	33.25	3.1264	677.60	0 2 1
8	33.70	3.0858	1000.00	1 1 3
9	34.85	2.9870	145.20	2 0 2
10	36.55	2.8525	137.00	h k l
11	41.00	2.5542	181.90	0 2 4
12	46.20	2.2799	216.00	h k l
13	53.50	1.9873	259.10	3 3+3 0



5.5. If a new database is selected, rename it and push **OK** button:



5.6. **Add** the new card (**Jarosite\_Rio Tinto** in the example) to the custom database (**Sulfates [70-1.94]** in the example).



Note: The index files of each database are placed in the directories:

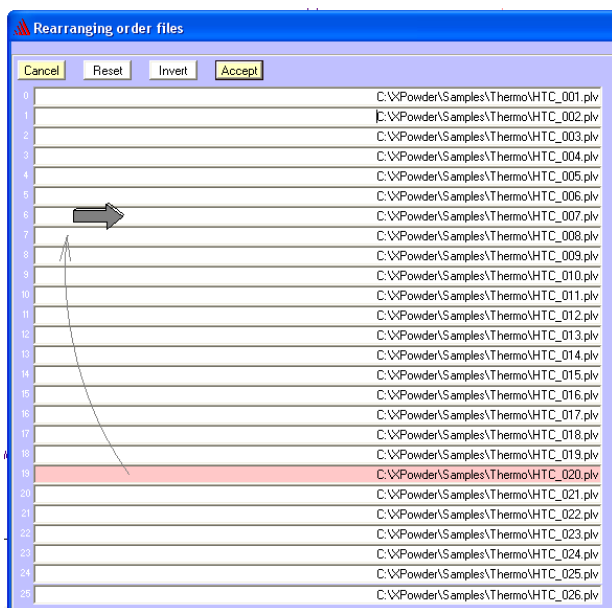
Program Directory\ DBlog\DB\_x

Where *x* are sequential integers for all databases . The value *x*=0 is reserved to the starting 'MyDatabase.myd'.

## 6. Rearranging diffraction patterns

This tool is very helpful to change the relative position of the diffractograms in 2D or 3D clusters.

- On the 'Home screen' push the right button in the mouse and select 'Files/Sorting patterns'.
- On the 'Stacking screen' push the right button in the mouse and select "Sorting files'.



Drag the file with the left mouse button to the new position.

[Home](#)



# XPowder12

## New features.

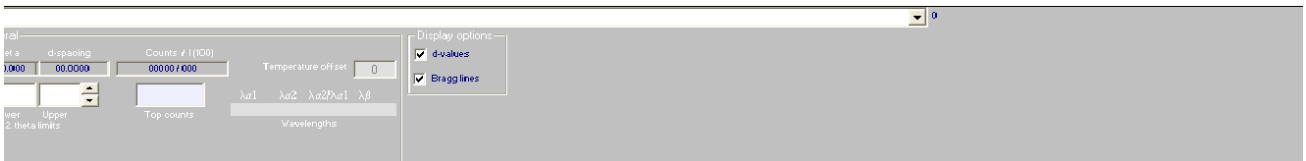
Ver 2012.01.01.

[General index](#)

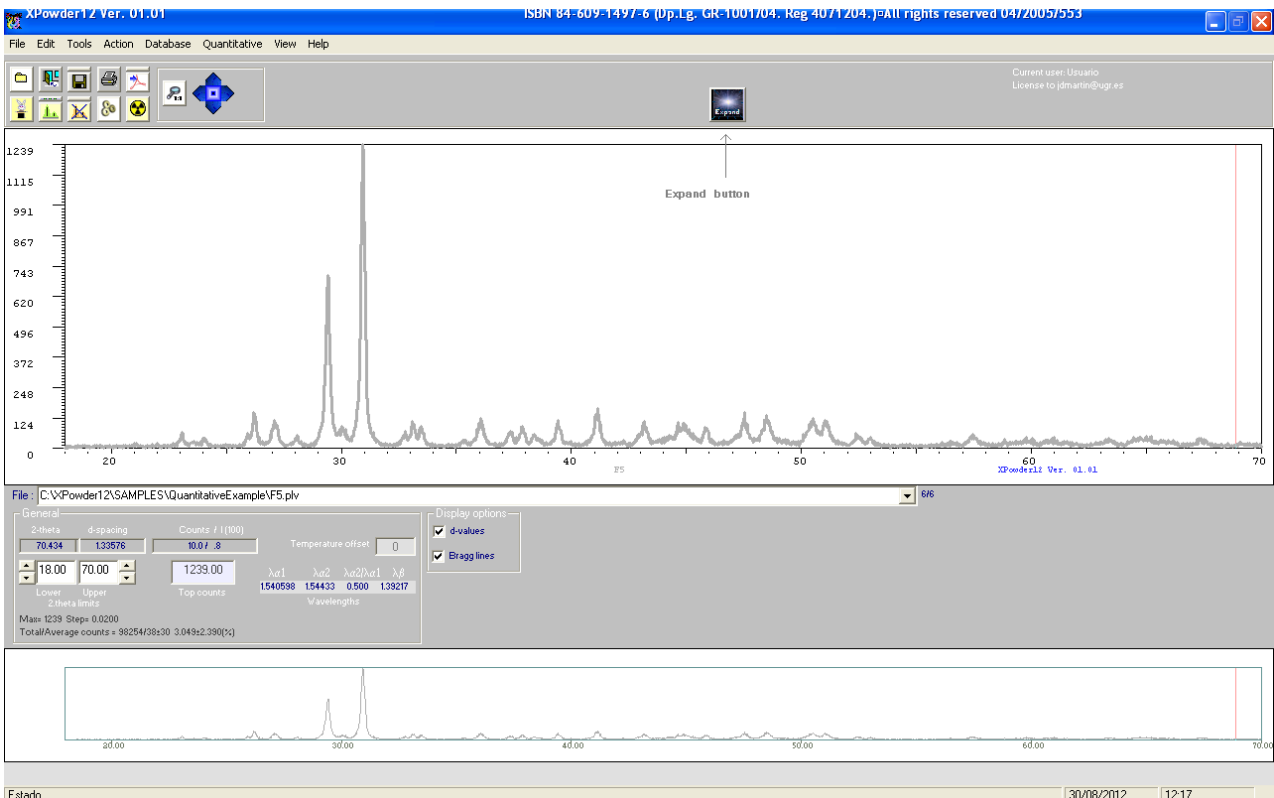
- Powerful [K \$\beta\$  stripping](#) function.
- Import additional diffractogram formats, including the direct conversion of [Chemin diffractometer images of Curiosity Mars Rover](#) of the *MSL* project to (x,y) text files.
- File reports in *Adobe pdf* format.
- Ability to save and restore complete work sessions.
- Display of [partial components in full-profile quantitative analysis](#).
- A new tool allows continuous zooming into diffractograms, both laterally and vertically.
- The databases installed previously with the old program **XPowder** can be used directly.
- Search-match, quantitative analysis,  $2\theta$  correction and profile tool are more compact than in the old **XPowder** program.
- In quantitative analysis with **XPowder12** program, the acronym [PIR](#) (*Pattern Intensity Ratio*) is used instead of the old *RIR* (*Reference Intensity Ratio*), because this term is usually calculated from a single reflection (the highest value in each phase divided by the highest value of a standard, i.e. corundum). However, both programs use the concept *PIR*, which is far more accurate.
- The [window program size](#) can be easily scaled.

**XPowder** and **XPowder12** can be used simultaneously. In this case it is preferable to install the programs in two different folders.

# HOME SCREEN



**Figure 12.1.** Home screen of XPowder12. The picture logo can be modified by including a line of the type 'Logo = Path\_picture' in the 'Xpowder12.ini' file. Alternatively, the logo picture file named 'Logo.jpg' in the folder XPowder12 program can be replaced by any other picture.



**Figure 12.2.** Up to fifty XRD patterns can be loaded simultaneously using the 'File' menu. In the figure the basic functions are shown. Sophisticated data analysis tools appear when clicking the button 'Expand'.

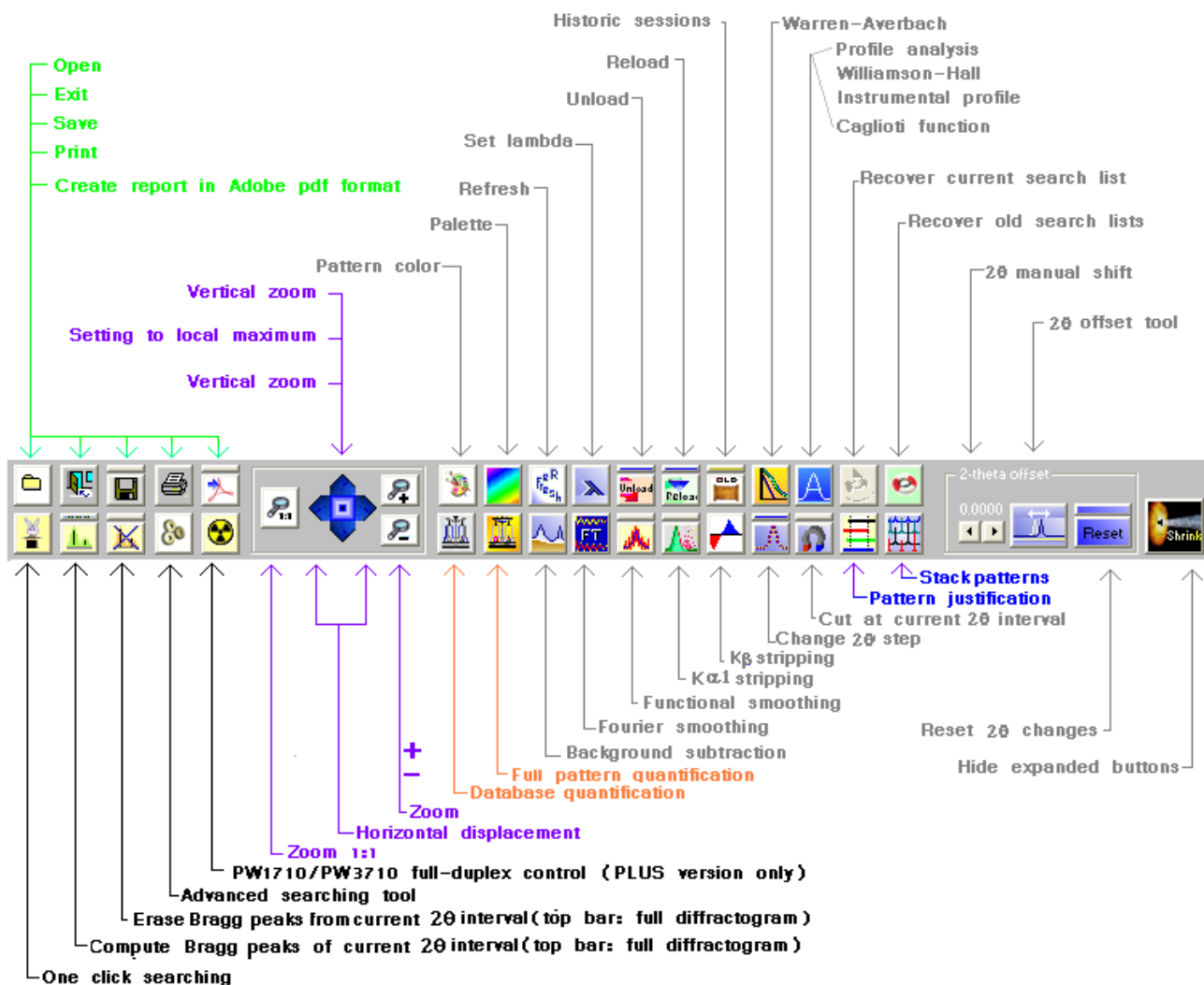


Figure 12.3. Main commands in the expanded 'Main menu' of X Powder12 program.

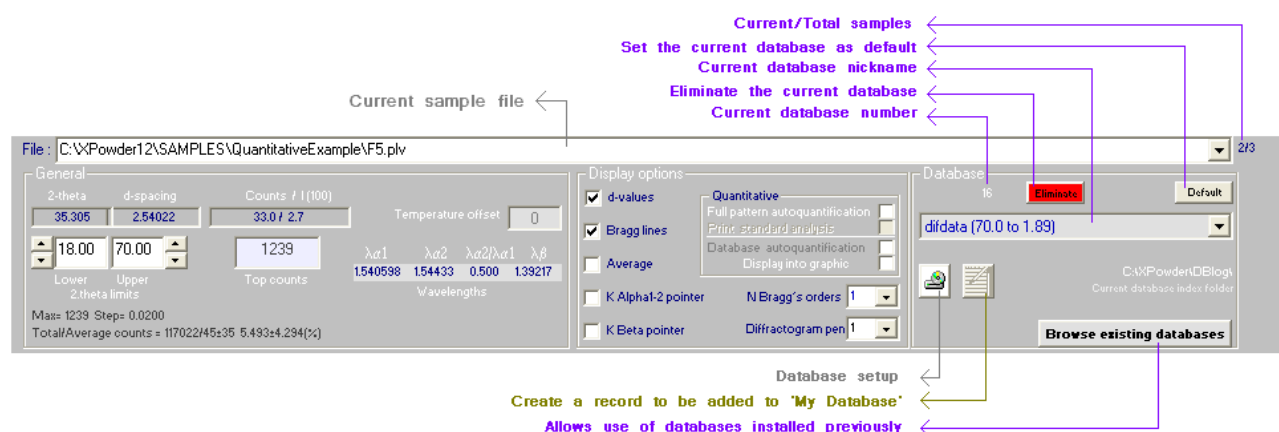


Figure 12.4. Dialog box for modifying diffractogram display settings and selection of the database to be used by data analysis tools.

# SEARCH and MATCH

Set default searching parameters

Home menu

Set cutoff lower limit = 0

Graphics display options

Expand results display for more details (see figure 12.6).

**Advanced searching. Sample: C:\XPowder12\SAMP...**

Subfiles and chemical restraints  
Looking for any chemical composition in selected subfiles

Match criteria: 4.100 (%), 0.4, 2-theta gap: 0.20

Match criteria options: FDM, Magic, Classic, Desperate, 2 reflections, 1 reflection

Mode cursor options: Normal, Gaps

Skip duplicates: 5

Buttons: Add, Search

**F5 in difdata (70.0 to 1.89)**

Looking for any chemical composition in selected subfiles

2θ offset = 0.003

Overstep search-match

Display patterns: bars, hkl

Checked, Current

Discard patterns: Duplicates, Deleted, Erase, Wipe, Unchecks, Select, Tiny, Minors, Largest, Discard -> except top

Least squares fit: Go, Automatic, Minors, Minor out-off %, Largest, Tiny out-off %, Both

Found	Penalty	Selected	Fraction
15	2	4	1.00

Buttons: Expand

**Dolomite**

Chemical: Ca (Mg<sub>94</sub> Fe<sub>05</sub> Mn<sub>0</sub>) C<sub>2</sub> O<sub>6</sub>

Ca (Mg<sub>94</sub> Fe<sub>05</sub> Mn<sub>0</sub>) C<sub>2</sub> O<sub>6</sub>

Set 2 File 341 Abs PIR 1000

Subfiles -Mineral

System Hexagonal aits Temp 25.0

Space group R-3 N 0

a 4.812 b 4.812 c 16.02

α 90 β 90 γ 120

Pattern C Active record

Dz 1 Pres kPa 100

Anode Cu Lambda 1540538

Unit cell Std Write + Info

Boolean Export Full profile

Figure 12.5. Advanced searching tool (above) and basic results display below).

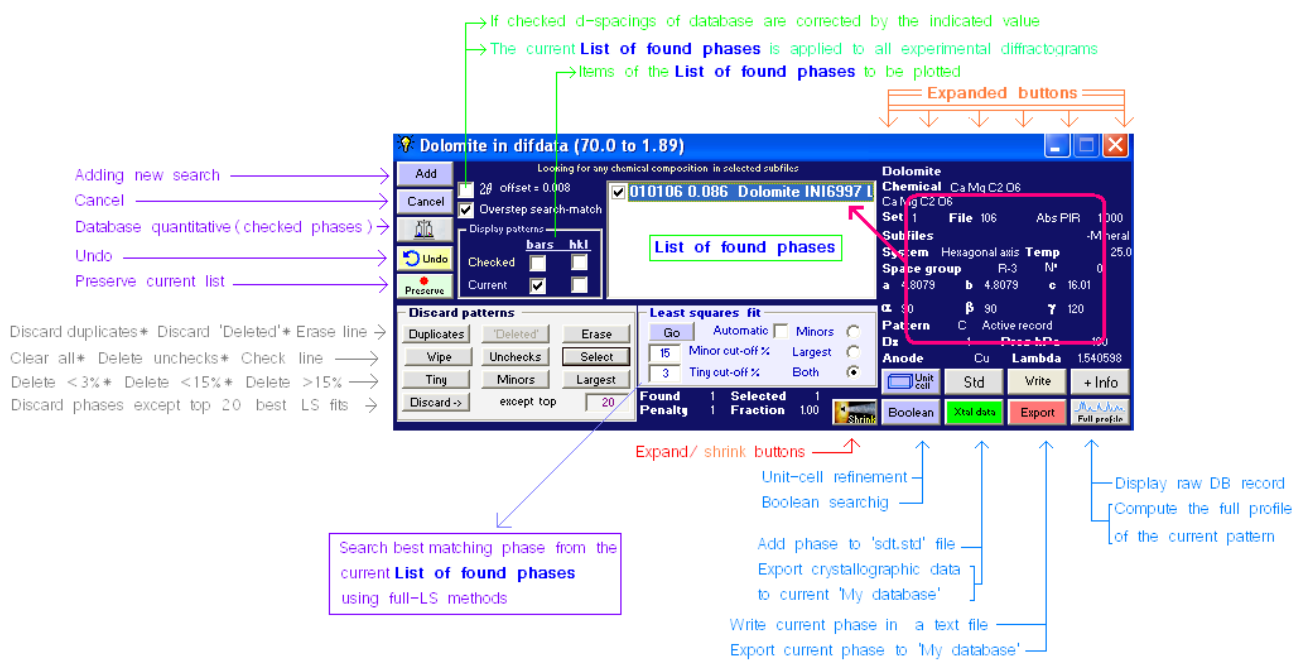


Figure 12.6. Expanded results display.

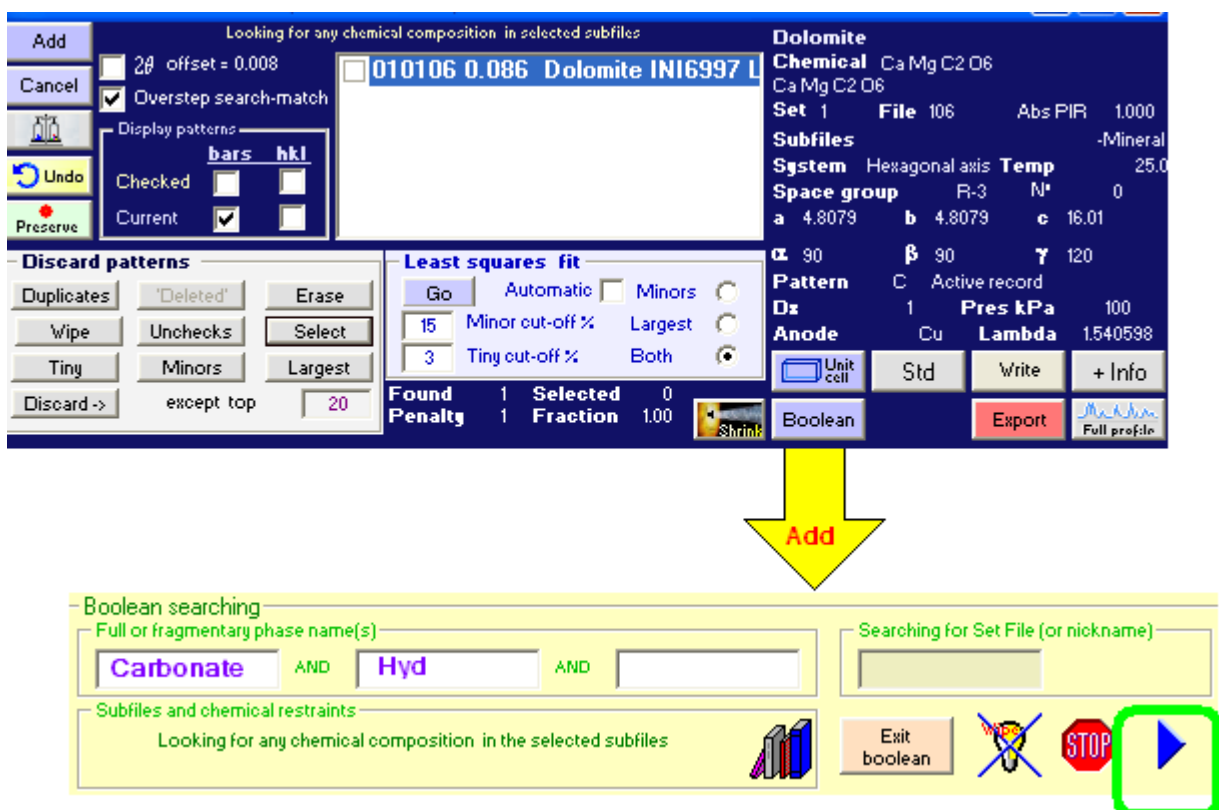


Figure 12.7. Boolean searching. In the example, every hydrated carbonate of the selected database will be added to the list, when the blue arrow button is pressed.

## QUANTIFICATION USING DATABASES

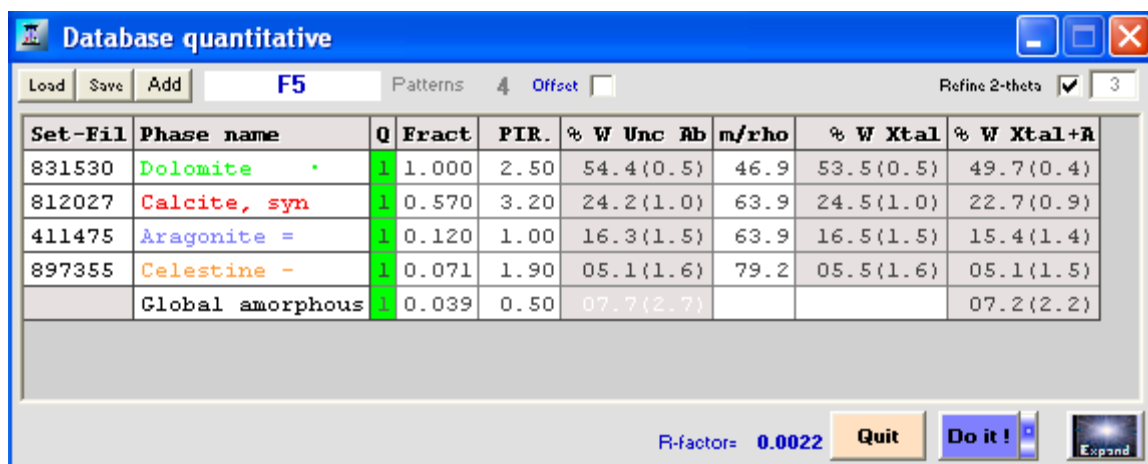


Figure 12.8. Quantitative analysis based on database records. Basic functions.

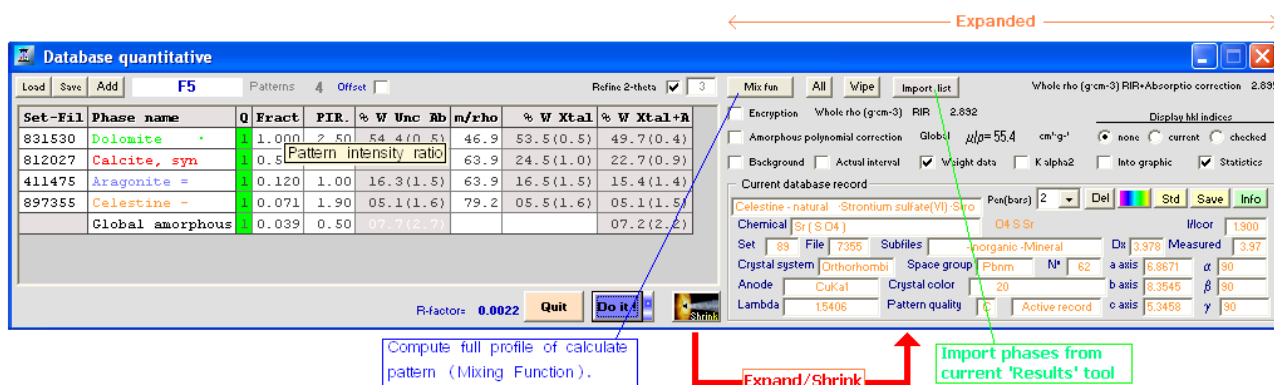


Figure 12.9. Quantitative analysis based on database records. Expanded functions.



# QUANTIFICATION USING EXPERIMENTAL PATTERNS

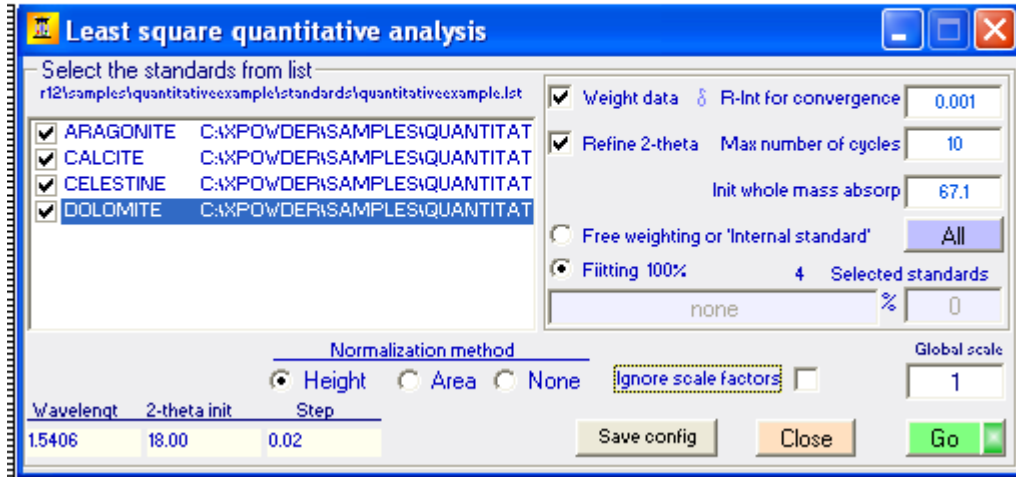


Figure 12.10. Tool for quantification using experimental standard patterns.

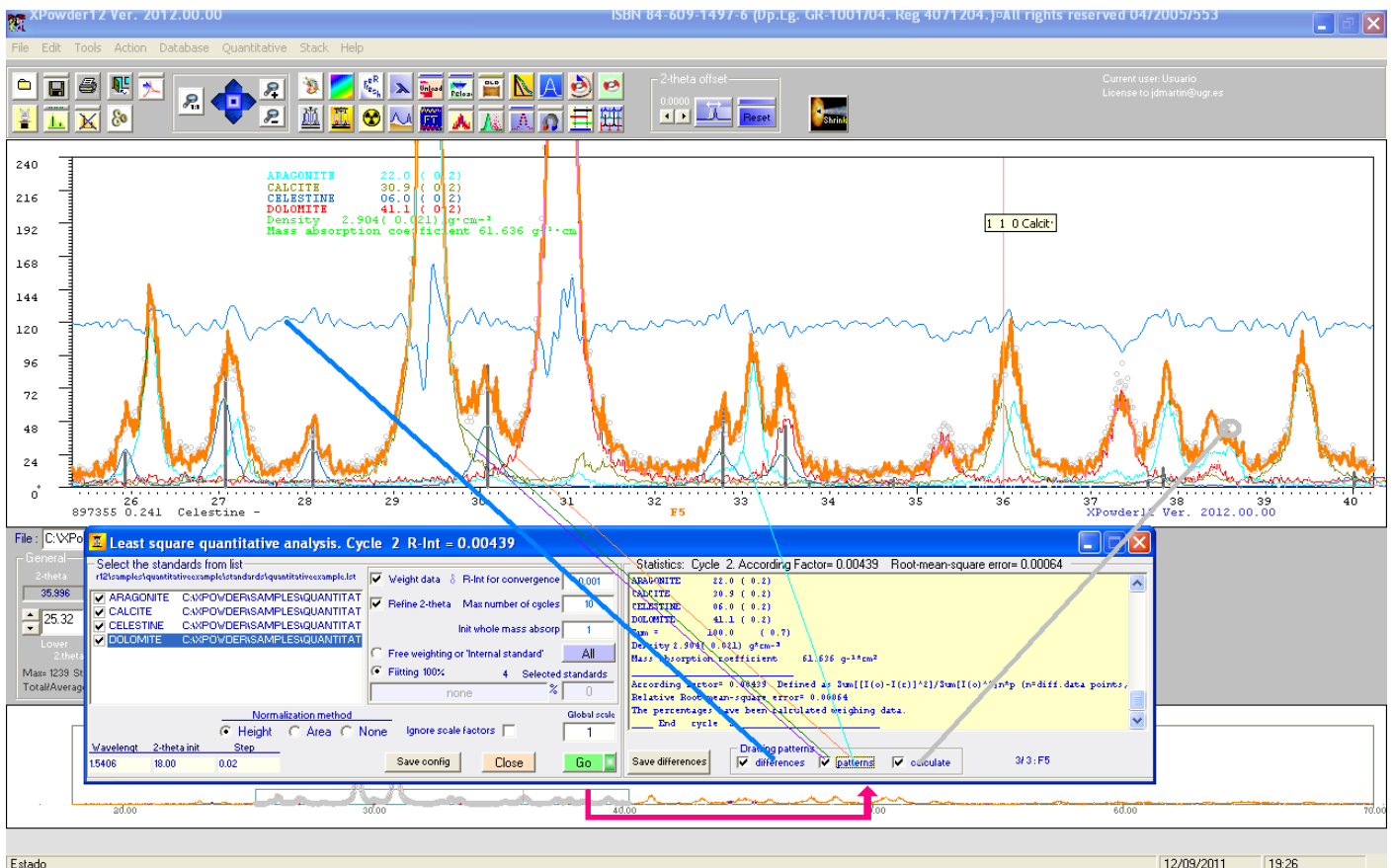


Figure 12.11. Quantification using the experimental standard pattern tool and results display (Note 'differences', 'components' and 'calculate' display options).

## Program window size

The program window size can be easily modified including the two following lines in the 'XPowder12.ini' file:

HeightScale = 'height scale factor'

WidthScale = 'width scale factor'

Where both scale factors may vary between 0,6 (60 % size) and 1 (full screen size).

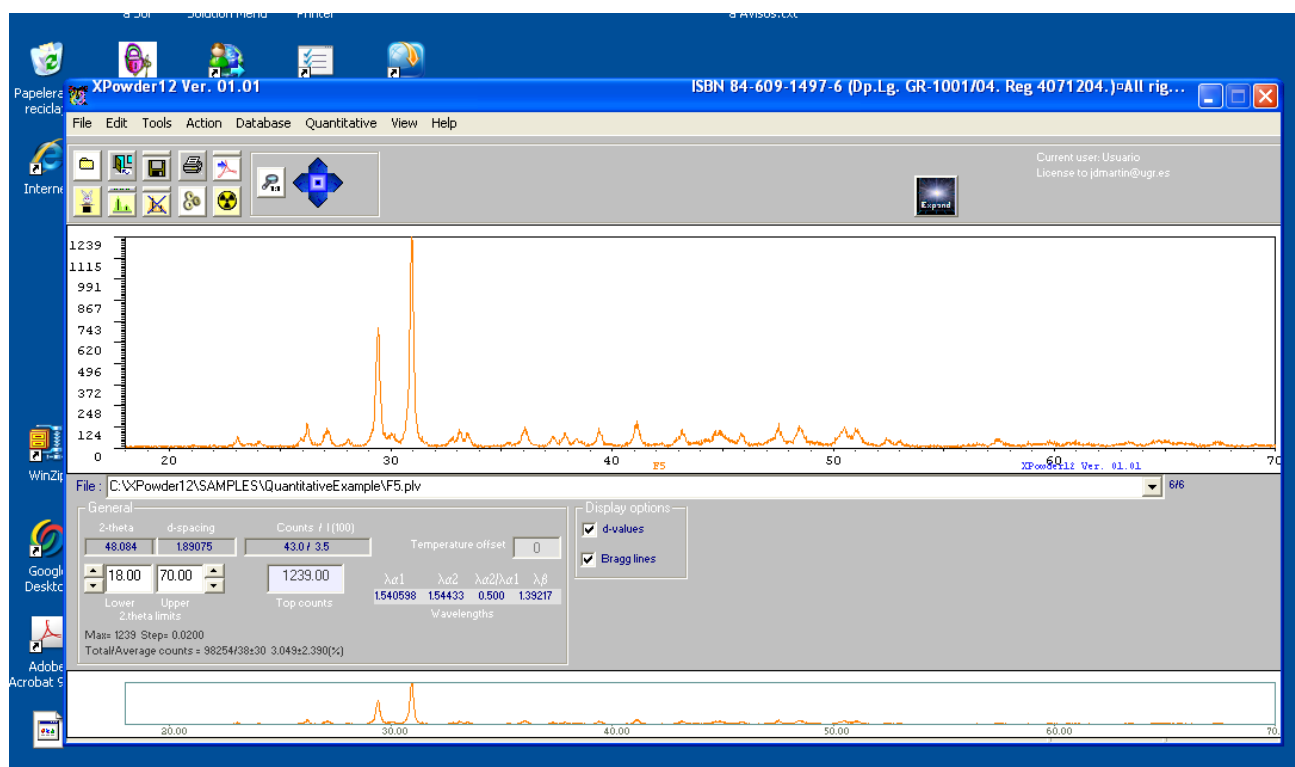


Figure 12.12. The example correspond to values of *HeightScale*= 0.8 and *WidthScale*= 0.9

## Transformation of 'Chemin' diffraction images to (x,y) text files

To access these functions simply open the image from the main menu:

**File > Open** /Select CHEMIN Images/ graphic file (\*.TIF, BMP,JPG, etc).

The image of the diffraction spots is displayed as in Figure 12.13. Also, the initial parameters that define the width, height and sample-CCD distance which are included in the file '*XPowder12.ini*', are shown in the top right of the screen. The initial coordinates of direct beam are referenced to the top left corner of the CCD. All units are in pixels and the values can be changed manually during the program execution. Additionally, some of these values, such as the coordinates of direct beam and the distance to the sample, can be tuned with various program tools.

The following actions may be performed:

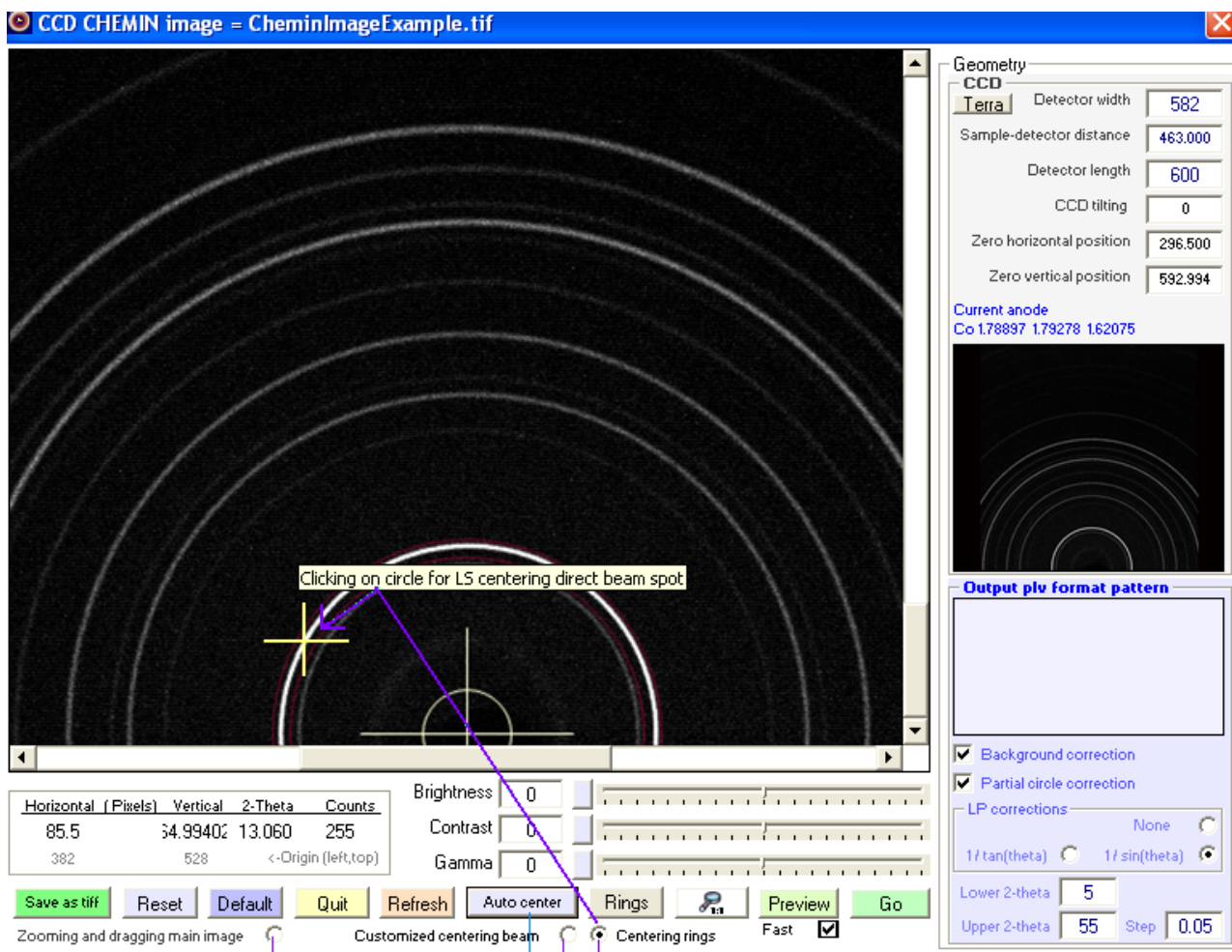
### 1. Centering of the direct X-Ray beam on CCD.

There are three available methods (figure 12.13):

1.1. Select '**Customized centering beam**' (*Focusing manual*). It is only necessary to press the proper point. This method lacks precision, but can be used as a preliminary starting point.

1.2. *Auto Center* button. It usually works well, especially if you use previously 1.1.

1.3. '**Centering ring**'. When the option is selected, just click on any ring and it will focus on the direct beam. This is the most accurate method.



1. Allows modifying the picture

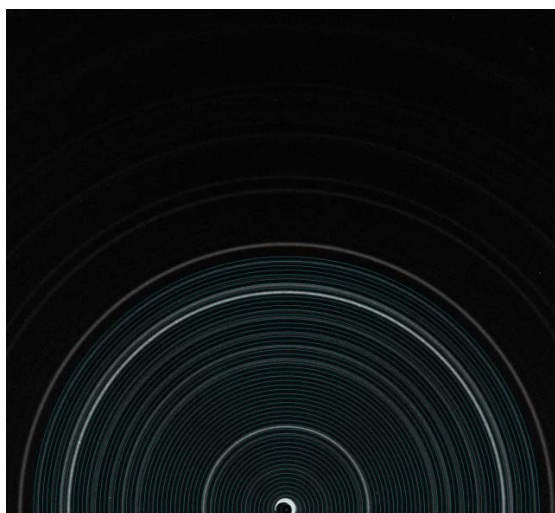
The center of the rings is calculated automatically

2. Define the center of the ring with a mouse click (innacurate)  
 3. By clicking around any circle, the center of the ring is calculated by LS.

**Figure 12.13.** Diffraction image and main commands and features of the graphic tool.

The quality of the focus can be tested by pressing the button 'Rings' (figure 12.14).

After having centered the direct beam it is advisable to mark the button 'Main image zooming and dragging' to prevent the X-Ray beam center from accidental modification. Furthermore, this option allows you to move and zoom the image with the left mouse button and mouse wheel respectively.



**Figure 12.14.** Checking quality of the focus with the button 'Rings'.

## 2. Computation of (X, Y) data.

(X =  $2\theta^\circ$ , Y = Accumulate counts at the ring of radius  $2\theta^\circ$ ).

The calculation is done with the buttons ('Preview' or 'Go', See figure 12.14). Several options can be used:

2.1. 'Partial circles correction'. Fix the breakdown of the circles outside the boundaries of the CCD (recommended).

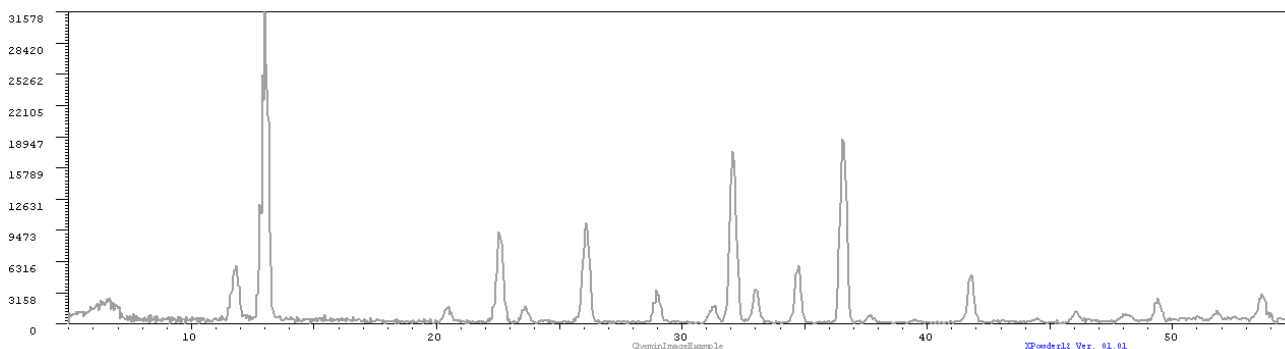
2.2. ' $1/\sin(\theta)$ ' correction. Create a diffractogram as obtained from Bragg-Brentano geometry and *automatic slit* (recommended).

2.3. ' $1/\tan(\theta)$ ' correction. This action computes a diffraction pattern similar to the previous one.

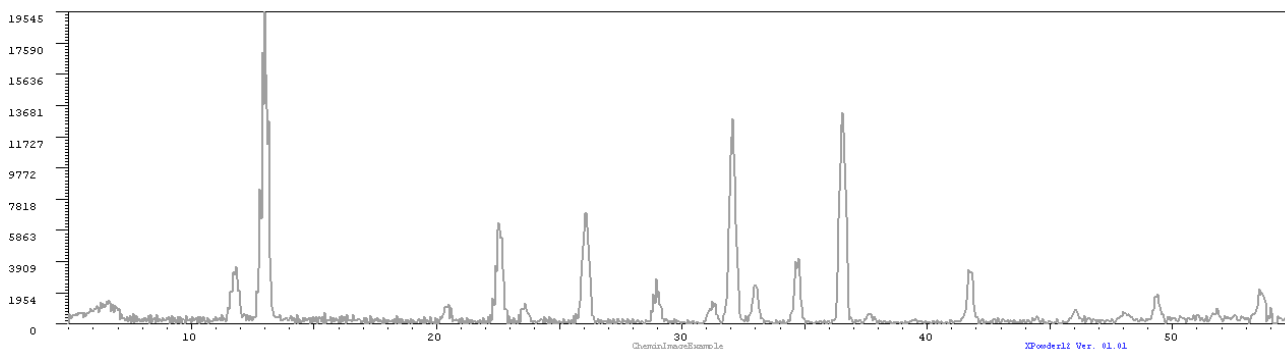
2.4. Background subtraction.

The  $2\theta$  limits and the  $2\theta$  step of the output diffractogram can be selected, as well as detector width, length, distance, tilting, etc of the device. Alternatively, 'Terra' diffractometer geometry can be used (button 'Terra').

The 'Go' button sends the calculated diffractogram to the main screen (figure 12.15.).



**Figure 12.15.** Computed diffraction pattern obtained from figure 12.13. containing  $K\alpha_1 + K\alpha_2 + K\beta$  peaks. Background has been subtracted and intensities have been divided by  $\sin\theta$ , according to instructions of figure 12.14. In most cases, as in the example, it is necessary to remove the  $K\alpha_2$  (figure 12.17) and  $K\beta$  (figure 12.18) components by using the commands of home menu (See figure 12.3.).



**Figure 12.16.** Pattern after having Stripped  $K\alpha_2$  (  in home screen).

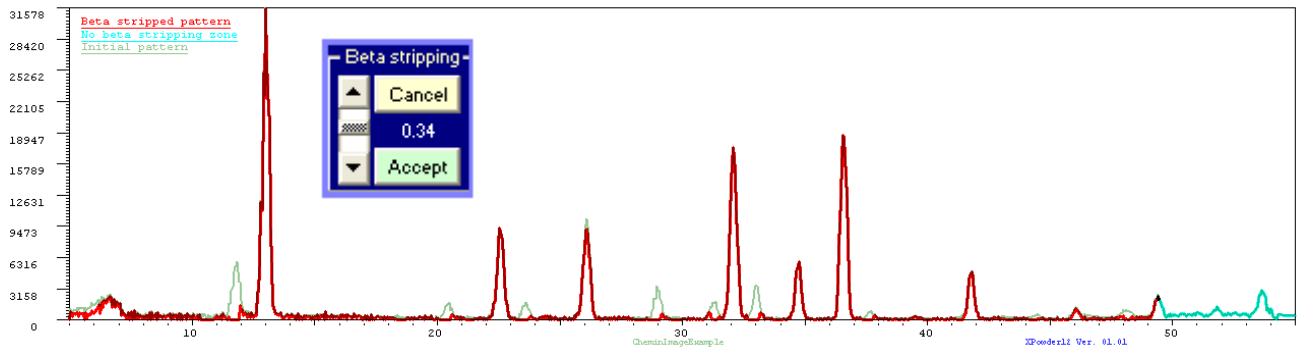



Figure 12.17.  $\beta$  stripping (  in home screen). The ( $1k\beta:1k\alpha1$ ) relation can be tuned with the vertical scroll bar of the figure. Original pattern shows in grey and  $\beta$ -stripped pattern shows in red. Final  $2\theta$  zone trace, in green, is unavoidably excluded from computation.

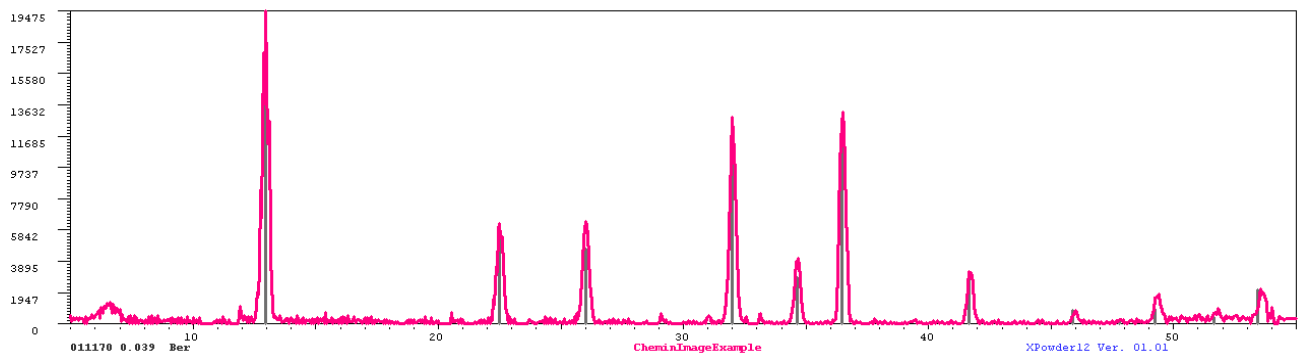


Figure 12.18. Pure  $K\alpha$  pattern

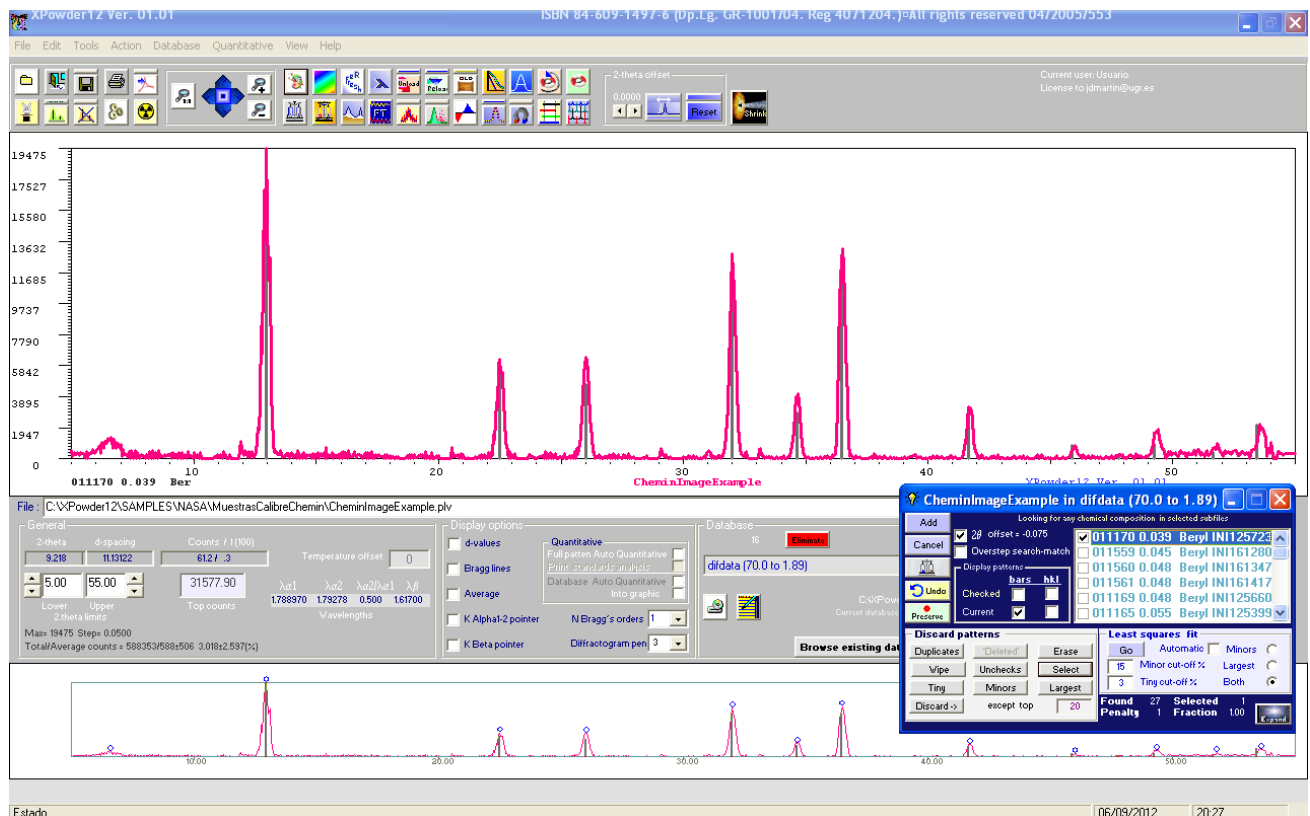


Figure 12.19. Applying *One-Click searching* on pattern from figure 12.17. The results list shows the beryl records of the database (AMCSD). [XPowder12](#) [Home](#)